

RL78/I1C

RENESAS MCU

R01DS0281EJ0230 Rev.2.30 Mar 29, 2024

True Low Power Platform, Independent power supply RTC, Hardware AES, 32-bit MAC, 1.9 V to 5.5 V operation, 64 to 256 Kbyte Flash, for Electric AMI Power Meter Application

1. OUTLINE

1.1 Features

Target application

Power meters

Ultra-low power consumption technology

- V_{DD} = single power supply voltage of 1.7 to 5.5 V^{Note 1}
- HALT mode
- STOP mode
- SNOOZE mode

RL78 CPU core

- CISC architecture with 3-stage pipeline
- Minimum instruction execution time: Can be changed from high speed (0.03125 μs: @ 32 MHz selection with PLL clock, 0.04167 μs: @ 24 MHz selection with high-speed on-chip oscillator) to ultra-low speed (66.6 μs: @ 15 kHz operation with low-speed on-chip oscillator)
- 16-bit multiplication, 16-bit multiply-accumulation, and 32-bit division are supported.
- Address space: 1 MB
- General-purpose registers: (8-bit register × 8) × 4 banks
- On-chip RAM: 6 KB to 16 KB

Code flash memory

- Code flash memory: 64 KB to 256 KB
- Block size: 1 KB
- Prohibition of block erase and rewriting (security function)
- · On-chip debug function
- Self-programming (with boot swap function/flash shield window function)

Data flash memory

- Data flash memory: 2 KB
- Back ground operation (BGO): Instructions can be executed from the program memory while rewriting the data flash memory
- Number of rewrites: 1,000,000 times (TYP.)
- Voltage of rewrites: V_{DD} = 1.9 to 5.5 V

PLL clockNote 2

• 32 MHz is selectable ($\Delta\Sigma$ A/D converter is operable even when the PLL clock is selected as a CPU clock.)

High-speed on-chip oscillator

- Select from 1 to 24 MHz (TYP.). However when it is used as a clock for the ΔΣ A/D converter, select from 24 MHz (TYP.), 12 MHz (TYP.), 6 MHz (TYP.), or 3 MHz (TYP.).
- High accuracy: ±1.0% (V_{DD} = 1.9 to 5.5 V, T_A = -20 to +85°C)
- On-chip high-speed on-chip oscillator clock frequency correction function

Middle-speed on-chip oscillator

 Select from 4 MHz/2 MHz/1 MHz (However ΔΣ A/D converter is disabled.)

Operating ambient temperature

• T_A = -40 to +85°C

Power management and reset function

- On-chip power-on-reset (POR) circuit for Internal VDD^{Note 3} power supply
- On-chip RTC power-on-reset (RTCPOR) circuit for VRTC power supply
- On-chip voltage detector (LVD) (Select interrupt and reset from 13 levels)

Voltage detective circuit

- Detective voltage for V_{DD} pin (Select interrupt from 6 levels)
- Detective voltage for VBAT pin (Select interrupt from 7 levels)
- Detective voltage for VRTC pin (Select interrupt from 4 levels)
- Detective voltage for EXLVD pin (Select interrupt from 1 level)

Data transfer controller (DTC)

- Transfer mode: Normal mode, repeat mode, block mode
- · Activation source: Start by interrupt sources
- Chain transfer function

Event link controller (ELC)

 Event signals of 22 types can be linked to the specified peripheral function.

On-chip 32-bit multiplier and multiply-accumulator

- 32 bits × 32 bits = 64 bits (Unsigned or signed)
- 32 bits × 32 bits + 64 bits = 64 bits (Unsigned or signed)

Serial interface

- Simplified SPI (CSI): 2 to 3 channels
- UART/UART (LIN-bus supported): 2 to 3 channels
- UART/IrDA: 1 channel
- Simplified I²C communication: 2 to 3 channels
- I²C communication: 1 channel

Timer

- 16-bit timer: 8 channels
- 12-bit interval timer: 1 channel
- 8-bit interval timer: 4 channels
- Independent power supply RTC: 1 channel (calendar for 99 years, alarm function, and clock correction function)
- Watchdog timer: 1 channel
- Oscillation stop detection circuit: 1 channel

LCD controller/driver

- Internal voltage boosting method, capacitor split method, and external resistance division method are switchable
- Segment signal output: 19 (15)^{Note 4} to 42 (38)^{Note 4}
- Common signal output: 4 (8)Note 4

A/D converter

- 24-Bit ΔΣ A/D converter: 3 or 4 channels
- 8/10-bit resolution A/D converter
 (VDD = 1.9 to 5.5 V): 4 or 6 channels
- Internal reference voltage (1.45 V) and temperature sensor

I/O port

- I/O port: 35 to 68 (N-ch open drain I/O [6 V tolerance]: 3, N-ch open drain I/O [VDD toleranceNote 5/EVDD toleranceNote 6]: 10 to 16)
- Can be set to N-ch open drain, TTL input buffer, and on-chip pull-up resistor
- Different potential interface: Can connect to a 1.8/2.5/3 V device
- On-chip clock output/buzzer output controller
- On-chip key interrupt function

AES circuitNote 7

- Cipher modes of operation: GCM/ECB/CBC
- Encryption key length: 128/192/256 bits

Others

- On-chip BCD (binary-coded decimal) correction circuit
- On-chip battery backup function
- **Notes 1.** The minimum operating voltage of this product varies according to the VBATEN setting value.

When VBATEN = 0, the minimum operating voltage is 1.7 V.
When VBATEN = 1, the minimum

operating voltage is 1.9 V.

As well, the minimum operating voltage of VRTC is 1.6 V.

- 2. R5F10NPJ, R5F10NMJ, R5F10NPG only.
- **3.** Either V_{DD} or VBAT is selected by the battery backup function.
- **4.** The values in parentheses are the number of signal outputs when 8 com is used.
- 5. 64 pin products only
- 6. 80 pin, 100 pin products only
- 7. Only available in R5F10N products.

Remark The functions mounted depend on the product. See **1.6 Outline of Functions**.

O ROM, RAM capacities

Code Flash	Data Flash	RAM	AES Function	RL78/I1C		
				64 pins	80 pins	100 pins
256 KB	2 KB	16 KB ^{Note 1}	Mounted	-	R5F10NMJ	R5F10NPJ
128 KB	2 KB	8 KB ^{Note 2}	Mounted	R5F10NLG	R5F10NMG	R5F10NPG
			Not mounted	R5F11TLG	-	-
64 KB	2 KB	6 KB	Mounted	R5F10NLE	R5F10NME	-
			Not mounted	R5F11TLE	-	-

Notes 1. This is about 15 KB when the self-programming function is used. (For details, refer to CHAPTER 3 in the RL78/I1C User's Manual.)

2. This is about 7 KB when the self-programming function is used (excluding in the case of the R5F10NPG). (For details, refer to CHAPTER 3 in the RL78/I1C User's Manual.)

1.2 List of Part Numbers

<R>

Figure 1-1. Part Number, Memory Size, and Package of RL78/I1C

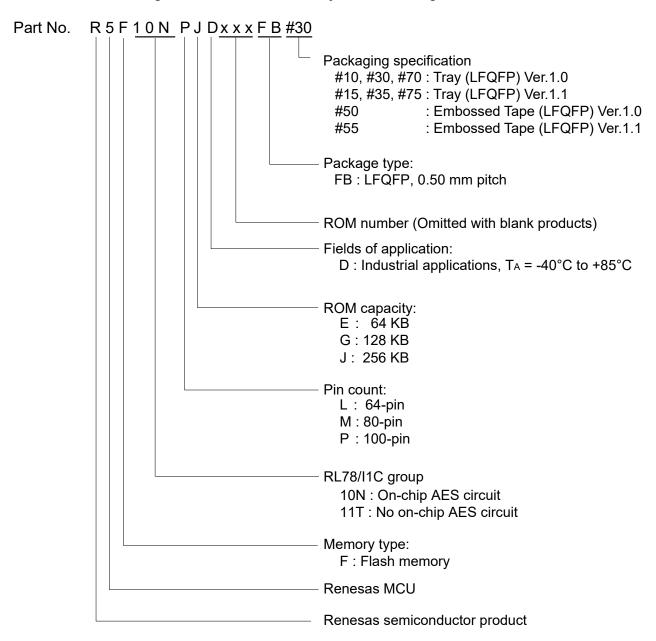


Table 1-1. List of Ordering Part Numbers

	Pin Count	Package	Data Flash	AES Function	Fields of Application ^{Note}	Ordering Part Number
	64 pins	64-pin plastic LFQFP	Mounted	Mounted	D	R5F10NLEDFB#10, R5F10NLGDFB#10,
		(10 × 10 mm, 0.5 mm				R5F10NLEDFB#15, R5F10NLGDFB#15,
		pitch)				R5F10NLEDFB#30, R5F10NLGDFB#30,
						R5F10NLEDFB#50, R5F10NLGDFB#50,
<r></r>						R5F10NLEDFB#70, R5F10NLGDFB#70,
						R5F10NLEDFB#35, R5F10NLGDFB#35,
						R5F10NLEDFB#55, R5F10NLGDFB#55,
<r></r>						R5F10NLEDFB#75, R5F10NLGDFB#75
				Not mounted	D	R5F11TLEDFB#10, R5F11TLGDFB#10,
						R5F11TLEDFB#15, R5F11TLGDFB#15,
						R5F11TLEDFB#30, R5F11TLGDFB#30,
						R5F11TLEDFB#50, R5F11TLGDFB#50,
<r></r>						R5F11TLEDFB#70, R5F11TLGDFB#70,
						R5F11TLEDFB#35, R5F11TLGDFB#35,
						R5F11TLEDFB#55, R5F11TLGDFB#55,
<r></r>						R5F11TLEDFB#75, R5F11TLGDFB#75
	80 pins	80-pin plastic LFQFP	Mounted	Mounted	D	R5F10NMEDFB#10, R5F10NMGDFB#10,
		(12 × 12 mm, 0.5 mm				R5F10NMJDFB#10, R5F10NMEDFB#15,
		pitch)				R5F10NMGDFB#15, R5F10NMJDFB#15,
						R5F10NMEDFB#30, R5F10NMGDFB#30,
						R5F10NMJDFB#30, R5F10NMEDFB#35,
						R5F10NMGDFB#35, R5F10NMJDFB#35,
						R5F10NMEDFB#50, R5F10NMGDFB#50,
						R5F10NMJDFB#50, R5F10NMEDFB#55,
ıD.						R5F10NMGDFB#55, R5F10NMJDFB#55,
<r></r>						R5F10NMEDFB#70, R5F10NMGDFB#70,
<r></r>						R5F10NMJDFB#70, R5F10NMEDFB#75
<r></r>						R5F10NMGDFB#75, R5F10NMJDFB#75
	100 pins	100-pin plastic LFQFP	Mounted	Mounted	D	R5F10NPJDFB#10, R5F10NPGDFB#10,
		(14 × 14 mm, 0.5 mm pitch)				R5F10NPJDFB#15, R5F10NPGDFB#15,
		pitori)				R5F10NPJDFB#30, R5F10NPGDFB#30,
						R5F10NPJDFB#35, R5F10NPGDFB#35,
						R5F10NPJDFB#50, R5F10NPGDFB#50,
∠D\						R5F10NPJDFB#55, R5F10NPGDFB#55,
<r></r>						R5F10NPJDFB#70, R5F10NPGDFB#70,
<r></r>						R5F10NPJDFB#75, R5F10NPGDFB#75

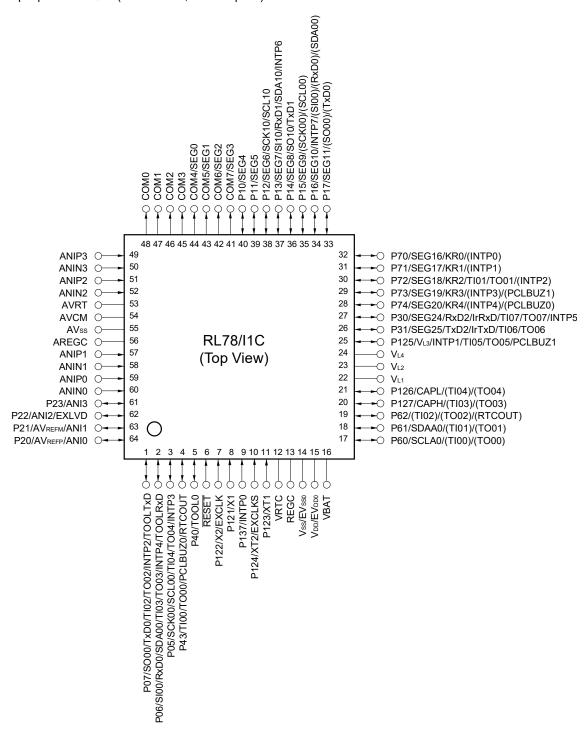
Note For the fields of application, see Figure 1-1 Part Number, Memory Size, and Package of RL78/I1C.

Caution The ordering part numbers represent the numbers at the time of publication. For the latest ordering part numbers, refer to the target product page of the Renesas Electronics website.

1.3 Pin Configuration (Top View)

1.3.1 64-pin products

• 64-pin plastic LFQFP (10 × 10 mm, 0.5 mm pitch)



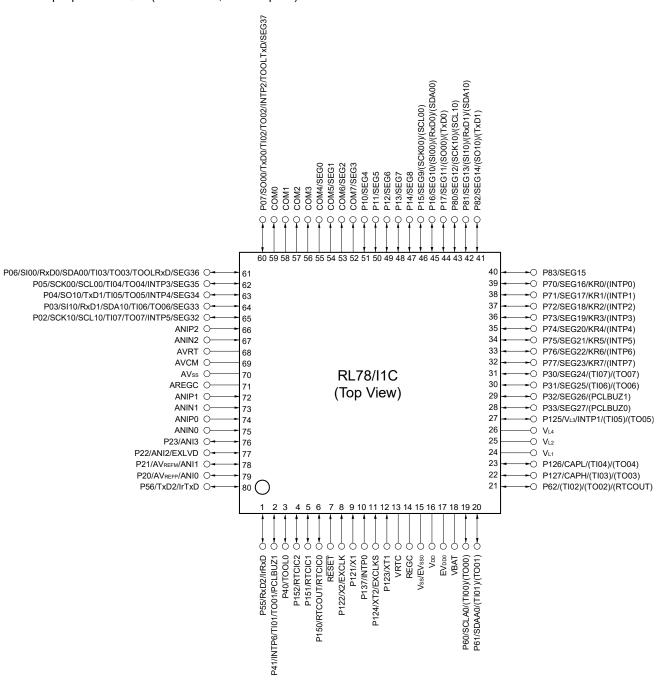
Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F).

Remarks 1. For pin identification, see 1.4 Pin Identification.

2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR0). See Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR0) in the RL78/I1C User's Manual.

1.3.2 80-pin products

• 80-pin plastic LFQFP (12 × 12 mm, 0.5 mm pitch)



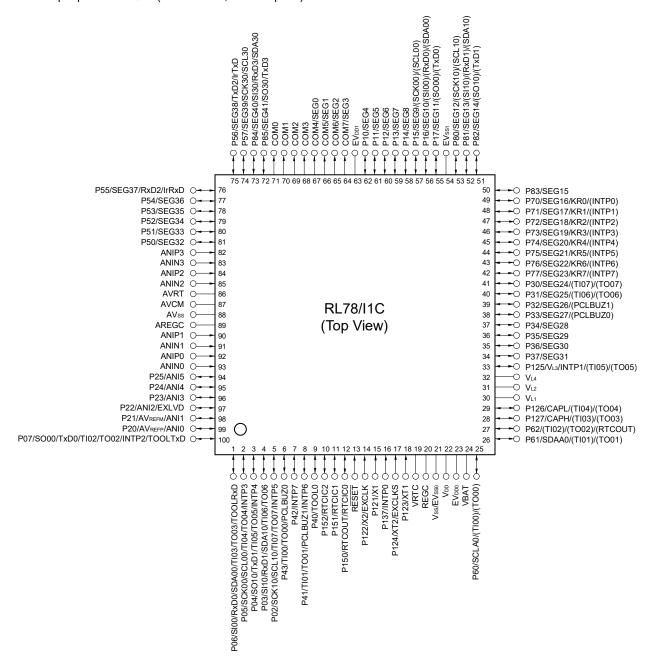
Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F).

Remarks 1. For pin identification, see 1.4 Pin Identification.

 Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR0). See Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR0) in the RL78/I1C User's Manual.

1.3.3 100-pin products

• 100-pin plastic LFQFP (14 × 14 mm, 0.5 mm pitch)



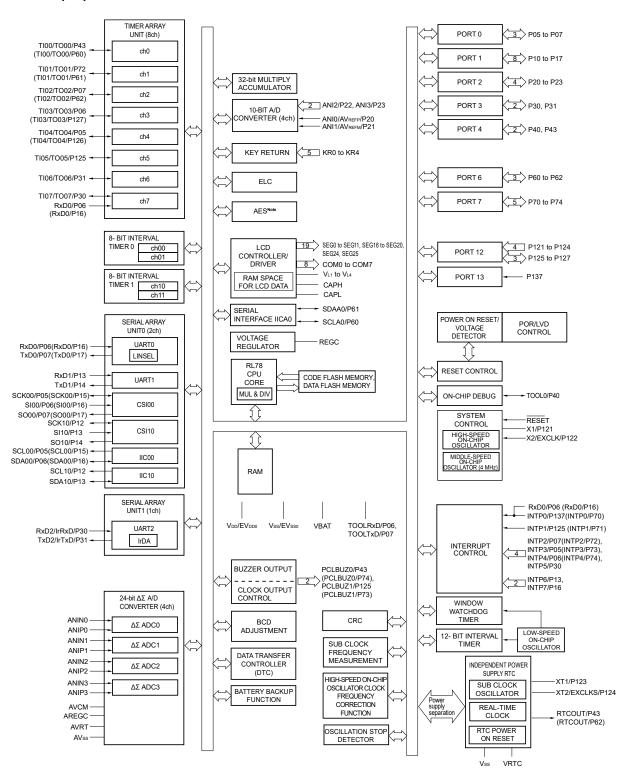
- Cautions 1. Make EVss1 the same potential as Vss/EVss0.
 - 2. Make EVDD1 the same potential as EVDD0.
 - 3. Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F).
- Remarks 1. For pin identification, see 1.4 Pin Identification.
 - 2. When using the microcontroller for an application where the noise generated inside the microcontroller must be reduced, it is recommended to supply separate powers to the V_{DD} and EV_{DD1} pins and connect the Vss and EVss1 pins to separate ground lines.
 - 3. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR0). See Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR0) in the RL78/I1C User's Manual.

1.4 Pin Identification

ANI0 to ANI5:	Analog Input	P137:	Port 13
ANIN0 to ANIN3,		P150 to P152:	Port 15
ANIP0 to ANIP3:	Analog Input for $\Delta\Sigma$ ADC	PCLBUZ0,	
AREGC:	Regulator Capacitance for $\Delta\Sigma$ ADC	PCLBUZ1:	Programmable Clock Output/Buzzer
AVCM:	Control for $\Delta\Sigma$ ADC		Output
AVREFM:	A/D Converter Reference Potential	REGC:	Regulator Capacitance
	(- side) Input	RESET:	Reset
AVREFP:	A/D Converter Reference Potential	RTCOUT:	Real-time Clock Correction Clock
	(+ side) Input		(1 Hz/64 Hz) Output
AVRT:	Reference Potential for $\Delta\Sigma$ ADC	RTCIC0 to RTCIC2:	RTC Time Capture Event Input
AVss:	Ground for $\Delta\Sigma$ ADC	RxD0 to RxD3:	Receive Data for UART
CAPH, CAPL:	Capacitor Connection	SCL00, SCL10,	
	for LCD Controller/Driver	SCL30:	Serial Clock Output for Simplified IIC
COM0 to COM7:	Common Signal Output for LCD	SDA00, SDA10,	
	Controller/Driver	SDA30:	Serial Data Input/Output for Simplified IIC
EVDD0, EVDD1:	Power Supply for Port	SCLA0:	Serial Clock Input/Output for IICA0
EVsso, EVss1:	Ground for Port	SDAA0:	Serial Data Input/Output for IICA0
EXCLK:	External Clock Input	SCK00, SCK10,	
	(Main System Clock)	SCK30:	Serial Clock Input/Output for CSI
EXCLKS:	External Clock Input	SEG0 to SEG41:	Segment Signal Output for LCD
	(Subsystem clock)		Controller/Driver
EXLVD:	External Input for Low Voltage	SI00, SI10, SI30:	Serial Data Input for CSI
	Detector	SO00, SO10, SO30:	Serial Data Output for CSI
INTP0 to INTP7:	Interrupt Request From Peripheral	TI00 to TI07:	Timer Input
IrRxD:	Receive Data for IrDA	TO00 to TO07:	Timer Output
IrTxD:	Transmit Data for IrDA	TOOL0:	Data Input/Output for Tool
KR0 to KR7:	Key Return	TOOLRxD,	
P02 to P07:	Port 0	TOOLTxD:	Data Input/Output for External Device
P10 to P17:	Port 1	TxD0 to TxD3:	Transmit Data for UART
P20 to P25:	Port 2	VBAT:	Battery Backup Power Supply
P30 to P37:	Port 3	V _{DD} :	Power Supply
P40 to P43:	Port 4	VL1 to VL4:	Voltage for Driving LCD
P50 to P57:	Port 5	VRTC:	RTC Power Supply
P60 to P62:	Port 6	Vss:	Ground
P70 to P77:	Port 7	X1, X2:	Crystal Oscillator (Main System
P80 to P85:	Port 8		Clock)
P121 to P127:	Port 12	XT1, XT2:	Crystal Oscillator (Subsystem Clock)

1.5 Block Diagram

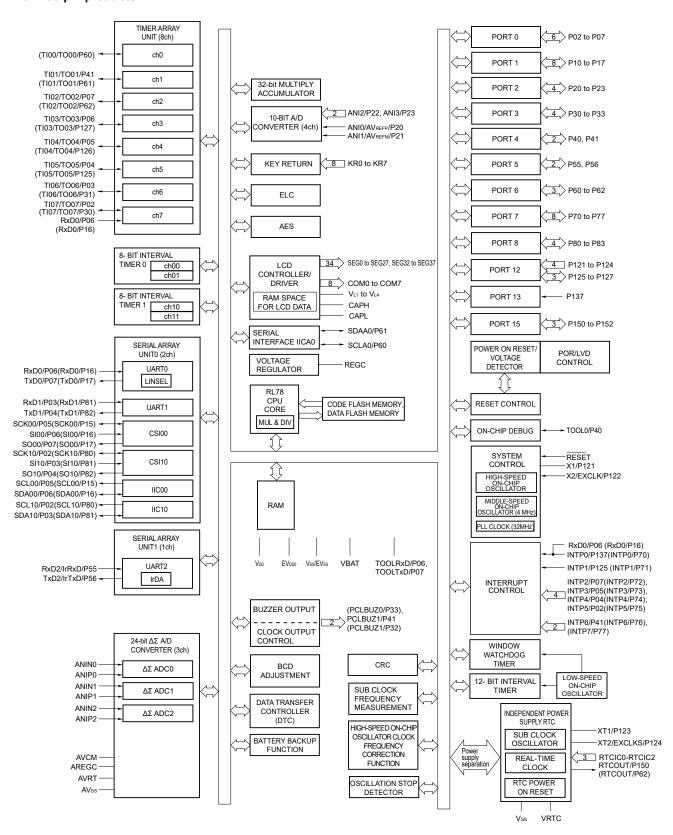
1.5.1 64-pin products



Note Only available in R5F10N products.

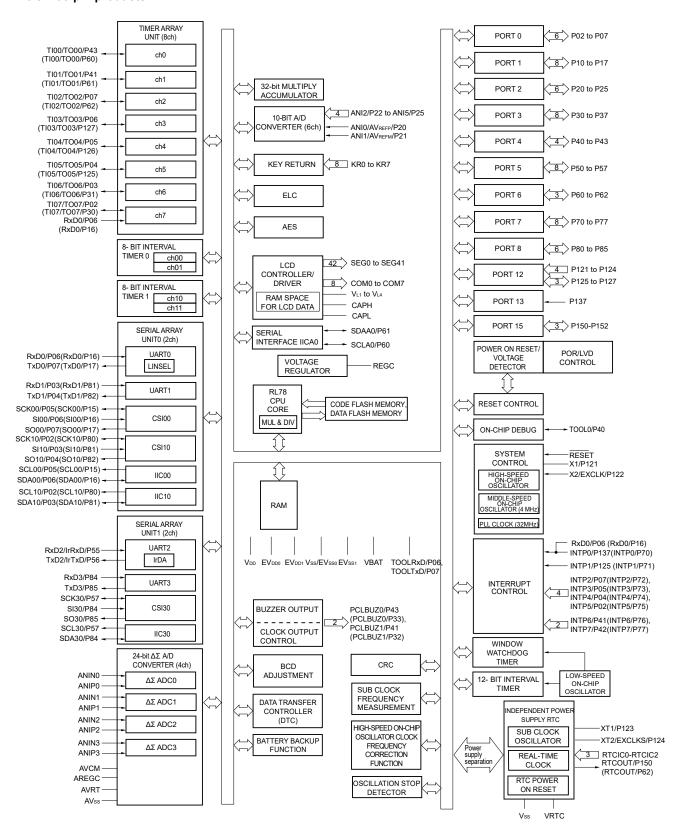
Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR0). See Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR0) in the RL78/I1C User's Manual.

1.5.2 80-pin products



Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR0). See Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR0) in the RL78/I1C User's Manual.

1.5.3 100-pin products



Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR0). See Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR0) in the RL78/I1C User's Manual.

1.6 Outline of Functions

(1/3)

	Item	64-	·pin		80-pin		100	(1/3) -pin	
		R5F10NLEDFB/	R5F10NLGDFB/	R5F10NMEDFB	R5F10NMGDFB	R5F10NMJDFB	R5F10NPGDFB	R5F10NPJDFB	
		R5F11TLEDFB	R5F11TLGDFB	THOI TOTAINED D	THOI TOTAMODE D				
Code flash m	emory (KB)	64 KB	128 KB	64 KB	128 KB	256 KB	128 KB	256 KB	
Data flash me					2 KB		ı		
RAM (KB)	• • •	6 KB	8 KB ^{Note 1}	6 KB	8 KB ^{Note 1}	16 KB ^{Note 2}	8 KB	16 KB ^{Note 2}	
Address space	ce	1 MB		•	•	•	•	•	
Main system clock	High-speed system clock	HS (High-spe HS (High-spe HS (High-spe HS (High-spe LS (Low-spe LV (Low-volta	eed main) mod eed main) mod eed main) mod eed main) mod ed main) mod age main) mod	e: 1 to 20 MH e: 1 to 16 MH e: 1 to 12 MH e: 1 to 6 MHz e: 1 to 8 MHz le: 1 to 4 MHz	nain system clo z (Vpd = 2.7 to z (Vpd = 2.5 to z (Vpd = 2.4 to (Vpd = 2.1 to (Vpd = 1.9 to (Vpd = 1.7 to (Vpd = 1.7 to (Vpd = 1.9 to	5.5 V), 5.5 V), 5.5 V), 5.5 V), 5.5 V), 5.5 V),	CLK)		
	High -speed on-chip oscillator clock (f _H) MAX.: 24 MHz	HS (High-spe	eed main) mod eed main) mod	e: 1 to 16 MH e: 1 to 12 MH	$z (V_{DD} = 2.7 \text{ to})$ $z (V_{DD} = 2.5 \text{ to})$ $z (V_{DD} = 2.4 \text{ to})$	5.5 V), 5.5 V),			
	Middle -speed on- chip oscillator clock (f _{IM}) MAX.: 4 MHz	LS (Low-spec	HS (High-speed main) mode: 1 to 6 MHz (V _{DD} = 2.1 to 5.5 V), LS (Low-speed main) mode: 1 to 8 MHz (V _{DD} = 1.9 to 5.5 V), LV (Low-voltage main) mode: 1 to 4 MHz (V _{DD} = 1.7 to 5.5 V), LP (Low-power main) mode: 1 MHz (V _{DD} = 1.9 to 5.5 V)						
	PLL clock (fPLL)			-		HS (High-spe (V _{DD} = 2.8 to	eed main) mod 5.5 V)	e: 32 MHz	
Subsystem clock	Subsystem clock oscillator clock (fsx)		oscillation, ex	-	em clock input	(EXCLKS)			
	Low-speed on-chip oscillator clock (fil.)	15 kHz (TYP	.): V _{DD} = 1.7 to	5.5V					
• .	n-chip oscillator clock rrection function	Correct the frequency of the high-speed on-chip oscillator clock by the subsystem clock.							
General-purp	ose register	8 bits × 8 registers × 4 banks							
Minimum inst	ruction execution time	0.03125 µs (l	PLL clock: fpll	= 32 MHz sele	ection)				
		0.04167 µs (l	High-speed on	-chip oscillator	: f _{IH} = 24 MHz	operation)			
		30.5 μs (Sub	system clock:	fsuв = 32.768 k	Hz operation)				
		66.6 µs (Low	-speed on-chip	o oscillator: f⊩	= 15 kHz opera	ation)			
Instruction se	t	Adder andMultiplicatiMultiplicati	on (16 bits × 1 on and accum	ulation (16 bits	n (32 bits ÷ 32 s × 16 bits + 32	2 bits)	an operation), e	etc.	
I/O port	Total	3	5		52		(68	
	CMOS I/O	2	7		44			30	
	CMOS input		5		5			5	
	CMOS output		-		-				
	N-ch O.D I/O (6 V tolerance)	;	3		3			3	

Notes 1. In the case of the 8 KB, this is about 7 KB when the self-programming function is used.

2. In the case of the 16 KB, this is about 15 KB when the self-programming function is used.

	14.		64	nin		90 nin		100	(2/3	
	Ш	em		pin		80-pin			-pin	
			R5F10NLEDFB/	R5F10NLGDFB/	R5F10NMEDFB	R5F10NMGDFB	R5F10NMJDFB	R5F10NPGDFB	R5F10NPJDF	
Timer	16	-bit timer TAU	R5F11TLEDFB	R5F11TLGDFB		8 channels				
Tillel	-	atchdog timer				1 channel				
		bit interval timer				1 channel				
			4 channels (8-bit)/2 channels (16-bit)							
		6-bit interval timer ependent power			4 channels	1 channel	ieis (To-bit)			
	sup	oply real-time ck (RTC)								
	Os	cillation stop	1 channel							
	det	ection circuit								
	Tin	ner output	Timer outputs: 8 channels PWM outputs: 7 ^{Note 1}							
	RT	C output	1 channel • 1 Hz/64 Hz (sub clock: fsx = 32.768 kHz)							
	RT inp	C time capture ut		-			3 channels			
Clock out	put/buzz	zer output				2				
			(Main syste ● 256 Hz, 51	em clock: fmain 2 Hz, 1.024 kl	= 20 MHz ope	4.096 kHz, 8.		84 kHz, 32.768	kHz	
10-bit resolution A/D converter			4 cha	annels		4 channels		6 ch	annels	
24-Bit ΔΣ	A/D Co	nverter	4 cha	annels		3 channels		4 cha	annels	
	SNDR		Typ. 80 dB (gain ×1)							
			Min. 69 dB (g	ain ×16)						
			Min. 65 dB (g	ain ×32)						
	Sampl	ing frequency	3.906 kHz/1.9	953 kHz						
	PGA		×1, ×2, ×4, ×	3, ×16, ×32						
Serial interface	-	ied SPI (CSI)/ simplified I ² C:	2 cha	annels		2 channels		3 ch	annels	
	UART/	'IrDA				1 channel		•		
	I ² C bus	3				1 channel				
32-bit mu	Itiplier a	nd multiply-	32 bits × 32 b	oits = 64 bits (L	Jnsigned or sig	gned) (5 clock)				
accumula	itor		32 bits × 32 b	oits + 64 bits =	64 bits (Unsig	ned or signed)	(5 clock)			
Data tran	sfer con	troller (DTC)			36 sources	<u> </u>	<u> </u>	38 so	ources	
Event link		Event input				9		l		
controller	(ELC)	Event trigger input				13				
LCD cont	roller/dri				ethod, capacito		, and external	resistance div	sion method	
Segment signal output		ent signal output		5) ^{Note 2}		34 (30) ^{Note 2}		42 (3	8) ^{Note 2}	
	910	on signal output	(1	- /	<u> </u>	4 (8) ^{Note 2}		(0	- /	
	Comm					· \-/				
Vectored	Comm	Internal	4	1		41		4	4	

Notes 1. The number of outputs varies, depending on the setting of channels in use and the number of the master (see 8.9.3 Operation as multiple PWM output function in the RL78/I1C User's Manual).

^{2.} The values in parentheses are the number of signal outputs when 8 com is used.

(3/3)

Item		64-	pin		80-pin		100	(3/3))-pin		
		R5F10NLEDFB/	R5F10NLGDFB/	R5F10NMEDFB	R5F10NMGDFB	R5F10NMJDFB	R5F10NPGDFB	R5F10NPJDFB		
		R5F11TLEDFB	R5F11TLGDFB							
Key interrupt input			5			8				
AES circuit ^{Note 3}		Cipher modes of operation: GCM/ECB/CBC								
		Encryption ke	ey length: 128/	192/256-bit						
Reset	MCU	Reset by F	Reset by RESET pin							
			set by watchdo	· ·						
				n-reset of inte						
				detector of inte	•	power supply				
			set by lilegal in set by RAM pa	struction exec	ution					
			-	nemory access	;					
	RTC		RTC circuit reset by RTC Power-on-reset							
Power-on-reset circuit	Internal VDD	Power-on-	Power-on-reset: 1.51 V (TYP.)							
	Note 1	Power-dov	Power-down-reset: 1.50 V (TYP.)							
	VRTC	• RTC Power-on-reset: 1.52 V (TYP.)								
	RTC Power-down-reset: 1.50 V (TYP.)									
Voltage detector	Internal VDD	Rising edg	e: 1.77 V to 4.	06 V (13 stage	es)					
	Note 1	• Falling edge: 1.73 V to 3.98 V (13 stages)								
	V _{DD}	Rising edge: 2.53 V to 3.77 V (6 stages)								
		Falling edge: 2.46 V to 3.70 V (6 stages)								
	VBAT	Rising edg	e: 2.11 V to 2.	73 V (7 stages	s)					
		Falling edg	ge: 2.05 V to 2	.67 V (7 stages	s)					
	VRTC	Rising edg	e: 2.22 V to 2.	84 V (4 stages	s)					
		Falling edg	ge: 2.16 V to 2	.78 V (4 stages	s)					
	EXLVD	Rising edg	e: 1.33 V							
		Falling edg	je: 1.28 V							
Battery backup	CPU	VDD/VBAT								
function	ΔΣ A/D Converter	VDD/VBAT								
	RTC	VRTC (indep	endent power	supply)						
On-chip debug function	1	Provided								
Power supply voltage		V _{DD} = 1.7 to 5.5 V								
Operating ambient tem	perature	T _A = -40 to +85°C								

- **Notes 1.** Either V_{DD} or VBAT is selected by the battery backup function.
 - This reset occurs when instruction code FFH is executed.
 This reset does not occur during emulation using an in-circuit emulator or an on-chip debugging emulator.
 - **3.** Only available in R5F10N products.

2. ELECTRICAL SPECIFICATIONS

- Cautions 1. The RL78 microcontrollers have an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.
 - 2. The pins mounted depend on the product. See 2.1 Port Function to 2.2.1 With functions for each product in the RL78/I1C User's Manual.
- Remarks 1. In the descriptions in this chapter, read EVDD as EVDD0 and EVDD1, and EVSs as EVSs0 and EVSs1.
 - 2. For 64-pin products, read EVDD as VDD and EVss as Vss.

2.1 Absolute Maximum Ratings

Absolute Maximum Ratings (1/3)

Parameter	Symbols	Conditions	Ratings	Unit
Supply voltage	V _{DD}		-0.5 to +6.5	V
	EV _{DD}		-0.5 to +6.5	V
	V _{BAT}		-0.5 to +6.5	V
	VRTC		-0.5 to +6.5	V
REGC pin input voltage	Virego	REGC	-0.3 to +2.8 and -0.3 to V _{DD} ^{Note 4} +0.3 ^{Note 1}	V
Input voltage	VII	P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P70 to P77, P80 to P85, P125 to P127	-0.3 to EV _{DD} +0.3 and -0.3 to V _{DD} ^{Note 4} +0.3 ^{Note 2}	V
	Vı2	P60 to P62 (N-ch open-drain)	-0.3 to +6.5	V
	Vı3	P20 to P25, P121 to P122, P137, P150 to 152, EXCLK	-0.3 to V _{DD} Note 4 +0.3Note 2	V
	V ₁₄	RESET	-0.3 to +6.5	V
	V _{I5}	P123, P124, EXCLKS	-0.3 to V _{RTC} +0.3 ^{Note 2}	V
Output voltage	Vo ₁	P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P60 to P62, P70 to P77, P80 to P85, P125 to P127	-0.3 to EV _{DD} +0.3 and -0.3 to V _{DD} ^{Note 4} +0.3 ^{Note 2}	V
	V _{O2}	P20 to P25, P150 to P152	-0.3 to V _{DD} ^{Note 4} +0.3 ^{Note 2}	V
Analog input voltage	VAI1	ANI0 to ANI5	-0.3 to $V_{DD}^{Note 4}$ +0.3 and -0.3 to $AV_{REF(+)}$ +0.3 $^{Notes 2, 3}$	V
	V _{Al2}	ANIP0 to ANIP3, ANIN0 to ANIN3	-0.6 to +2.8 and -0.6 to AREGC +0.3 ^{Note 5}	V
Reference supply voltage	VIDSAD	AREGC, AVCM, AVRT	-0.3 to +2.8 and -0.3 to V _{DD} ^{Note 4} +0.3 ^{Note 6}	V

Notes 1. Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F). This value regulates the absolute maximum rating of the REGC pin. Do not use this pin with voltage applied to it.

- 2. Must be 6.5 V or lower.
- 3. Do not exceed AVREF(+) + 0.3 V in case of A/D conversion target pin.
- **4.** Either V_{DD} or VBAT is selected by the battery backup function.
- 5. The $\Delta\Sigma$ A/D conversion target pin must not exceed AREGC +0.3 V.
- 6. Connect AREGC, AVCM, and AVRT terminals to Vss via capacitor (0.47 μF). This value defines the absolute maximum rating of AREGC, AVCM, and AVRT terminal. Do not use with voltage applied.

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

- **Remarks 1.** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.
 - 2. AV_{REF (+)}: + side reference voltage of the A/D converter.
 - 3. Vss: Reference voltage



Absolute Maximum Ratings (2/3)

Parameter	Symbols		Conditions	Ratings	Unit
LCD voltage	VLI1	V _{L1} voltage ^{Note 1}		–0.3 to 2.8 and –0.3 to V _L 4 +0.3	V
	V _{LI2}	V _{L2} voltage ^{Note 1}		-0.3 to V _{L4} +0.3 ^{Note 2}	V
	VLI3	V _{L3} voltage ^{Note 1}		-0.3 to V _{L4} +0.3 ^{Note 2}	V
	V _{LI4}	V _{L4} voltage ^{Note 1}		-0.3 to +6.5	V
	VLCAP	CAPL, CAPH vol	tage ^{Note 1}	-0.3 to V _{L4} +0.3 ^{Note 2}	V
	Vouт	COM0 to COM7, SEG0 to SEG41,	External resistance division method	-0.3 to V _{DD} Note 3 +0.3Note 2	V
		output voltage	Capacitor split method	-0.3 to V _{DD} ^{Note 3} +0.3 ^{Note 2}	V
			Internal voltage boosting method	-0.3 to V _{L4} +0.3 ^{Note 2}	V

- Notes 1. This value only indicates the absolute maximum ratings when applying voltage to the V_{L1}, V_{L2}, V_{L3}, and V_{L4} pins; it does not mean that applying voltage to these pins is recommended. When using the internal voltage boosting method or capacitance split method, connect these pins to Vss via a capacitor (0.47 μF ± 30%) and connect a capacitor (0.47 μF ± 30%) between the CAPL and CAPH pins.
 - 2. Must be 6.5 V or lower.
 - 3. Either VDD or VBAT is selected by the battery backup function.

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Remark Vss: Reference voltage

Absolute Maximum Ratings (3/3)

Parameter	Symbols		Conditions	Ratings	Unit
Output current, high	Іон1	Per pin	P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P70 to P77, P80 to P85, P125 to P127	-40	mA
		Total of all pins –170 mA	P02 to P07, P40 to P43	– 70	mA
			P10 to P17, P30 to P37, P50 to P57, P70 to P77, P80 to P85, P125 to P127	-100	mA
	І он2	Per pin	P20 to P25, P150 to P152	-0.5	mA
		Total of all pins		-2	mA
Output current, low	lol1	Per pin	P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P70 to P77, P80 to P85, P125 to P127	40	mA
		Total of all pins 170 mA	P02 to P07, P40 to P43	70	mA
			P10 to P17, P30 to P37, P50 to P57, P60 to P62, P70 to P77, P80 to P85, P125 to P127	100	mA
	lo _{L2}	Per pin	P20 to P25, P150 to P152	1	mA
		Total of all pins		5	mA
Operating ambient	TA	In normal operati	on mode	-40 to +85	°C
temperature		In flash memory	programming mode		
Storage temperature	T _{stg}			-65 to +150	°C

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

2.2 Oscillator Characteristics

2.2.1 X1, XT1 oscillator characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le V_{DD}^{Note 2} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$

Parameter	Resonator	Conditions	MIN.	TYP.	MAX.	Unit
X1 clock oscillation frequency (fx) ^{Notes 1, 2}	Ceramic resonator/	2.7 V ≤ V _{DD} ≤ 5.5 V	1.0		20.0	MHz
	crystal resonator	2.5 V ≤ V _{DD} < 2.7 V	1.0		16.0	MHz
		2.4 V ≤ V _{DD} < 2.5 V	1.0		12.0	MHz
		1.9 V ≤ V _{DD} < 2.4 V	1.0		8.0	MHz
		1.7 V ≤ V _{DD} < 1.9 V	1.0		4.0	MHz
XT1 clock oscillation frequency (f _{XT}) ^{Notes 1, 2}	Crystal resonator		32	32.768	35	kHz

- **Notes 1.** Indicates only permissible oscillator frequency ranges. See **2.4 AC Characteristics** for instruction execution time. Request evaluation by the manufacturer of the oscillator circuit mounted on a board to check the oscillator characteristics.
 - 2. Either VDD or VBAT is selected by the battery backup function.

Caution Since the CPU is started by the high-speed on-chip oscillator clock after a reset release, check the X1 clock oscillation stabilization time using the oscillation stabilization time counter status register (OSTC) by the user. Determine the oscillation stabilization time of the OSTC register and the oscillation stabilization time select register (OSTS) after sufficiently evaluating the oscillation stabilization time with the resonator to be used.

Remark When using the X1 oscillator and XT1 oscillator, see 6.4 System Clock Oscillator in the RL78/I1C User's Manual.

2.2.2 On-chip oscillator characteristics

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le V_{DD}^{Note 3} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$

Oscillators	Parameters		Conditions	MIN.	TYP.	MAX.	Unit
High-speed on-chip oscillator clock frequency ^{Notes 1, 2}	fін			1.5		24	MHz
High-speed on-chip oscillator		–20 to +85°C	$1.9 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 3}} \leq 5.5 \text{ V}$	-1.0		+1.0	%
clock frequency accuracy			$1.7 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 3}} \leq 1.9 \text{ V}$	-5.0		+5.0	%
		–40 to –20°C	$1.9 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 3}} \leq 5.5 \text{ V}$	-1.5		+1.5	%
			$1.7 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 3}} \leq 1.9 \text{ V}$	-5.5		+5.5	%
Middle-speed on-chip oscillator clock frequency ^{Note 2}	fім			1		4	MHz
Middle-speed on-chip oscillator clock frequency accuracy		1.9 V ≤ V _{DD} Note 3 ≤	5.5 V	-12		+12	%
Low-speed on-chip oscillator clock frequency	fı∟				15		kHz
Low-speed on-chip oscillator clock frequency accuracy				-15		+15	%

- **Notes 1.** The high-speed on-chip oscillator frequency is selected by using bits 0 to 3 of option byte (000C2H/010C2H) and bits 0 to 2 of the HOCODIV register.
 - 2. This indicates the oscillator characteristics only. See 2.4 AC Characteristics for the instruction execution time.
 - 3. Either VDD or VBAT is selected by the battery backup function.

2.2.3 PLL oscillator characteristics

(T_A = -40 to +85°C, 2.7 V \leq V_{DD}Note 2 \leq 5.5 V, Vss = 0 V)

Oscillators	Parameters	Conditions	MIN.	TYP.	MAX.	Unit
PLL input frequency Note 1	f _{PLLIN}	fін		4		MHz
PLL output frequency Note 1	fpll			32		MHz
Lockup wait time		Wait time from PLL output enable to frequency stabilization	40			μs
Interval wait time		Wait time from PLL stop to PLL restart setting	4			μs
Setting wait time		Wait time from PLL input clock stabilization and PLL setting fixedness to start-up setting	1			μs

Notes 1. Indicates only permissible oscillator frequency ranges.

2. Either VDD or VBAT is selected by the battery backup function.

2.3 DC Characteristics

2.3.1 Pin characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}_{DD0} = \text{EV}_{DD1} \le \text{V}_{DD}^{Note 4} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS0} = \text{EV}_{SS1} = 0 \text{ V})$

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output current, high ^{Note 1}	Іон1	Per pin for P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P70 to P77, P80 to P85, P125 to P127	1.9 V ≤ EV _{DD} ≤ 5.5 V			-10.0 ^{Note 2}	mA
		Total of P02 to P07, P40 to P43	4.0 V ≤ EV _{DD} ≤ 5.5 V			-55.0	mA
		(When duty ≤ 70% ^{Note 3})	2.7 V ≤ EV _{DD} < 4.0 V			-10.0	mA
			1.9 V ≤ EV _{DD} < 2.7 V			-5.0	mA
			1.7 V ≤ EV _{DD} < 1.9 V			-2.5	mA
		P57, P70 to P77, P80 to P85, P125 to P127 (When duty ≤ 70% ^{Note 3})	4.0 V ≤ EV _{DD} ≤ 5.5 V			-80.0	mA
			2.7 V ≤ EV _{DD} < 4.0 V			-19.0	mA
			1.9 V ≤ EV _{DD} < 2.7 V			-10.0	mA
			1.7 V ≤ EV _{DD} < 1.9 V			-5.0	mA
		Total of all pins (When duty ≤ 70% ^{Note 3})				-100.0	mA
	І он2	Per pin for P20 to P25, P150 to P152	1.7 V ≤ V _{DD} ^{Note 4} ≤ 5.5 V		_	-0.1 ^{Note 2}	mA
	Total of all pins (When duty ≤ 70% Note 3)		1.7 V ≤ V _{DD} Note 4 ≤ 5.5 V			-0.9	mA

- **Notes 1**. Value of current at which the device operation is guaranteed even if the current flows from the EV_{DD} and V_{DD} pins to an output pin.
 - 2. Do not exceed the total current value.
 - 3. Specification under conditions where the duty factor $\leq 70\%$.

The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

• Total output current of pins = (IoH × 0.7)/(n × 0.01)

<Example> Where n = 80% and Ioн = -10.0 mA

Total output current of pins = $(-10.0 \times 0.7)/(80 \times 0.01) \cong -8.7$ mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor.

A current higher than the absolute maximum rating must not flow into one pin.

4. Either VDD or VBAT is selected by the battery backup function.

Caution P02 to P07, P12 to P17, P31, P56, P57, P80 to P82, P84, and P85 do not output high level in N-ch open-drain mode.

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}_{\text{DD0}} = \text{EV}_{\text{DD1}} \le \text{V}_{\text{DD}}^{\text{Note } 4} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{\text{SS0}} = \text{EV}_{\text{SS1}} = 0 \text{ V})$

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output current, low ^{Note 1}	lol1	Per pin for P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P70 to P77, P80 to P85, P125 to P127				20.0 ^{Note 2}	mA
		Per pin for P60 to P62				15.0 ^{Note 2}	mA
		Total of P02 to P07, P40 to P43	4.0 V ≤ EV _{DD} ≤ 5.5 V			70.0	mA
		(When duty ≤ 70% ^{Note 3})	2.7 V ≤ EV _{DD} < 4.0 V			15.0	mA
			1.9 V ≤ EV _{DD} < 2.7 V			9.0	mA
		Total of P10 to P17, P30 to P37, P50 to P57, P60 to P62, P70 to P77, P80 to P85, P125 to P127	1.7 V ≤ EV _{DD} < 1.9 V			4.5	mA
			4.0 V ≤ EV _{DD} ≤ 5.5 V			80.0	mA
			2.7 V ≤ EV _{DD} < 4.0 V			35.0	mA
			1.9 V ≤ EV _{DD} < 2.7 V			20.0	mA
		,	1.7 V ≤ EV _{DD} < 1.9 V			10.0	mA
		Total of all pins (When duty ≤ 70% ^{Note 3})				150.0	mA
	lol2	Per pin for P20 to P25, P150 to P152	1.7 V ≤ V _{DD} ^{Note 4} ≤ 5.5 V			0.4 ^{Note 2}	mA
		Total of all pins (When duty ≤ 70% ^{Note 3})	1.7 V ≤ V _{DD} ^{Note 4} ≤ 5.5 V			3.6	mA

- **Notes 1**. Value of current at which the device operation is guaranteed even if the current flows from an output pin to the EVss and Vss pins.
 - 2. However, do not exceed the total current value.
 - 3. Specification under conditions where the duty factor ≤ 70%.

The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

Total output current of pins = (loL × 0.7)/(n × 0.01)

<Example> Where n = 80% and IoL = 10.0 mA

Total output current of pins = $(10.0 \times 0.7)/(80 \times 0.01) \approx 8.7$ mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

4. Either VDD or VBAT is selected by the battery backup function.

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}_{DD0} = \text{EV}_{DD1} \le \text{V}_{DD}^{Note} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS0} = \text{EV}_{SS1} = 0 \text{ V})$

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Input voltage, high	V _{IH1}	P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P70 to P77, P80 to P85, P125 to P127	Normal input buffer	0.8EV _{DD}		EV _{DD}	V
	V _{IH2}	P02, P03, P05, P06, P12, P13, P15, P16, P30, P55, P57, P80, P81, P84	TTL input buffer 4.0 V ≤ EV _{DD} ≤ 5.5 V	2.2		EV _{DD}	V
			TTL input buffer 3.3 V ≤ EV _{DD} < 4.0 V	2.0		EV _{DD}	V
			TTL input buffer 1.7 V ≤ EV _{DD} < 3.3 V	1.5		EV _{DD}	V
	VIH3	P20 to P25		0.7V _{DD} Note		V _{DD} Note	V
	V _{IH4}	P60 to P62		0.7EV _{DD}		6.0	V
	V _{IH5}	P121 to P122, P137, P150 to P152, E	0.8V _{DD} Note		V _{DD} Note	V	
	VIH6	RESET	0.8V _{DD} Note		6.0	V	
	V _{IH7}	P123, P124, EXCLKS		0.8VRTC		VRTC	V
Input voltage, low	VIL1	P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P70 to P77, P80 to P85, P125 to P127	Normal input buffer	0		0.2EV _{DD}	V
	VIL2	P02, P03, P05, P06, P12, P13, P15, P16, P30, P55, P57, P80, P81, P84	TTL input buffer 4.0 V ≤ EV _{DD} ≤ 5.5 V	0		0.8	V
			TTL input buffer 3.3 V ≤ EV _{DD} < 4.0 V	0		0.5	V
		TTL input buffer 1.7 V ≤ EV _{DD} < 3.3 V		0		0.32	V
	V _{IL3}	P20 to P25		0		0.3V _{DD} Note	V
	VIL4	P60 to P62		0		0.3EV _{DD}	V
	V _{IL5}	P121, P122, P137, P150 to P152, EX	CCLK, RESET	0		0.2V _{DD} Note	V
	VIL6	P123, P124, EXCLKS		0		0.2VRTC	V

 $\textbf{Note} \quad \text{Either V_{DD} or VBAT is selected by the battery backup function}.$

Caution The maximum value of V_{IH} of pins P02 to P07, P12 to P17, P31, P56, P57, P80 to P82, P84, and P85 is EV_{DD}, even in the N-ch open-drain mode.

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}_{\text{DD0}} = \text{EV}_{\text{DD1}} \le \text{V}_{\text{DD}}^{\text{Note}} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{\text{SS0}} = \text{EV}_{\text{SS1}} = 0 \text{ V})$

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output voltage, high	Vон1	P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P70 to P77,	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $I_{OH1} = -10.0 \text{ mA}$	EV _{DD} – 1.5			V
		P80 to P85, P125 to P127	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $I_{OH1} = -3.0 \text{ mA}$	EV _{DD} - 0.7			V
			$2.7 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $I_{OH1} = -2.0 \text{ mA}$	EV _{DD} - 0.6			V
			1.9 V ≤ EV _{DD} ≤ 5.5 V, I _{OH1} = −1.5 mA	EV _{DD} - 0.5			V
			1.7 V ≤ EV _{DD} ≤ 5.5 V, I _{OH1} = −1.0 mA	EV _{DD} - 0.5			V
	V _{OH2}	P20 to P25, P150 to P152	$1.7 \text{ V} \le \text{V}_{\text{DD}}^{\text{Note}} \le 5.5 \text{ V},$ $I_{\text{OH2}} = -100 \mu\text{A}$	V _{DD} - 0.5			V
Output voltage, low	V _{OL1}	P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P70 to P77,	•			1.3	V
		P80 to P85, P125 to P127	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $I_{OL1} = 8.5 \text{ mA}$			0.7	V
			$2.7 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $I_{OL1} = 3.0 \text{ mA}$			0.6	V
			$2.7 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $I_{OL1} = 1.5 \text{ mA}$			0.4	V
			1.9 V ≤ EV _{DD} ≤ 5.5 V, I _{OL1} = 0.6 mA			0.4	V
			1.7 V ≤ EV _{DD} ≤ 5.5 V, I _{OL1} = 0.3 mA			0.4	V
	V _{OL2}	P20 to P25, P150 to P152	$1.7 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note}} \leq 5.5 \text{ V},$ $I_{\text{OL2}} = 400 \mu\text{A}$			0.4	V
	V _{OL3}	P60 to P62	4.0 V ≤ EV _{DD} ≤ 5.5 V, I _{OL3} = 15.0 mA			2.0	V
			4.0 V ≤ EV _{DD} ≤ 5.5 V, I _{OL3} = 5.0 mA			0.4	V
			2.7 V ≤ EV _{DD} ≤ 5.5 V, lo _{L3} = 3.0 mA			0.4	V
			1.9 V ≤ EV _{DD} ≤ 5.5 V, lo _{L3} = 2.0 mA			0.4	V
			1.7 V ≤ EV _{DD} ≤ 5.5 V, lo _{L3} = 1.0 mA			0.4	V

Note Either VDD or VBAT is selected by the battery backup function.

Caution P02 to P07, P12 to P17, P31, P56, P57, P80 to P82, P84, and P85 do not output high level in N-ch open-drain mode.

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}_{\text{DD0}} = \text{EV}_{\text{DD1}} \le \text{V}_{\text{DD}}^{\text{Note}} \le 5.5 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS0}} = \text{EV}_{\text{SS1}} = 0 \text{ V})$

Items	Symbol	Condi	MIN.	TYP.	MAX.	Unit		
Input leakage current, high	Ішнт	P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P60 to P62, P70 to P77, P80 to P85, P125 to P127	V _I = EV _{DD}				1	μΑ
	ILIH2	P20 to P25, P137, P150 to P152, RESET	$V_I = V_{DD}^{Note}$				1	μΑ
	Ішнз	P121, P122 (X1, X2, EXCLK)	$V_{I} = V_{DD}^{Note}$	In input port or external clock input			1	μΑ
				In resonator connection			10	μΑ
	ILIH4	P123, P124 (EXCLKS)	VI = VRTC	In input port or external clock input			1	μΑ
				In resonator connection			10	μΑ
Input leakage current, low	ILIL1	P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P70 to P77, P80 to P85, P125 to P127	Vı = EVss				-1	μΑ
	ILIL2	P20 to P25, P137, P150 to P152, RESET	VI = VSS				-1	μΑ
	Ішз	P121, P122 (X1, X2, EXCLK)	VI = VSS	In input port or external clock input			-1	μА
				In resonator connection			-10	μΑ
	ILIL4	P123, P124 (EXCLKS)	VI = VSS	In input port or external clock input			-1	μΑ
				In resonator connection			-10	μΑ
On-chip pull-	Ru ₁	P10 to P17, P30 to P37, P50 to P57,	Vı = EVss	2.4 V ≤ EV _{DD} ≤ 5.5 V	10	20	100	kΩ
up resistance		P70 to P77, P80 to P85, P125 to P127		1.7 V ≤ EV _{DD} ≤ 5.5 V	10	30	100	kΩ
	Ru2	P02 to P07, P40 to P43, P150 to P152	Vı = EVss		10	20	100	kΩ

 $\textbf{Note} \quad \text{Either V_{DD} or VBAT is selected by the battery backup function}.$

2.3.2 Supply current characteristics

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}_{DD0} = \text{EV}_{DD1} \le \text{V}_{DD}^{Note 8} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS0} = \text{EV}_{SS1} = 0 \text{ V})$ (1/6)

Parameter	Symbol			Conditions			MIN.	TYP.	MAX.	Unit
Supply	I _{DD1}	Operating	HS (high-	fclk = 32 MHz ^{Note 3}	Normal	V _{DD} = 5.0 V		5.2	8.5	mA
current ^{Note 1}		mode	speed main)	PLL operation	operation	V _{DD} = 3.0 V		5.2	8.5	mA
			mode ^{Note 5}	f _{IH} = 24 MHz ^{Note 3}	Basic	V _{DD} = 5.0 V		1.7		mA
					operation	$V_{DD} = 3.0 \text{ V}$		1.7		mA
					Normal	V _{DD} = 5.0 V		3.9	6.6	mA
					operation	V _{DD} = 3.0 V		3.9	6.6	mA
				f _{IH} = 12 MHz ^{Note 3}	Normal	$V_{DD} = 5.0 \text{ V}$		2.4	3.8	mA
					operation	$V_{DD} = 3.0 \text{ V}$		2.4	3.8	mA
				speed main)	Normal	V _{DD} = 5.0 V		1.7	2.6	mA
					operation	$V_{DD} = 3.0 \text{ V}$		1.7	2.6	mA
					Normal	$V_{DD} = 5.0 \text{ V}$		1.3	2.0	mA
					operation	$V_{DD} = 3.0 \text{ V}$		1.3	2.0	mA
			speed main) mode ^{Note 5}		Normal	$V_{DD} = 3.0 \text{ V}$		1.3	2.2	mA
					operation	$V_{DD} = 2.0 \text{ V}$		1.3	2.2	mA
				f _{IH} = 6 MHz ^{Note 3}	Normal	$V_{DD} = 3.0 \text{ V}$		1.1	2.1	mA
				f _{IH} = 4 MHz ^{Note 3}	operation	$V_{DD} = 2.0 \text{ V}$		1.1	2.1	mA
					Normal	$V_{DD} = 3.0 \text{ V}$		0.84	1.40	mA
					operation	$V_{DD} = 2.0 \text{ V}$		0.84	1.40	mA
				f _{IM} = 4 MHz ^{Note 6}	Normal	$V_{DD} = 3.0 \text{ V}$		0.70	1.20	mA
					operation	$V_{DD} = 2.0 \text{ V}$		0.70	1.20	mA
				f _{IH} = 3 MHz ^{Note 3}	Normal	$V_{DD} = 3.0 \text{ V}$		0.7	1.4	mA
					operation	$V_{DD} = 2.0 \text{ V}$		0.7	1.4	mA
			LV (low-	f _{IH} = 4 MHz ^{Note 3}	Normal	$V_{DD} = 3.0 \text{ V}$		1.3	1.9	mA
			voltage main) mode ^{Note 5}		operation	V _{DD} = 2.0 V		1.3	1.9	mA
			LP (low-	f _{IH} = 1 MHz ^{Note 3}	Normal	$V_{DD} = 3.0 \text{ V}$		315	530	μΑ
			power main)		operation	$V_{DD} = 2.0 \text{ V}$		315	530	μΑ
			mode ^{Note 5}	f _{IM} = 1 MHz ^{Note 6}	Normal	$V_{DD} = 3.0 \text{ V}$		160	300	μΑ
					operation	$V_{DD} = 2.0 \text{ V}$		160	300	μΑ

(Notes and Remarks are listed on the page after the next page.)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}_{\text{DD0}} = \text{EV}_{\text{DD1}} \le \text{V}_{\text{DD}}^{\text{Note 8}} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{\text{SS0}} = \text{EV}_{\text{SS1}} = 0 \text{ V})$

(2/6)

•	Symbol	1		Conditions	<u> </u>	- EV550 - EV551 -	MIN.	TYP.	MAX.	Unit
Supply	I _{DD1}	Operating	HS (high-	f _{MX} = 20 MHz ^{Note 2} ,	Normal	Square wave input	IVIII V.	3.3	5.5	mA
current ^{Note 1}	IDD1	mode	speed main)	· · · · · · · · · · · · · · · · · · ·	operation	Resonator connection		3.5	5.7	mA
			mode ^{Note 5}	f _{MX} = 20 MHz ^{Note 2} ,	Normal	Square wave input		3.3	5.5	mA
				V _{DD} = 3.0 V	operation	Resonator connection		3.5	5.7	mA
				f _{MX} = 16 MHz ^{Note 2} .	Normal	Square wave input		2.8	4.4	mA
				V _{DD} = 5.0 V	operation	Resonator connection		2.9	4.6	mA
				f _{MX} = 16 MHz ^{Note 2} ,	Normal	Square wave input		2.8	4.4	mA
				V _{DD} = 3.0 V	operation	Resonator connection		2.9	4.6	mA
				f _{MX} = 12 MHz ^{Note 2} .	Normal	Square wave input		2.3	3.6	mA
				V _{DD} = 5.0 V	operation	Resonator connection		2.4	3.7	mA
				$f_{MX} = 12 \text{ MHz}^{\text{Note 2}},$ Normal $V_{\text{DD}} = 3.0 \text{ V}$ operation	Normal	Square wave input		2.3	3.6	mA
					operation	Resonator connection		2.4	3.7	mA
				f _{MX} = 10 MHz ^{Note 2} ,	Normal	Square wave input		2.0	3.2	mA
				V _{DD} = 5.0 V	operation	Resonator connection		2.1	3.3	mA
				f _{MX} = 10 MHz ^{Note 2} ,	Normal	Square wave input		2.0	3.2	mA
				V _{DD} = 3.0 V	operation	Resonator connection		2.1	3.3	mA
			speed main)	f _{MX} = 8 MHz ^{Note 2} ,	Normal	Square wave input		1.1	2.0	mA
				V _{DD} = 3.0 V	operation	Resonator connection		1.2	2.1	mA
				f _{MX} = 8 MHz ^{Note 2} ,	Normal	Square wave input		1.1	2.0	mA
			V _{DD} = 2.0 V	operation	Resonator connection		1.2	2.1	mA	
			f _{MX} = 4 MHz ^{Note 2} ,	Normal	Square wave input		0.7	1.2	mA	
				V _{DD} = 3.0 V	operation	Resonator connection		0.7	1.3	mA
				f _{MX} = 4 MHz ^{Note 2} ,	Normal	Square wave input		0.7	1.2	mA
				V _{DD} = 2.0 V	operation	Resonator connection		0.7	1.3	mA
			LP (low-	f _{IH} = 1 MHz ^{Note 2} ,	Normal	Square wave input		140	240	μA
			power main)	V _{DD} = 3.0 V	operation	Resonator connection		190	300	μA
			mode ^{Note 5}	f _{IH} = 1 MHz ^{Note 2} ,	Normal	Square wave input		140	240	μA
				V _{DD} = 2.0 V	operation	Resonator connection		190	300	μΑ
			Subclock	fsub = 32.768 kHz ^{Note 4} ,	Normal	Square wave input		5.1	6.6	μΑ
			operation	$T_A = -40^{\circ}C$	operation	Resonator connection		5.2	6.7	μA
				fsuB = 32.768 kHz ^{Note 4} ,	Normal	Square wave input		5.4	7.1	μA
				T _A = +25°C	operation	Resonator connection		5.5	7.2	μA
				fsub = 32.768 kHz ^{Note 4} ,	Normal	Square wave input		5.6	8.0	μΑ
				T _A = +50°C	operation	Resonator connection		5.7	8.1	μA
				fsuB = 32.768 kHz ^{Note 4} ,	Normal	Square wave input		6.1	9.7	μA
				$T_A = +70^{\circ}C$	operation	Resonator connection		6.2	9.8	μΑ
				fsuB = 32.768 kHz ^{Note 4} ,	Normal	Square wave input		6.8	13.7	μA
				T _A = +85°C	operation	Resonator connection		6.9	13.8	μA
				f _{IL} = 15 kHz, T _A = +85°C Note 7	Normal operation			2.5	7.0	μA
			fiL =	$f_{IL} = 15 \text{ kHz},$ $T_A = -40^{\circ} \text{C}^{\text{Note 7}}$	Normal operation			2.8	7.0	μA
				f _{IL} = 15 kHz, T _A =+ 25°C Note 7	Normal operation			4.1	11.0	μA

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(Notes and Remarks are listed on the next page.)

- Notes 1. Total current flowing into VDD, EVDD, and VRTC including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDD or Vss, EVss. When the VBAT pin (pin for battery backup) is selected, current flowing into VBAT. The following points apply in the HS (high-speed main), LS (low-speed main), LV (low-voltage main), and LP (low-power main) modes.
 - •The currents in the "TYP." column do not include the operating currents of the peripheral modules.
 - The currents in the "MAX." column include the operating currents of the peripheral modules, except for those flowing into the LCD controller/driver, A/D converter, $\Delta\Sigma$ A/D converter, LVD circuit, battery backup circuit, I/O port, and on-chip pull-up/pull-down resistors, and those flowing while the data flash memory is being rewritten. In the subsystem clock operation, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules. However, in HALT mode, including the current flowing into the independent power supply RTC.
 - 2. When high-speed on-chip oscillator, middle-speed on-chip oscillator, low-speed on-chip oscillator, and subsystem clock are stopped.
 - **3.** When high-speed system clock, middle-speed on-chip oscillator, low-speed on-chip oscillator, and subsystem clock are stopped.
 - **4.** When high-speed on-chip oscillator, middle-speed on-chip oscillator, and high-speed system clock are stopped. When setting ultra-low current consumption (AMPHS1 = 1).
 - 5. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: 2.8 V ≤ V_{DD} ≤ 5.5 V@1 MHz to 32 MHz

 $2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V} @1 \text{ MHz to } 24 \text{ MHz}$ $2.5 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V} @1 \text{ MHz to } 16 \text{ MHz}$ $2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V} @1 \text{ MHz to } 12 \text{ MHz}$ $2.1 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V} @1 \text{ MHz to } 6 \text{ MHz}$

LS (low-speed main) mode: $1.9 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}_{\odot}1 \text{ MHz}$ to 8 MHz

LP (low-power main) mode: 1.9 V ≤ V_{DD} ≤ 5.5 V@1 MHz

LV (low-voltage main) mode: 1.7 V ≤ V_{DD} ≤ 5.5 V@1 MHz to 4 MHz

- **6.** When high-speed on-chip oscillator, low-speed on-chip oscillator, high-speed system clock, and subsystem clock are stopped.
- 7. When high-speed on-chip oscillator, middle-speed on-chip oscillator, high-speed system clock, and subsystem clock are stopped.
- 8. Either VDD or VBAT is selected by the battery backup function.
- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
 - 2. fin: High-speed on-chip oscillator clock frequency
 - 3. fim: Middle-speed on-chip oscillator clock frequency
 - 4. fil: Low-speed on-chip oscillator clock frequency
 - 5. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - 6. Except subsystem clock operation, temperature condition of the TYP. value is TA = 25°C

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}_{\text{DD0}} = \text{EV}_{\text{DD1}} \le \text{V}_{\text{DD}}^{\text{Note 10}} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{\text{SS0}} = \text{EV}_{\text{SS1}} = 0 \text{ V})$ (3/6)

Parameter	Symbol			Conditions		MIN.	TYP.	MAX.	Unit
Supply	I _{DD2} Note 2		HS (high-	fclk = 32 MHz ^{Note 4} ,	V _{DD} = 5.0 V		0.80	2.0	mA
current ^{Note 1}			speed main)	PLL operation	V _{DD} = 3.0 V		0.80	2.0	mA
			mode ^{Note 7}	f _{IH} = 24 MHz ^{Note 4}	V _{DD} = 5.0 V		0.48	1.45	mA
					V _{DD} = 3.0 V		0.48	1.45	mA
				f _{IH} = 12 MHz ^{Note 4}	V _{DD} = 5.0 V		0.37	0.91	mA
					V _{DD} = 3.0 V		0.37	0.91	mA
				f _{IH} = 6 MHz ^{Note 4}	V _{DD} = 5.0 V		0.32	0.63	mA
					V _{DD} = 3.0 V		0.32	0.63	mA
				f _{IH} = 3 MHz ^{Note 4}	V _{DD} = 5.0 V		0.29	0.49	mA
					V _{DD} = 3.0 V		0.29	0.49	mA
			LS (low-	f _{IH} = 8 MHz ^{Note 4}	V _{DD} = 3.0 V		280	740	μA
			speed main)		V _{DD} = 2.0 V		280	740	μΑ
			mode ^{Note 7}	f _{IH} = 6 MHz ^{Note 4}	V _{DD} = 3.0 V		230	620	μA
					V _{DD} = 2.0 V		230	620	μA
				f _{IH} = 4 MHz ^{Note 4}	V _{DD} = 3.0 V		220	440	μA
					V _{DD} = 2.0 V		220	440	μA
				f _{IM} = 4 MHz ^{Note 5}	V _{DD} = 3.0 V		55	300	μΑ
					V _{DD} = 2.0 V		55	300	μΑ
				f _{IH} = 3 MHz ^{Note 4}	V _{DD} = 3.0 V		200	534	μΑ
					V _{DD} = 2.0 V		200	534	μΑ
			LV (low-	f _{IH} = 4 MHz ^{Note 4}	V _{DD} = 3.0 V		450	825	μA
			voltage main) mode ^{Note 7} LP (low- power main) mode ^{Note 7}		V _{DD} = 2.0 V		450	825	μA
				f _{IH} = 1 MHz ^{Note 4}	V _{DD} = 3.0 V		195	400	μA
					V _{DD} = 2.0 V		195	400	μA
				f _{IM} = 1 MHz ^{Note 5}	V _{DD} = 3.0 V		33	100	μA
					V _{DD} = 2.0 V		33	100	μA
			HS (high-	f _{MX} = 20 MHz ^{Note 3} ,	Square wave input		0.31	1.08	mA
			speed main)	V _{DD} = 5.0 V	Resonator connection		0.48	1.28	mA
			mode ^{Note 7}	f _{MX} = 20 MHz ^{Note 3} ,	Square wave input		0.31	1.08	mA
				V _{DD} = 3.0 V	Resonator connection		0.48	1.28	mA
				$f_{MX} = 16 \text{ MHz}^{\text{Note 3}},$	Square wave input		0.28	0.86	mA
				V _{DD} = 5.0 V	Resonator connection		0.42	1.00	mA
				$f_{MX} = 16 \text{ MHz}^{\text{Note 3}},$	Square wave input		0.28	0.86	mA
				V _{DD} = 3.0 V	Resonator connection		0.42	1.00	mA
				$f_{MX} = 12 \text{ MHz}^{\text{Note 3}},$	Square wave input		0.23	0.70	mA
				V _{DD} = 5.0 V	Resonator connection		0.37	0.79	mA
				$f_{MX} = 12 \text{ MHz}^{Note 3},$	Square wave input		0.23	0.70	mA
				V _{DD} = 3.0 V	Resonator connection		0.36	0.79	mA
			V _D	$f_{MX} = 10 \text{ MHz}^{\text{Note 3}},$	Square wave input		0.21	0.63	mA
				V _{DD} = 5.0 V	Resonator connection		0.29	0.71	mA
				$f_{MX} = 10 \text{ MHz}^{\text{Note 3}},$ $V_{DD} = 3.0 \text{ V}$	Square wave input		0.21	0.63	mA
				ע 3.0 – טעע – 3.0 V	Resonator connection		0.28	0.71	mA

(Notes and Remarks are listed on the page after the next page.)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}_{DD0} = \text{EV}_{DD1} \le \text{V}_{DD}^{Note 10} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS0} = \text{EV}_{SS1} = 0 \text{ V})$ (4/6)

Parameter	Symbol			Conditions		MIN.	TYP.	MAX.	Unit
Supply			LS (low-	$f_{MX} = 8 \text{ MHz}^{\text{Note 3}},$	Square wave input		110	360	μΑ
current ^{Note 1}		mode	speed main)	$V_{DD} = 3.0 \text{ V}$	Resonator connection		160	420	μΑ
			mode ^{Note 7}	$f_{MX} = 8 \text{ MHz}^{\text{Note 3}},$	Square wave input		110	360	μA
				V _{DD} = 2.0 V	Resonator connection		160	420	μΑ
				$f_{MX} = 4 \text{ MHz}^{\text{Note 3}},$	Square wave input		39	200	μA
				V _{DD} = 3.0 V	Resonator connection		81	250	μΑ
				$f_{MX} = 4 \text{ MHz}^{\text{Note 3}},$	Square wave input		39	200	μΑ
				$V_{DD} = 2.0 \text{ V}$	Resonator connection		81	250	μA
			LP (low- power main)	$f_{MX} = 1 \text{ MHz}^{\text{Note 3}},$	Square wave input		14	100	μΑ
				$V_{DD} = 3.0 \text{ V}$	Resonator connection		70	200	μΑ
			mode ^{Note 7}	$f_{MX} = 1 \text{ MHz}^{\text{Note 3}},$	Square wave input		14	100	μA
				$V_{DD} = 2.0 \text{ V}$	Resonator connection		70	200	μA
			Subsystem	fsub = 32.768 kHz ^{Note 6} ,	Square wave input		0.80	1.60	μA
			clock operation	$T_A = -40^{\circ}C$	Resonator connection		1.00	1.80	μΑ
				$f_{SUB} = 32.768 \text{ kHz}^{Note 6},$ $T_A = +25^{\circ}\text{C}$	Square wave input		0.93	1.70	μΑ
					Resonator connection		1.13	1.90	μΑ
				f _{SUB} = 32.768 kHz ^{Note 6} ,	Square wave input		1.10	3.00	μΑ
				$T_A = +50^{\circ}\text{C}$ $f_{SUB} = 32.768 \text{ kHz}^{\text{Note 6}},$ $T_A = +70^{\circ}\text{C}$ $f_{SUB} = 32.768 \text{ kHz}^{\text{Note 6}},$	Resonator connection		1.30	3.20	μΑ
					Square wave input		1.50	5.00	μΑ
					Resonator connection		1.70	5.20	μΑ
					Square wave input		2.80	9.00	μΑ
				T _A = +85°C	Resonator connection		3.00	9.20	μΑ
				fı∟ = 15 kHz ^{Note 9} ,			0.78	1.60	μΑ
				T _A = -40°C					μΑ
				f _{IL} = 15 kHz ^{Note 9} ,			1.01	1.76	μΑ
				T _A = +25°C					μΑ
	IDD3 STOP mode ^{Note 8}			f _{IL} = 15 kHz ^{Note 9} ,			2.25	8.45	μΑ
				T _A = +85°C					μΑ
			T _A = -40°C				0.47	0.90	μA
			T _A = +25°C				0.65	1.20	μΑ
			T _A = +50°C				0.84	2.80	μA
		Т,	T _A = +70°C				1.21	4.70	μA
	T _A = +85°C						1.82	9.00	μΑ

(Notes and Remarks are listed on the next page.)

- Notes 1. Total current flowing into VDD, EVDD, and VRTC including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDD or Vss, EVss. When the VBAT pin (pin for battery backup) is selected, current flowing into VBAT. The following points apply in the HS (high-speed main), LS (low-speed main), LV (low-voltage main), and LP (low-power main) modes.
 - •The currents in the "TYP." column do not include the operating currents of the peripheral modules.
 - The currents in the "MAX." column include the operating currents of the peripheral modules, except for those flowing into LCD controller/driver, the A/D converter, $\Delta\Sigma$ A/D converter, LVD circuit, battery backup circuit, I/O port, and on-chip pull-up/pull-down resistors, and those flowing while the data flash memory is being rewritten. In the subsystem clock operation, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules. However, in HALT mode, including the current flowing into the independent power supply RTC.
 - In the STOP mode, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules.
 - 2. During HALT instruction execution by flash memory.
 - **3.** When high-speed on-chip oscillator, middle-speed on-chip oscillator, low-speed on-chip oscillator, and subsystem clock are stopped.
 - **4.** When high-speed system clock, middle-speed on-chip oscillator, low-speed on-chip oscillator, and subsystem clock are stopped.
 - **5.** When high-speed on-chip oscillator, low-speed on-chip oscillator, high-speed system clock, and subsystem clock are stopped.
 - **6.** When operating independent power supply RTC and setting ultra-low current consumption (AMPHS1 = 1). When high-speed on-chip oscillator, middle-speed on-chip oscillator, and high-speed system clock are stopped.
 - 7. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: 2.8 V ≤ VDD ≤ 5.5 V@1 MHz to 32 MHz

 $2.7 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V@1 MHz to 24 MHz}$

 $2.5 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V@1 MHz to 16 MHz}$

 $2.4 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V} @ 1 \text{ MHz to } 12 \text{ MHz}$

 $2.1 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V} @ 1 \text{ MHz to } 6 \text{ MHz}$

LS (low-speed main) mode: 1.9 V ≤ V_{DD} ≤ 5.5 V@1 MHz to 8 MHz

LP (low-power main) mode: 1.9 V ≤ V_{DD} ≤ 5.5 V@1 MHz

LV (low-voltage main) mode: 1.7 V ≤ V_{DD} ≤ 5.5 V@1 MHz to 4 MHz

- **8.** If operation of the subsystem clock when STOP mode, same as when HALT mode of subsystem clock operation.
- 9. When high-speed on-chip oscillator, middle-speed on-chip oscillator, and high-speed system clock are stopped.
- **10.** Either V_{DD} or VBAT is selected by the battery backup function.
- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
 - 2. fin: High-speed on-chip oscillator clock frequency
 - 3. fim: Middle-speed on-chip oscillator clock frequency
 - 4. fil: Low-speed on-chip oscillator clock frequency
 - 5. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - **6.** Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is $T_A = 25^{\circ}C$

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}_{DD0} = \text{EV}_{DD1} \le \text{V}_{DD}^{Note 15} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS0} = \text{EV}_{SS1} = 0 \text{ V})$ (5/6)

Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Independent power supply RTC operating current	I _{RTC} Notes 3	fsuв = 32.768 kHz			0.70		μА
12-bit interval timer operating current	I _{TMKA} Notes 1, 2, 4	fsuв = 32.768 kHz,	fsuв = 32.768 kHz, fмаin is stopped				μА
8-bit interval	_{TMT} Notes 1, 2, 5	fsuв = 32.768 kHz,	8-bit counter mode × 2 ch operation		0.12		μΑ
timer operating current		fмаім is stopped, per unit	16-bit counter mode operation		0.10		μA
Watchdog timer operating current	_{WDT} Notes 1, 2, 6	fil = 15 kHz, fmain i	s stopped		0.22		μΑ
LVD operating current	I _{LVD} Notes 1, 7				0.10		μA
LVDVDD	ILVDVDD	Current flowing to	V _{DD}		0.05		μA
operating current		Current flowing to	V _{DD} or VBAT ^{Note 1}		0.04		μA
LVDVBAT	ILVDVBAT	Current flowing to	VBAT		0.04		μΑ
operating current		Current flowing to	V _{DD} or VBAT ^{Note 1}		0.04		μΑ
LVDVRTC	ILVDVRTC	Current flowing to	VRTC		0.04		μΑ
operating current		Current flowing to	V _{DD} or VBAT ^{Note 1}		0.04		μΑ
LVDEXLVD	ILVDEXLVD	Current flowing to	EXLVD		0.16		μΑ
operating current		Current flowing to	V _{DD} or VBAT ^{Note 1}		0.04		μΑ
Oscillation stop detection circuit operating current	lospc Note 1				0.02		μA
Battery backup circuit operating current	BUP Note 1				0.05		μA
A/D converter	I _{ADC} Notes 1, 8	When	Normal mode, AV _{REFP} = V _{DD} = 5.0 V		1.3	2.4	mA
operating current		conversion at maximum speed	Low voltage mode, AV _{REFP} = V _{DD} = 3.0 V		0.5	1.0	mA
A/D converter reference voltage current	ADREF Note 1				75.0		μA
Temperature sensor operating current	I _{TMPS} Note 1				105		μА
BGO operating current	I _{BGO} Notes 1, 9				2.00	12.20	mA
Self- programming operating current	FSP ^{Notes 1, 10}				2.00	12.20	mA

(Notes and Remarks are listed on the next page.)

(1A40 to	TOS C, 1.7 V		01 ≥ V 00 ···· ·· ≥ 5.5 V ,	VSS - EVSSO	- EVSS	1 – U V)	1	(0/0)
Parameter	Symbol		Conditions		MIN.	TYP.	MAX.	Unit
24-Bit ΔΣ A/D	IDSAD Notes 1, 11	In 4 ch ΔΣ A/D cor	In 4 ch ΔΣ A/D converter operation			1.45	2.30	mA
Converter operating		In 3 ch ΔΣ A/D cor	nverter operation			1.14	1.85	mA
current		In 1 ch ΔΣA/D con	verter operation			0.52	0.94	mA
SNOOZE	I _{SNOZ} Notes 1, 12	ADC operation	The mode is performed			0.50	0.80	mA
operating current			The A/D conversion opera performed, low voltage mo V _{DD} = 3.0 V			1.20	1.80	mA
		Simplified SPI (CS	Simplified SPI (CSI)/UART operation			0.70	1.05	mA
		DTC operation				2.20		mA
LCD operating current	_{LCD1} Notes 1, 13, 14	External resistance division method	f _{LCD} = f _{SUB} LCD clock = 128 Hz 1/3 bias, four-time-slices	V _{DD} = 5.0 V, V _{L4} = 5.0 V		0.06		μА
	LCD2Notes 1, 13	Internal voltage boosting method	f _{LCD} = f _{SUB} LCD clock = 128 Hz 1/3 bias, four-time-slices	V _{DD} = 3.0 V, V _{L4} = 3.0 V (VLCD = 04H)		0.85		μА
				V _{DD} = 5.0 V, V _{L4} = 5.1 V (VLCD = 12H)		1.55		μΑ
	I _{LCD3} Notes 1, 13	Capacitor split method	fLCD = fSUB LCD clock = 128 Hz	V _{DD} = 3.0 V, V _{L4} = 3.0 V		0.20		μΑ

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}_{DD0} = \text{EV}_{DD1} \le \text{V}_{DD}^{Note 15} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS0} = \text{EV}_{SS1} = 0 \text{ V})$ (6/6)

Notes 1. Current flowing to V_{DD}. When the VBAT pin (battery backup power supply pin) is selected, current flowing to the VBAT.

1/3 bias, four-time-slices

- 2. When high speed on-chip oscillator and high-speed system clock are stopped.
- 3. Current flowing to VRTC pin, including RTC power supply, subsystem clock oscillator circuit, and RTC.
- **4.** Current flowing only to the 12-bit interval timer (excluding the operating current of the low-speed on-chip oscillator and XT1 oscillator). The value of the current value of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and ITMKA, when the 12-bit interval timer operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added.
- 5. Current flowing only to the 8-bit interval timer (excluding the operating current of the low-speed on-chip oscillator and XT1 oscillator). The value of the current value of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and ITMT, when the 8-bit interval timer operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added.
- 6. Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The current value of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and IWDT when the watchdog timer operates.
- 7 Current flowing only to the LVD circuit. The current value of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and ILVD when the LVD circuit operates.
- 8. Current flowing only to the A/D converter. The current value of the RL78 microcontrollers is the sum of IDD1 or IDD2 and IADC when the A/D converter operates in an operation mode or the HALT mode.
- 9. Current flowing only during rewrite of 1 KB data flash memory.
- 10. Current flowing only during self programming.
- **11.**Current flowing only to the 24-bit $\Delta\Sigma$ A/D converter. The current value of the RL78 microcontrollers is the sum of I_{DD1} or I_{DD2}, and I_{DSAD} when the 24-bit $\Delta\Sigma$ A/D converter operates.
- 12. For shift time to the SNOOZE mode, see 26.3.3 SNOOZE mode in the RL78/I1C User's Manual.

- Notes 13. Current flowing only to the LCD controller/driver. The current value of the RL78 microcontrollers is the sum of the LCD operating current (ILCD1, ILCD2 or ILCD3) to the supply current (IDD1, or IDD2) when the LCD controller/driver operates in an operation mode or HALT mode. Not including the current that flows through the LCD panel. Conditions of the TYP. value and MAX. value are as follows.
 - Setting 20 pins as the segment function and blinking all
 - Selecting fsub for system clock when LCD clock = 128 Hz (LCDC0 = 07H)
 - Setting four time slices and 1/3 bias
 - **14.** Not including the current flowing into the external division resistor when using the external resistance division method.
 - **15.** Either V_{DD} or VBAT is selected by the battery backup function.
- Remarks 1. fil: Low-speed on-chip oscillator clock frequency
 - 2. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - 3. fclk: CPU/peripheral hardware clock frequency
 - 4. Temperature condition of the TYP. value is T_A = 25°C

2.4 AC Characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}_{DD0} = \text{EV}_{DD1} \le \text{V}_{DD}^{Note 1} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS0} = \text{EV}_{SS1} = 0 \text{ V})$ (1/2)

Items	Symbol		Conditio	ons	MIN.	TYP.	MAX.	Unit
Instruction cycle (minimum	Tcy	Main system	HS (high-speed	$2.8 \text{ V} \le \text{V}_{\text{DD}}^{\text{Note 1}} \le 5.5 \text{ V}$	0.03125		1	μs
instruction execution time)		clock (fmain)	main) mode	2.7 V ≤ V _{DD} ^{Note 1} < 2.8 V	0.04167		1	μs
		operation		2.5 V ≤ V _{DD} ^{Note 1} < 2.7 V	0.0625		1	μs
				2.4 V ≤ V _{DD} ^{Note 1} < 2.5 V	0.08333		1	μs
				2.1 V ≤ V _{DD} ^{Note 1} < 2.4 V	0.16667		1	μs
			LS (low-speed main) mode	1.9 V ≤ V _{DD} ^{Note 1} ≤ 5.5 V	0.125		1	μs
			LS (low-speed main) mode @4 MHz	1.9 V ≤ V _{DD} Note 1 ≤ 5.5 V	0.25		1	μs
			LP (low-power main) mode	1.9 V ≤ V _{DD} Note 1 ≤ 5.5 V	1		2	μs
			LV (low-voltage main) mode	1.7 V ≤ V _{DD} ^{Note 1} ≤ 5.5 V	0.25		1	μs
		Subsystem cl operation	ock (fsuв)	1.9 V ≤ V _{DD} ^{Note 1} ≤ 5.5 V	28.5	30.5	31.3	μs
		In the self	HS (high-speed	$2.8 \text{ V} \le \text{V}_{\text{DD}}^{\text{Note 1}} \le 5.5 \text{ V}$	0.03125		1	μs
		programming mode	main) mode	2.7 V ≤ V _{DD} ^{Note 1} < 2.8 V	0.04167		1	μs
		mode		2.5 V ≤ V _{DD} ^{Note 1} < 2.7 V	0.0625		1	μs
				2.4 V ≤ V _{DD} ^{Note 1} < 2.5 V	0.08333		1	μs
				2.1 V ≤ V _{DD} ^{Note 1} < 2.4 V	0.16667		1	μs
			LS (low-speed main) mode	1.9 V ≤ V _{DD} ^{Note 1} ≤ 5.5 V	0.125		1	μs
			LV (low-voltage main) mode	$1.7 \text{ V} \le \text{V}_{\text{DD}}^{\text{Note 1}} \le 5.5 \text{ V}$	0.25		1	μs
External system clock	fex	2.7 V ≤ V _{DD} Not	^{e 1} ≤ 5.5 V		1		20	MHz
frequency		2.5 V ≤ V _{DD} ^{Not}	^{e 1} < 2.7 V		1		16	MHz
		2.4 V ≤ V _{DD} ^{Not}	^{e 1} < 2.5 V		1		12	MHz
		1.9 V ≤ V _{DD} ^{Not}	e 1 < 2.4 V		1		8	MHz
		1.7 V ≤ V _{DD} ^{Not}	e1 < 1.9 V		1		4	MHz
	fexs				32		35	kHz
External system clock input	texH,	2.7 V ≤ V _{DD} Not	^{e 1} ≤ 5.5 V		24			ns
high-level width, low-level width	t exL	2.5 V ≤ V _{DD} ^{Not}			30			ns
		2.4 V ≤ V _{DD} Not			40			ns
		1.9 V ≤ V _{DD} ^{Not}	e 1 < 2.4 V		60			ns
		1.7 V ≤ V _{DD} ^{Not}	e 1 < 1.9 V		120			ns
	texhs,				13.7			μs
TI00 to TI07 input high-level width, low-level width					1/fмск+10			ns ^{Note 2}

(Notes and Remark are listed on the next page.)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}_{DD0} = \text{EV}_{DD1} \le \text{V}_{DD}^{Note 1} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS0} = \text{EV}_{SS1} = 0 \text{ V})$ (2/2)

Items	Symbol	Con	ditions	MIN.	TYP.	MAX.	Unit
TO00 to TO07 output	fто	HS (high-speed main) $4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}$ mode $2.7 \text{ V} \le \text{EV}_{DD} \le 4.0 \text{ V}$				16	MHz
frequency		mode	2.7 V ≤ EV _{DD} < 4.0 V			8	MHz
			2.4 V ≤ EV _{DD} < 2.7 V			4	MHz
			2.1 V ≤ EV _{DD} < 2.4 V			4	MHz
		LS (low-speed main) mode	1.9 V ≤ EV _{DD} ≤ 5.5 V			4	MHz
		LP (low-power main) mode	1.9 V ≤ EV _{DD} ≤ 5.5 V			0.5	MHz
		LV (low-voltage main) mode	1.7 V ≤ EV _{DD} ≤ 5.5 V			2	MHz
PCLBUZ0, PCLBUZ1 output	f PCL	HS (high-speed main)	4.0 V ≤ EV _{DD} ≤ 5.5 V			16	MHz
frequency		mode	2.7 V ≤ EV _{DD} < 4.0 V			8	MHz
			2.4 V ≤ EV _{DD} < 2.7 V			4	MHz
			2.1 V ≤ EV _{DD} < 2.4 V			4	MHz
		LS (low-speed main) mode	1.9 V ≤ EV _{DD} ≤ 5.5 V			4	MHz
		LP (low-power main) mode	1.9 V ≤ EV _{DD} ≤ 5.5 V			1	MHz
		LV (low-voltage main)	1.9 V ≤ EV _{DD} ≤ 5.5 V			4	MHz
		mode	1.7 V ≤ EV _{DD} < 1.9 V			2	MHz
Interrupt input high-level	tinth,	INTP0	1.7 V ≤ V _{DD} ^{Note 1} ≤ 5.5 V	1			μs
width, low-level width	tintl	INTP1 to INTP7	1.7 V ≤ EV _{DD} ≤ 5.5 V	1			μs
Key interrupt input low-level	t kr	KR0 to KR7	1.9 V ≤ EV _{DD} ≤ 5.5 V	250			ns
width			1.7 V ≤ EV _{DD} < 1.9 V	1			μs
RESET low-level width	trsL			10			μs

Notes 1. Either V_{DD} or VBAT is selected by the battery backup function.

2. The following conditions are required for low voltage interface:

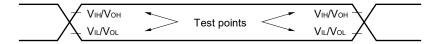
 $1.9 \text{ V} \le \text{V}_{\text{DD}} \le 2.7 \text{ V}$: MIN. 125 ns

Remark fmck: Timer array unit operation clock frequency

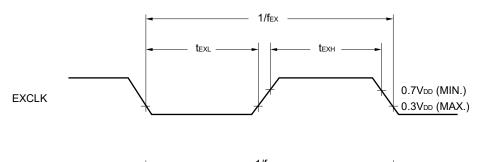
(Operation clock to be set by the CKSmn0, CKSmn1 bits of timer mode register mn (TMRmn)

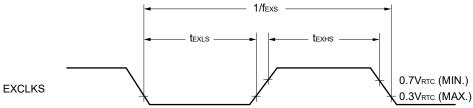
m: Unit number (m = 0), n: Channel number (n = 0 to 7))

AC Timing Test Points

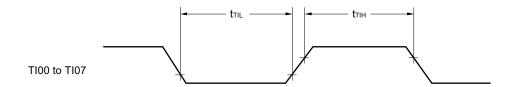


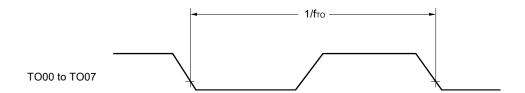
External System Clock Timing



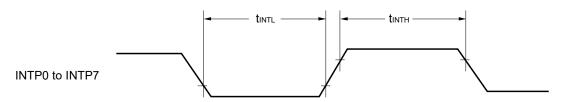


TI/TO Timing

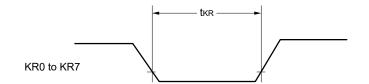




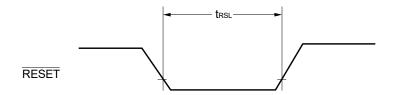
Interrupt Request Input Timing



Key interrupt Input Timing

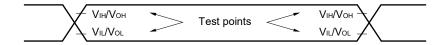


RESET Input Timing



2.5 Peripheral Functions Characteristics

AC Timing Test Points



2.5.1 Serial array unit

(1) During communication at same potential (UART mode) (dedicated baud rate generator output) $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}_{DD0} = \text{EV}_{DD1} \le \text{V}_{DD}^{Note 4} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{SS0} = \text{EV}_{SS1} = 0 \text{ V})$

Parameter	Symbol		Conditions	`	igh-speed n) Mode		v-speed Mode		w-power n) Mode	,	w-voltage n) Mode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Transfer rate ^{Note 1}		2.4	4 V ≤ V _{DD} ≤ 5.5 V		fмск/6 ^{Note 2}		fmck/6 ^{Note}		fmck/6 ^{Note 2}		fmck/6 ^{Note 2}	bps
			Theoretical value of the maximum transfer rate fmck = fclk Note 3		4.0		1.3		0.1		0.6	Mbps
		1.9	9 V ≤ V _{DD} ≤ 5.5 V		fмск/6 ^{Note 2}		fmck/6 ^{Note}		fmck/6 ^{Note 2}		fmck/6 ^{Note 2}	bps
			Theoretical value of the maximum transfer rate fmck = fclk Note 3		1.0		1.3		0.1		0.6	Mbps
		1.8	3 V ≤ V _{DD} ≤ 5.5 V		fмск/6 ^{Note 2}		fmck/6 ^{Note}		fmck/6 ^{Note 2}		fmck/6 ^{Note 2}	bps
			Theoretical value of the maximum transfer rate fmck = fclk Note 3		1.0		1.3		0.1		0.6	Mbps
		1.7	7 V ≤ V _{DD} ≤ 5.5 V								fmck/6 ^{Note 2}	bps
			Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 3}$								0.6	Mbps

Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

2. The following conditions are required for low voltage interface.

 $2.4 \text{ V} \le \text{EV}_{DD} < 2.7 \text{ V} : \text{MAX}. 2.6 \text{ Mbps}$

1.9 V ≤ EV_{DD} < 2.4 V: MAX. 1.3 Mbps

3. The maximum operating frequencies of the CPU/peripheral hardware clock (fclk) are:

HS (high-speed main) mode: 32 MHz (2.8 V \leq EV_{DD} \leq 5.5 V), 24 MHz (2.7 V \leq EV_{DD} \leq 5.5 V),

16 MHz (2.5 V \leq EV_{DD} \leq 5.5 V), 12 MHz (2.4 V \leq EV_{DD} \leq 5.5 V),

6 MHz (2.1 V \leq EV_{DD} \leq 5.5 V),

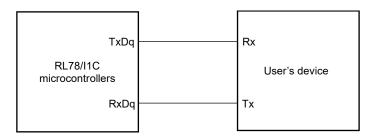
LS (low-speed main) mode: $8 \text{ MHz} (1.9 \text{ V} \leq \text{EV}_{DD} \leq 5.5 \text{ V}), 4 \text{ MHz} (1.9 \text{ V} \leq \text{EV}_{DD} \leq 5.5 \text{ V})$

LP (low-power main) mode: 1 MHz (1.9 V \leq EV_{DD} \leq 5.5 V) LV (low-voltage main) mode: 4 MHz (1.7 V \leq EV_{DD} \leq 5.5 V)

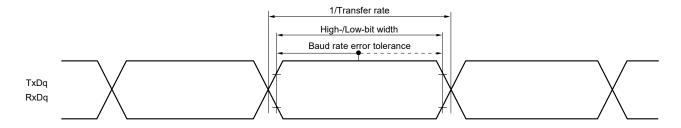
4. Either VDD or VBAT is selected by the battery backup function.

Caution Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

UART mode connection diagram (during communication at same potential)



UART mode bit width (during communication at same potential) (reference)



Remarks 1. q: UART number (q = 0 to 3), g: PIM and POM number (g = 0, 1, 3, 5, 8)

2. fmck: Serial array unit operation clock frequency (Operating clock that is set with the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number, n: Channel number (mn = 00 to 03, 10 to 13))

(2) During communication at same potential (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note 4}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

Parameter	Symbol		onditions		h-speed Mode	LS (low main)	•	LP (low main)	-power Mode	LV (low- main)	•	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	t KCY1	2.7 V ≤	EV _{DD} ≤ 5.5 V	125		500		4000		1000		ns
		2.4 V ≤	EV _{DD} ≤ 5.5 V	250		500		4000		1000		ns
		1.9 V ≤	EV _{DD} ≤ 5.5 V	500		500		4000		1000		ns
		1.8 V ≤	EV _{DD} ≤ 5.5 V	1000		1000		4000		1000		ns
		1.7 V ≤	EV _{DD} ≤ 5.5 V			1000		4000		1000		ns
SCKp high-/low-level	tкн1, tкL1	4.0 V ≤	EV _{DD} ≤ 5.5 V	tkcy1/ 2 – 12		tkcy1/ 2 - 50		tkcy1/ 2 - 50		tkcy1/ 2 - 50		ns
width		2.7 V ≤	EV _{DD} ≤ 5.5 V	tkcy1/ 2 – 18		tkcy1/ 2 - 50		tксү1/ 2 – 50		tkcy1/ 2 - 50		ns
		2.4 V ≤	EV _{DD} ≤ 5.5 V	tkcy1/ 2-38		tkcy1/ 2 - 50		tксү1/ 2 – 50		tkcy1/ 2-50		ns
		1.9 V ≤	EV _{DD} ≤ 5.5 V	tkcy1/ 2 - 50		tkcy1/ 2 - 50		tксү1/ 2 – 50		tkcy1/ 2 - 50		ns
		1.8 V ≤	EV _{DD} ≤ 5.5 V			tkcy1/ 2 - 100		tксү1/ 2 – 100		tkcy1/ 2 – 100		ns
		1.7 V ≤	EV _{DD} ≤ 5.5 V			tkcy1/ 2 - 100		tксү1/ 2 – 100		tkcy1/ 2 - 100		ns
SIp setup time (to	tsıĸ1	4.0 V ≤	EV _{DD} ≤ 5.5 V	44		110		110		110		ns
SCKp↑) ^{Note 1}		2.7 V ≤	EV _{DD} ≤ 5.5 V	44		110		110		110		ns
		2.4 V ≤	EV _{DD} ≤ 5.5 V	75		110		110		110		ns
		1.9 V ≤	EV _{DD} ≤ 5.5 V	110		110		110		110		ns
		1.8 V ≤	EV _{DD} ≤ 5.5 V	220		220		220		220		ns
		1.7 V ≤	EV _{DD} ≤ 5.5 V			220		220		220		ns
SIp hold time	t KSI1	1.8 V ≤	EV _{DD} ≤ 5.5 V	19		19		19		19		ns
(from SCKp↑) ^{Note 2}		1.7 V ≤	EV _{DD} ≤ 5.5 V			19		19		19		ns
Delay time from SCKp↓ to SOp	tkso1	C = 30 pF ^{Note 3}	1.8 V ≤ EV _{DD} ≤ 5.5 V		25		25		25		25	ns
output ^{Note 3}			1.7 V ≤ EV _{DD} ≤ 5.5 V				25		25		25	ns

- **Notes 1.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 3. C is the load capacitance of the SCKp and SOp output lines.
 - **4.** Either V_{DD} or VBAT is selected by the battery backup function.

Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

- **Remarks 1.** p: CSI number (p = 00, 10, 30), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM and POM numbers (g = 0, 1, 8)
 - 2. fmck: Serial array unit operation clock frequency (Operating clock that is set with the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).
 - m: Unit number, n: Channel number (mn = 00, 10, 30))

(3) During communication at same potential (Simplified SPI (CSI) mode) (slave mode, SCKp... external clock input)

(TA = -40 to +85°C, 1.7 V \leq EVDD0 = EVDD1 \leq VDDNote 5 \leq 5.5 V, Vss = EVss0 = EVss1 = 0 V)

Parameter	Symb ol	C	Conditions	HS (high- main) N	•	LS (low- main) N	•	LP (low- main) N	•	LV (low-v main) N	•	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle	tkcy2	4.0 V ≤	20 MHz < fмск	8/ƒмск		_		_		_		ns
time ^{Note 4}		EV _{DD} ≤ 5.5 V	fмск ≤ 20 MHz	6/fмск		6/ƒмск		6/ƒмск		6/fмск		ns
		2.7 V ≤	16 MHz < fмск	8/fмск		_		_		_		ns
		EV _{DD} ≤ 5.5 V	fмск ≤ 16 MHz	6/ƒмск		6/ƒмск		6/ƒмск		6/fмск		ns
		2.4 V ≤ E	EV _{DD} ≤ 5.5 V	6/fмск and 500		6/fмск and 500		6/fмск and 500		6/fмск and 500		ns
		1.9 V ≤ E	EV _{DD} ≤ 5.5 V	6/fмск and 750		6/fмск and 750		6/fмск and 750		6/fмск and 750		ns
		1.8 V ≤ E	EV _{DD} ≤ 5.5 V	6/fмск and 1500		6/fмск and 1500		6/fмск and 1500		6/fмск and 1500		ns
		1.7 V ≤ E	EV _{DD} ≤ 5.5 V			6/fмск and 1500		6/fмск and 1500		6/fмск and 1500		ns
SCKp high-/low-	tkH2, tkL2	4.0 V ≤ E	EV _{DD} ≤ 5.5 V	tксү2/ 2 – 7		tксү2/ 2 – 7		tксү2/ 2 – 7		tксү2/ 2 – 7		ns
level width		2.7 V ≤ E	EV _{DD} ≤ 5.5 V	tксү2/ 2 – 8		tксү2/ 2 – 8		tксү2/ 2 – 8		tксу2/ 2 – 8		ns
		1.9 V ≤ E	EV _{DD} ≤ 5.5 V	tксү2/ 2 – 18		tксү2/ 2 – 18		tксү2/ 2 – 18		tксү2/ 2 – 18		ns
		1.8 V ≤ E	EV _{DD} ≤ 5.5 V	tксү2/ 2 – 66		tксү2/ 2 – 66		tксү2/ 2 – 66		tксү2/ 2 – 66		ns
		1.7 V ≤ E	EV _{DD} ≤ 5.5 V			tксү2/ 2 – 66		tксү2/ 2 – 66		tксү2/ 2 – 66		ns
SIp setup	tsik2	2.7 V ≤ E	EV _{DD} ≤ 5.5 V	1/fmck+20		1/fмск+30		1/fмск+30		1/fмск+30		ns
time (to		1.9 V ≤ E	EV _{DD} ≤ 5.5 V	1/fмск+30		1/fмск+30		1/fмск+30		1/fмск+30		ns
SCKp↑) ^{Note 1}		1.8 V ≤ E	EV _{DD} ≤ 5.5 V	1/fмск+40		1/fмск+40		1/fмск+40		1/fмск+40		ns
		1.7 V ≤ E	EV _{DD} ≤ 5.5 V			1/fмск+40		1/fмск+40		1/fмск+40		ns
SIp hold	t _{KSI2}	2.1 V ≤ E	EV _{DD} ≤ 5.5 V	1/fмск+31		1/fмск+31		1/fмск+31		1/fмск+31		ns
time (from		1.9 V ≤ E	EV _{DD} ≤ 5.5 V			1/fмск+31		1/fмск+31		1/fмск+31		ns
SCKp↑) ^{Note 1}		1.7 V ≤ E	EV _{DD} ≤ 5.5 V							1/fмск+250		ns
Delay time from SCKp↓	tkso2	C = 30 pF ^{Note 3}	2.7 V ≤ EV _{DD} ≤ 5.5 V		2/fмск+ 44		2/fмск+ 110		2/fмск+ 110		2/fмск+ 110	ns
to SOp output ^{Note 2}			2.4 V ≤ EV _{DD} ≤ 5.5 V		2/fмск+ 75		2/fмск+ 110		2/fмск+ 110		2/fмск+ 110	ns
			1.9 V ≤ EV _{DD} ≤ 5.5 V		2/fмск+ 100		2/fмск+ 110		2/fмск+ 110		2/fмск+ 110	ns
			1.8 V ≤ EV _{DD} ≤ 5.5 V		2/fмск+ 220		2/fмск+ 220		2/fмск+ 220		2/fмск+ 220	ns
			1.7 V ≤ EV _{DD} ≤ 5.5 V				2/fмск+ 220		2/fмск+ 220		2/fмск+ 220	ns

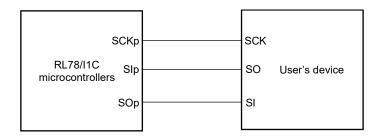
(Notes, Caution, and Remarks are listed on the next page.)

- **Notes 1.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 3. C is the load capacitance of the SOp output lines.
 - 4. Transfer rate in the SNOOZE mode: MAX. 1 Mbps
 - **5.** Either V_{DD} or VBAT is selected by the battery backup function.

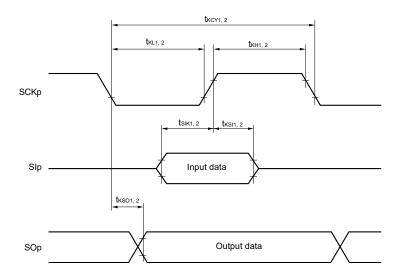
Caution Select the normal input buffer for the SIp pin and SCKp pin and the normal output mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

- **Remarks 1.** p: CSI number (p = 00, 10, 30), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM number (g = 0, 1, 8)
 - 2. fmck: Serial array unit operation clock frequency (Operating clock that is set with the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).
 - m: Unit number, n: Channel number (mn = 00, 10, 30))

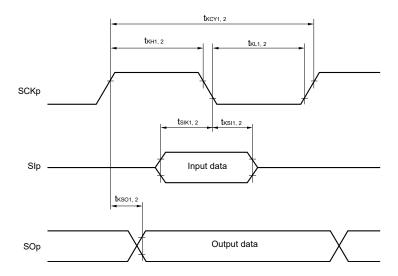
Simplified SPI (CSI) mode connection diagram (during communication at same potential)



Simplified SPI (CSI) mode serial transfer timing (during communication at same potential) (when DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1)



Simplified SPI (CSI) mode serial transfer timing (during communication at same potential) (when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0)



Remarks 1. p: CSI number (p = 00, 10, 30)

2. m: Unit number, n: Channel number (mn = 00, 10, 30)

(4) During communication at same potential (simplified I²C mode)

(TA = -40 to +85°C, 1.7 V \leq EVDD0 = EVDD1 \leq VDDNote 3 \leq 5.5 V, Vss = EVss0 = EVss1 = 0 V)

(1/2)

Parameter	Symbol	Conditions	HS (high-s _l Mo		LS (low main)	/-speed Mode	LP (low main)	/-power Mode	,	/-voltage Mode	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCLr clock frequency	fscL	$2.7 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $C_b = 50 \text{ pF}, R_b = 2.7 \text{ k}\Omega$		1000 ^{Note 1}		400 ^{Note 1}		400 ^{Note 1}		400 ^{Note 1}	kHz
		1.9 V ≤ EV _{DD} ≤ 5.5 V, $C_b = 100 \text{ pF}, R_b = 3 \text{ k}\Omega$		400 ^{Note 1}		400 ^{Note 1}		400 ^{Note 1}		400 ^{Note 1}	kHz
		1.9 V \leq EV _{DD} $<$ 2.7 V, C _b = 100 pF, R _b = 5 kΩ		300 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}	kHz
		1.8 V \leq EV _{DD} $<$ 1.9 V, C _b = 100 pF, R _b = 5 kΩ		250 ^{Note 1}		250 ^{Note 1}		250 ^{Note 1}		250 ^{Note 1}	kHz
		1.7 V \leq EV _{DD} $<$ 1.9 V, C _b = 100 pF, R _b = 5 kΩ				250 ^{Note 1}		250 ^{Note 1}		250 ^{Note 1}	kHz
Hold time when SCLr =	tLow	$2.7 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $C_b = 50 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	475		1150		1150		1150		ns
" <u>L</u> "		1.9 V ≤ EV _{DD} ≤ 5.5 V, $C_b = 100 \text{ pF}, R_b = 3 \text{ k}\Omega$	1150		1150		1150		1150		ns
		1.9 V ≤ EV _{DD} < 2.7 V, C _b = 100 pF, R _b = 5 kΩ	1550		1550		1550		1550		ns
		1.8 V \leq EV _{DD} $<$ 1.9 V, C _b = 100 pF, R _b = 5 kΩ	1850		1850		1850		1850		ns
		1.7 V ≤ EV _{DD} < 1.9 V, C _b = 100 pF, R _b = 5 kΩ			1850		1850		1850		ns
Hold time when SCLr =	tнісн	2.7 V \leq EV _{DD} \leq 5.5 V, C _b = 50 pF, R _b = 2.7 kΩ	475		1150		1150		1150		ns
"H"		1.9 V \leq EV _{DD} \leq 5.5 V, C _b = 100 pF, R _b = 3 kΩ	1150		1150		1150		1150		ns
		1.9 V ≤ EV _{DD} < 2.7 V, C _b = 100 pF, R _b = 5 kΩ	1550		1550		1550		1550		ns
		1.8 V ≤ EV _{DD} < 1.9 V, C _b = 100 pF, R _b = 5 kΩ	1850		1850		1850		1850		ns
		1.7 V \leq EV _{DD} $<$ 1.9 V, C _b = 100 pF, R _b = 5 kΩ			1850		1850		1850		ns
Data setup time	tsu:dat	2.7 V \leq EV _{DD} \leq 5.5 V, C _b = 50 pF, R _b = 2.7 kΩ	1/f _{MCK} + 85 ^{Notes 1, 2}		1/f _{MCK} + 145 ^{Notes 1, 2}		1/f _{MCK} + 145 ^{Notes 1, 2}		1/f _{MCK} + 145 ^{Notes 1,2}		ns
(reception)		1.9 V ≤ EV _{DD} ≤ 5.5 V, $C_b = 100$ pF, $R_b = 3$ kΩ	1/f _{MCK} + 145 ^{Notes 1, 2}		1/f _{MCK} + 145 ^{Notes 1, 2}		1/f _{MCK} + 145 ^{Notes 1,2}		1/f _{MCK} + 145 ^{Notes 1,2}		ns
		1.9 V ≤ EV _{DD} < 2.7 V, C _b = 100 pF, R _b = 5 kΩ	1/f _{MCK} + 230 ^{Notes 1, 2}		1/f _{MCK} + 230 ^{Notes 1, 2}		1/f _{MCK} + 230 ^{Notes 1,2}		1/f _{MCK} + 230 ^{Notes 1,2}		ns
		1.8 V ≤ EV _{DD} < 1.9 V, C _b = 100 pF, R _b = 5 kΩ	1/f _{MCK} + 290 ^{Notes 1, 2}		1/f _{MCK} + 290 ^{Notes 1, 2}		1/f _{MCK} + 290 ^{Notes 1,2}		1/f _{MCK} + 290 ^{Notes 1, 2}		ns
		1.7 V ≤ EV _{DD} < 1.9 V, C _b = 100 pF, R _b = 5 kΩ			1/f _{MCK} + 290 ^{Notes 1, 2}		1/f _{MCK} + 290 ^{Notes 1,2}		1/f _{MCK} + 290 ^{Notes 1, 2}		ns

(Notes, Caution, and Remarks are listed on the next page.)

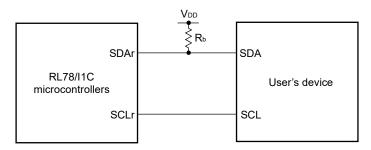
(2/2)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		`	v-speed Mode	,	v-power Mode	`	-voltage Mode	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Data hold time	thd:dat	$2.7 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $C_b = 50 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	0	305	0	305	0	305	0	305	ns
(transmission)		1.9 V \leq EV _{DD} \leq 5.5 V, C _b = 100 pF, R _b = 3 kΩ	0	355	0	355	0	355	0	355	ns
		1.9 V \leq EV _{DD} $<$ 2.7 V, C _b = 100 pF, R _b = 5 kΩ	0	405	0	405	0	405	0	405	ns
		1.8 V \leq EV _{DD} $<$ 1.9 V, C _b = 100 pF, R _b = 5 kΩ	0	405	0	405	0	405	0	405	ns
		1.7 V \leq EV _{DD} $<$ 1.9 V, C _b = 100 pF, R _b = 5 kΩ			0	405	0	405	0	405	ns

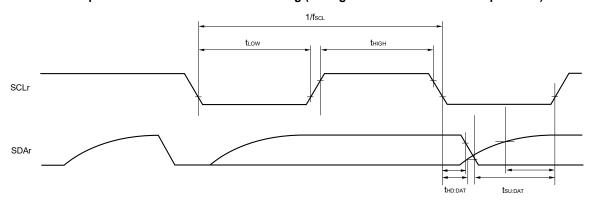
 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note 3}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

- Notes 1. The value must also be equal to or less than fmck/4.
 - 2. Set the fmck value to keep the hold time of SCLr = "L" and SCLr = "H".
 - 3. Either VDD or VBAT is selected by the battery backup function.

Simplified I²C mode connection diagram (during communication at same potential)



Simplified I²C mode serial transfer timing (during communication at same potential)



Caution Select the normal input buffer and the N-ch open drain output (VDD tolerance) mode for the SDAr pin and the normal output mode for the SCLr pin by using port input mode register g (PIMg) and port output mode register g (POMg).

- **Remarks 1.** R_b[Ω]:Communication line (SDAr) pull-up resistance, C_b[F]: Communication line (SDAr, SCLr) load capacitance
 - 2. r: IIC number (r = 00, 10, 30), g: PIM and POM number (g = 0, 1, 8)
 - fmck: Serial array unit operation clock frequency (Operating clock that is set with the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number (m = 0, 1), n: Channel number (n = 0, 2), mn = 00, 02, 12))

(5) Communication at different potential (1.9 V, 2.5 V, 3 V) (UART mode) (1/2)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note 1}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

Parameter	Symbol		Conditions		gh-speed ı) Mode		w-speed ı) Mode		w-power ı) Mode		w-voltage า) Mode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Transfer rate		Reception	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V}$		fмск/6 ^{Note 1}	bps						
		Rec	Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 4}$		5.3		1.3		0.1		0.6	Mbps
			$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V}$		fmck/6 ^{Note 1}		fmck/6 ^{Note 1}		fmck/6 ^{Note 1}		fмск/6 ^{Note 1}	bps
			Theoretical value of the maximum transfer rate fMCK = fCLKNote 4		5.3		1.3		0.1		0.6	Mbps
			$1.9 \text{ V} \le \text{EV}_{DD} < 3.3 \text{ V},$ $1.8 \text{ V} \le \text{V}_{b} \le 2.0 \text{ V}$		fMCK/6 Notes 1 to 3		fMCK/6 Notes 1, 2		fMCK/6 Notes 1, 2		fmck/6 Notes 1, 2	bps
			Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 4}$		5.3		1.3		0.1		0.6	Mbps

Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

- 2. Use it with $EV_{DD} \ge V_b$.
- 3. The following conditions are required for low voltage interface.

2.4 V ≤ EV_{DD} < 2.7 V: MAX. 2.6 Mbps 1.9 V ≤ EV_{DD} < 2.4 V: MAX. 1.3 Mbps

4. The maximum operating frequencies of the CPU/peripheral hardware clock (fclk) are:

HS (high-speed main) mode: 32 MHz (2.8 V \leq EV_{DD} \leq 5.5 V), 24 MHz (2.7 V \leq EV_{DD} \leq 5.5 V),

16 MHz (2.5 V \leq EV_{DD} \leq 5.5 V), 12 MHz (2.4 V \leq EV_{DD} \leq 5.5 V),

6 MHz (2.1 V \leq EV_{DD} \leq 5.5 V),

LS (low-speed main) mode: $8 \text{ MHz} (1.9 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}), 4 \text{ MHz} (1.9 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V})$

LP (low-power main) mode: 1 MHz (1.9 V \leq EV_{DD} \leq 5.5 V) LV (low-voltage main) mode: 4 MHz (1.7 V \leq EV_{DD} \leq 5.5 V)

Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (Vpd tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

Remarks 1. $V_b[V]$: Communication line voltage

- **2.** q: UART number (q = 0 to 3), g: PIM and POM number (g = 0, 1, 3, 5, 8)
- 3. fmck: Serial array unit operation clock frequency

(Operating clock that is set with the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number, n: Channel number (mn = 00 to 03, 10 to 13))

(5) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode) (2/2)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note } 10} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

Parameter	Symbol		Conditions	, -	jh-speed) Mode	•	/-speed Mode	-	/-power Mode	,	-voltage Mode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Transfer rate		ission	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $2.7 \text{ V} \le \text{V}_{b} \le 4.0 \text{ V}$		Notes 1, 2		Notes 1, 2		Notes 1, 2		Notes 1, 2	bps
		Transmission	Theoretical value of the maximum transfer rate ^{Note 9} $C_b = 50$ pF, $R_b = 1.4$ k Ω , $V_b = 2.7$ V		2.8 ^{Note 3}	Mbps						
			$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V}$		Notes 2, 4		Notes 2, 4		Notes 2, 4		Notes 2, 4	bps
			Theoretical value of the maximum transfer rate $^{\text{Note 9}}$ $C_b = 50 \text{ pF}, R_b = 2.7 \text{ k}\Omega,$ $V_b = 2.3 \text{ V}$		1.2 ^{Note 5}	Mbps						
			1.9 V ≤ EV _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V		Notes 2, 6, 7	bps						
			Theoretical value of the maximum transfer rate Note 9 $C_b = 50$ pF, $R_b = 5.5$ k Ω , $V_b = 1.6$ V		0.43 ^{Note 8}	Mbps						

Notes 1. The smaller maximum transfer rate derived by using fmck/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 4.0 V ≤ EV_{DD} ≤ 5.5 V and 2.7 V ≤ V_b ≤ 4.0 V

$$\label{eq:maximum transfer rate} \begin{aligned} & \frac{1}{\{-C_b \times R_b \times ln\ (1-\frac{2.2}{V_b})\} \times 3} \ [bps] \end{aligned}$$

Baud rate error (theoretical value) =
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln (1 - \frac{2.2}{V_b})\}}{\frac{1}{(\text{Transfer rate})} \times \text{Number of transferred bits}} \times 100 \, [\%]$$

- * This value is the theoretical value of the relative difference between the transmission and reception sides.
- 2. Transfer rate in the SNOOZE mode is 4800 bps only.
- **3.** This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to **Note 1** above to calculate the maximum transfer rate under conditions of the customer.
- **4.** The smaller maximum transfer rate derived by using fmck/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.7 V ≤ EVDD < 4.0 V and 2.3 V ≤ Vb ≤ 2.7 V

$$\label{eq:maximum transfer rate} \text{Maximum transfer rate} = \frac{1}{\{-C_b \times R_b \times \text{ln } (1 - \frac{2.0}{V_b})\} \times 3} \text{ [bps]}$$

Baud rate error (theoretical value) =
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\}}{\frac{1}{(\text{Transfer rate})} \times \text{Number of transferred bits}} \times 100 \, [\%]$$

^{*} This value is the theoretical value of the relative difference between the transmission and reception sides.

- **Notes 5.** This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to **Note 4** above to calculate the maximum transfer rate under conditions of the customer.
 - 6. Use it with EV_{DD} ≥ V_b.
 - 7. The smaller maximum transfer rate derived by using fmck/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 1.9 V \leq EV_{DD} < 2.7 V and 1.6 V \leq V_b \leq 2.0 V

Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times ln (1 - \frac{1.5}{V_b})\} \times 3}$$
 [bps]

Baud rate error (theoretical value) =
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{1.5}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 \, [\%]$$

- * This value is the theoretical value of the relative difference between the transmission and reception sides.
- **8.** This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to **Note 7** above to calculate the maximum transfer rate under conditions of the customer.
- 9. The maximum operating frequencies of the CPU/peripheral hardware clock (fCLK) are:

HS (high-speed main) mode: 32 MHz (2.8 V \leq EVDD \leq 5.5 V), 24 MHz (2.7 V \leq EVDD \leq 5.5 V),

16 MHz (2.5 V \leq EV_{DD} \leq 5.5 V), 12 MHz (2.4 V \leq EV_{DD} \leq 5.5 V),

6 MHz (2.1 V \leq EV_{DD} \leq 5.5 V),

LS (low-speed main) mode: $8 \text{ MHz} (1.9 \text{ V} \leq \text{EV}_{DD} \leq 5.5 \text{ V}), 4 \text{ MHz} (1.9 \text{ V} \leq \text{EV}_{DD} \leq 5.5 \text{ V})$

LP (low-power main) mode: 1 MHz (1.9 V ≤ EV_{DD} ≤ 5.5 V) LV (low-voltage main) mode: 4 MHz (1.7 V ≤ EV_{DD} ≤ 5.5 V)

10. Either VDD or VBAT is selected by the battery backup function.

Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (V_{DD} tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

Remarks 1. $R_b[\Omega]$:Communication line (TxDq) pull-up resistance,

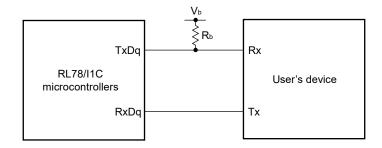
Cb[F]: Communication line (TxDq) load capacitance, Vb[V]: Communication line voltage

- **2.** q: UART number (q = 0 to 3), g: PIM and POM number (g = 0, 1, 3, 5, 8)
- 3. fmck: Serial array unit operation clock frequency

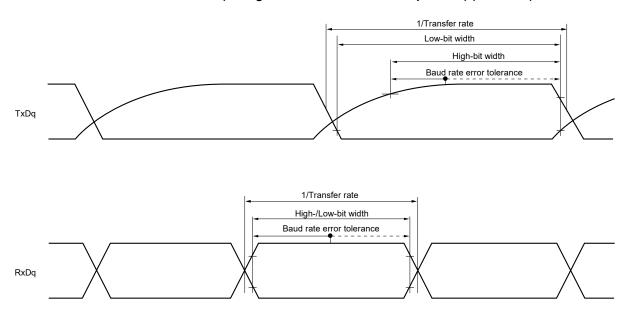
(Operating clock that is set with the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number, n: Channel number (mn = 00 to 03, 10 to 13))

UART mode connection diagram (during communication at different potential)



UART mode bit width (during communication at different potential) (reference)



Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (V_{DD} tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

Remarks 1. $R_b[\Omega]$:Communication line (TxDq) pull-up resistance, $V_b[V]$: Communication line voltage

2. q: UART number (q = 0 to 3), g: PIM and POM number (g = 0, 1, 3, 5, 8)

(6) Communication at different potential (2.5 V, 3 V) (fmck/2) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output, corresponding CSI00 only) (1/2)

(TA = -40 to +85°C, 2.7 V \leq EVDD0 = EVDD1 \leq VDDNote 3 \leq 5.5 V, Vss = EVss0 = EVss1 = 0 V)

Parameter	Symbol		Conditions	HS (high- main) N	•	LS (low- main) l		LP (low- main) N		LV (low-v main) M	•	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkcy1	tксү1 ≥ 2/fс∟к	$\begin{aligned} 4.0 & \ V \leq EV_{DD} \leq 5.5 \ V, \\ 2.7 & \ V \leq V_b \leq 4.0 \ V, \\ C_b & = 20 \ pF, \ R_b = 1.4 \ k\Omega \end{aligned}$	200		1150		1150		1150		ns
			$\begin{split} 2.7 & \text{ V} \leq \text{EV}_{\text{DD}} < 4.0 \text{ V}, \\ 2.3 & \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}, \\ C_{\text{b}} & = 20 \text{ pF}, \text{ R}_{\text{b}} = 2.7 \text{ k}\Omega \end{split}$	300		1150		1150		1150		ns
SCKp high- level width	t кн1	2.7 V ≤	$4 = V_{DD} ≤ 5.5 V,$ $4 = V_{D} ≤ 4.0 V,$ $4 = 0.0 V_{D}$ $4 = 0.0 V_{D}$ $4 = 0.0 V_{D}$	tксүт/ 2 – 50		tксү1/ 2 – 50		tксү1/ 2 – 50		tксү1/ 2 – 50		ns
		2.3 V ≤	$≤ EV_{DD} < 4.0 \text{ V},$ $≤ V_{D} ≤ 2.7 \text{ V},$ $≤ OpF, R_{D} = 2.7 \text{ k}Ω$	tксу1/ 2 – 120		tксү1/ 2 – 120		tксү1/ 2 – 120		tксү1/ 2 — 120		ns
SCKp low- level width	t _{KL1}	2.7 V ≤		tксу1/ 2-7		tксү1/ 2 – 50		tксү1/ 2 – 50		tkcy1/ 2 - 50		ns
		2.3 V ≤	$4 ∈ V_{DD} < 4.0 V,$ $4 ∈ V_{D} ≤ 2.7 V,$ $4 ∈ V_{D} ∈ V_{D} ∈ V_{D}$ $4 ∈ V_{D} ∈$	tксү1/ 2 – 10		tксү1/ 2 – 50		tксү1/ 2 – 50		tксү1/ 2 – 50		ns
SIp setup time (to SCKp↑) ^{Note 1}	tsıĸı	2.7 V ≤	$≤ EV_{DD} ≤ 5.5 V,$ $≤ V_{D} ≤ 4.0 V,$ $∑ pF, R_{D} = 1.4 kΩ$	58		479		479		479		ns
		2.3 V ≤	$≤ EV_{DD} < 4.0 V,$ $≤ V_{D} ≤ 2.7 V,$ $≤ D_{DF}$, $R_{D} = 2.7 kΩ$	121		479		479		479		ns
SIp hold time (from SCKp↑) ^{Note 1}	tksıı	2.7 V ≤	$4 \text{EV}_{DD} \le 5.5 \text{ V},$ $4 \text{EV}_{D} \le 4.0 \text{ V},$ $4 \text{OpF}, R_{b} = 1.4 \text{ k}\Omega$	10		10		10		10		ns
		2.3 V ≤		10		10		10		10		ns
Delay time from SCKp↓ to SOp	tkso1	2.7 V ≤			60		60		60		60	ns
output ^{Note 1}		2.3 V ≤	$≤ EV_{DD} < 4.0 V,$ $≤ V_b ≤ 2.7 V,$ $≤ 0 pF, R_b = 2.7 kΩ$		130		130		130		130	ns
SIp setup time (to SCKp↓) ^{Note 2}	tsıĸ1	2.7 V ≤	$4 \text{ EV}_{DD} \le 5.5 \text{ V},$ $4 \text{ V}_{D} \le 4.0 \text{ V},$ $4 \text{ OpF}, R_{D} = 1.4 \text{ k}\Omega$	23		110		110		110		ns
		2.3 V ≤	$4 = V_{DD} < 4.0 V$, $4 = V_{DD} < 4.0 V$,	33		110		110		110		ns

(Notes, Caution, and Remarks are listed on the next page.)

(6) Communication at different potential (2.5 V, 3 V) (fmck/2) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output, corresponding CSI00 only) (2/2)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.7 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note 3}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

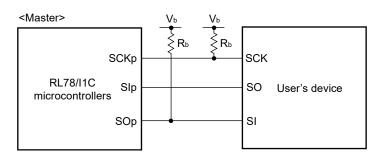
Parameter	Symbol	Conditions	HS (high-speed main) Mode		main) Mode		main) Mode		LV (low- main)	•	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SIp hold time (from SCKp↓) ^{Note 2}	tksii	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$ $C_b = 20 \text{ pF}, R_b = 1.4 \text{ k}\Omega$	10		10		10		10		ns
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$ $C_{b} = 20 \text{ pF}, R_{b} = 2.7 \text{ k}\Omega$	10		10		10		10		ns
Delay time from SCKp↑ to SOp	tkso1	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$ $C_b = 20 \text{ pF}, R_b = 1.4 \text{ k}\Omega$		10		10		10		10	ns
output ^{Note 2}		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$ $C_b = 20 \text{ pF}, R_b = 2.7 \text{ k}\Omega$		10		10		10		10	ns

Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.

- 2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 3. Either VDD or VBAT is selected by the battery backup function.

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

Simplified SPI (CSI) mode connection diagram (during communication at different potential)



- **Remarks 1.** R_b[Ω]:Communication line (SCKp, SOp) pull-up resistance, C_b[F]: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage
 - **2.** p: CSI number (p = 00, 10, 30), m: Unit number, n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1, 8)
 - 3. fmck: Serial array unit operation clock frequency (Operating clock that is set with the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).
 - m: Unit number, n: Channel number (mn = 00, 02, 12))
 - 4. This specification is valid only when CSI00's peripheral I/O redirect function is not used.

(7) Communication at different potential (1.8 V, 2.5 V, 3 V) (fmck/4) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output) (1/2)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note 4}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

Parameter	Symbol		Conditions	HS (high		LS (low- main) I	•	LP (low main)		LV (low-v	-	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkcy1	t _{KCY1} ≥ 4/f _{CLK}	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$ $C_b = 30 \text{ pF}, R_b = 1.4 \text{ k}\Omega$	300		1150		1150		1150		ns
			$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$ $C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	500		1150		1150		1150		ns
			1.9 V ≤ EV _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V, $C_b = 30$ pF, $R_b = 5.5$ kΩ	1150		1150		1150		1150		ns
SCKp high- level width	t кн1	2.7 V ≤	$V_{DD} \le 5.5 \text{ V},$ $V_{b} \le 4.0 \text{ V},$ $V_{b} = 1.4 \text{ k}\Omega$	tксү1/ 2 – 75		tkcy1/ 2-75		tkcy1/ 2 – 75		tксү1/ 2 – 75		ns
		2.3 V ≤	$EV_{DD} < 4.0 \text{ V},$ $V_b \le 2.7 \text{ V},$ $V_b = 2.7 \text{ k}$	tксу1/ 2 – 170		tксү1/ 2 – 170		tксү1/ 2 – 170		tксү1/ 2 – 170		ns
		1.6 V ≤	$^{\text{te 4}} \le \text{EV}_{\text{DD}} < 3.3 \text{ V},$ $^{\text{V}}_{\text{b}} \le 2.0 \text{ V}^{\text{Note 3}},$ $^{\text{O}}_{\text{DF}}, R_{\text{b}} = 5.5 \text{ k}\Omega$	tксү1/ 2 – 458		tkcy1/ 2 - 458		tkcy1/ 2-458		tксү1/ 2 – 458		ns
SCKp low- level width	t _{KL1}	2.7 V ≤	$EV_{DD} \le 5.5 \text{ V},$ $V_b \le 4.0 \text{ V},$ 0 pF, R _b = 1.4 kΩ	tксү1/ 2 – 12		tkcy1/ 2 - 50		tkcy1/ 2-50		tксү1/ 2 – 50		ns
		2.3 V ≤	$V_{DD} < 4.0 \text{ V},$ $V_{b} \le 2.7 \text{ V},$ $V_{D} = 2.7 \text{ k}$	tксү1/ 2 – 18		tkcy1/ 2-50		tkcy1/ 2-50		tксү1/ 2 – 50		ns
		1.6 V ≤	$\label{eq:controller} \begin{split} &^{\text{te 4}} \leq \text{EV}_{\text{DD}} < 3.3 \text{ V}, \\ &^{\text{t}} \text{V}_{\text{b}} \leq 2.0 \text{ V}^{\text{Note 3}}, \\ &^{\text{pF}}, \text{R}_{\text{b}} = 5.5 \text{ k}\Omega \end{split}$	tkcy1/ 2-50		tксү1/ 2 – 50		tксү1/ 2 – 50		tксү1/ 2 – 50		ns
SIp setup time (to SCKp↑) ^{Note 1}	tsıĸı	2.7 V ≤	$\begin{split} EV_{DD} &\leq 5.5 \text{ V}, \\ V_b &\leq 4.0 \text{ V}, \\ 0 \text{ pF, } R_b &= 1.4 \text{ k}\Omega \end{split}$	81		479		479		479		ns
		2.3 V ≤	$\begin{split} EV_{DD} &< 4.0 \text{ V},\\ V_b &\leq 2.7 \text{ V},\\) \text{ pF, } R_b &= 2.7 \text{ k}\Omega \end{split}$	177		479		479		479		ns
		1.6 V ≤	$\begin{split} EV_{DD} &< 3.3 \text{ V},\\ V_b &\leq 2.0 \text{ V}^{\text{Note 3}},\\ 0 \text{ pF}, R_b &= 5.5 \text{ k}\Omega \end{split}$	479		479		479		479		ns

(Notes, Caution and Remarks are listed on the page after the next page.)

(7) Communication at different potential (1.8 V, 2.5 V, 3 V) (fmck/4) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output) (2/2)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note 4}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

Parameter	Symbol	Conditions	, ,	h-speed Mode	,	v-speed Mode	,	v-power Mode		v-voltage Mode	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SIp hold time (from SCKp↑) ^{Note 1}	tksi1	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$ $C_b = 30 \text{ pF}, R_b = 1.4 \text{ k}\Omega$	19		19		19		19		ns
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$ $C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	19		19		19		19		ns
		$\begin{split} 1.9 \ V &\leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 3}}, \\ C_b &= 30 \ \text{pF}, \ R_b = 5.5 \ k\Omega \end{split}$	19		19		19		19		ns
Delay time from SCKp↓ to	tkso1	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$ $C_b = 30 \text{ pF}, R_b = 1.4 \text{ k}\Omega$		100		100		100		100	ns
SOp output ^{Note 1}		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$ $C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$		195		195		195		195	ns
		$\begin{split} 1.9 \ V &\leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 3}}, \\ C_b &= 30 \ \text{pF}, \ R_b = 5.5 \ \text{k}\Omega \end{split}$		483		483		483		483	ns
SIp setup time (to $SCKp\downarrow)^{Note 2}$	tsıĸı	$ 4.0 \text{ V} \leq \text{EV}_{DD} \leq 5.5 \text{ V}, \\ 2.7 \text{ V} \leq \text{V}_b \leq 4.0 \text{ V}, \\ C_b = 30 \text{ pF}, R_b = 1.4 \text{ k}\Omega $	44		110		110		110		ns
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$ $C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	44		110		110		110		ns
		1.9 V ≤ EV _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V ^{Note 3} , C _b = 30 pF, R _b = 5.5 kΩ	110		110		110		110		ns
SIp hold time (from SCKp↓) ^{Note 2}	tksi1	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$ $C_b = 30 \text{ pF}, R_b = 1.4 \text{ k}\Omega$	19		19		19		19		ns
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$ $C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	19		19		19		19		ns
		$\begin{split} 1.9 \ V &\leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 3}}, \\ C_b &= 30 \ \text{pF}, \ R_b = 5.5 \ k\Omega \end{split}$	19		19		19		19		ns
Delay time from SCKp↑ to SOp	tkso1	$\begin{aligned} 4.0 & \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}, \\ 2.7 & \text{ V} \leq \text{V}_{\text{b}} \leq 4.0 \text{ V}, \\ \text{C}_{\text{b}} & = 30 \text{ pF}, \text{ R}_{\text{b}} = 1.4 \text{ k}\Omega \end{aligned}$		25		25		25		25	ns
output ^{Note 2}		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$ $C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$		25		25		25		25	ns
		1.9 V ≤ EV _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V ^{Note 3} , C _b = 30 pF, R _b = 5.5 kΩ		25		25		25		25	ns

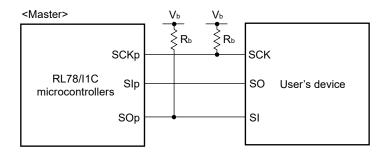
(Notes, Caution and Remarks are listed on the next page.)

- Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
 - 2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 3. Use it with $EV_{DD} \ge V_b$.
 - 4. Either VDD or VBAT is selected by the battery backup function.

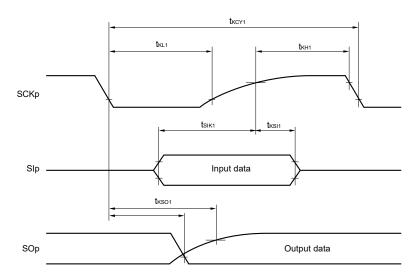
Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

- **Remarks 1.** R_b[Ω]:Communication line (SCKp, SOp) pull-up resistance, C_b[F]: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage
 - 2. p: CSI number (p = 00, 10, 30), m: Unit number, n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1, 8)
 - fmck: Serial array unit operation clock frequency
 (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn).
 m: Unit number, n: Channel number (mn = 00, 02, 12))

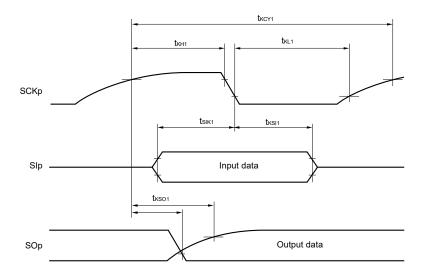
Simplified SPI (CSI) mode connection diagram (during communication at different potential)



Simplified SPI (CSI) mode serial transfer timing (master mode) (during communication at different potential) (when DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1)



Simplified SPI (CSI) mode serial transfer timing (master mode) (during communication at different potential) (when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0)



Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

Remark p: CSI number (p = 00, 10, 30), m: Unit number, n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1, 8)

(8) Communication at different potential (1.8 V, 2.5 V, 3 V) (Simplified SPI (CSI) mode) (slave mode, SCKp ... external clock input)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note 5}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V}) (1/2)$

Parameter	Symb ol		Conditions		h-speed Mode	,	/-speed Mode	LP (low main)	/-power Mode	-	-voltage Mode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle	t _{KCY2}	4.0 V≤	24 MHz < f _{MCK}	14/fмск		_		_		-		ns
time ^{Note 1}		EV _{DD} ≤ 5.5 V,	20 MHz < fмcк ≤ 24 MHz	12/fмск		-		-		-		ns
		2.7 V ≤ V _b ≤ 4.0 V	8 MHz < f _{MCK} ≤ 20 MHz	10/fмск		_		-		_		ns
		ľ	4 MHz < f _{MCK} ≤ 8 MHz	8/ƒмск		16/ƒмск		_		_		ns
			fмcк ≤ 4 MHz	6/fмск		10/fмск		10/fмск		10/fмск		ns
		2.7 V ≤	24 MHz < f _{MCK}	20/fмск		_		_		-		ns
		EV _{DD} < 4.0 V,	20 MHz < fмcк ≤ 24 MHz	16/ƒмск		-		-		-		ns
		2.3 V ≤ V _b ≤ 2.7 V	16 MHz < fмcк ≤ 20 MHz	14/fмск		-		-		_		ns
			8 MHz < fмcк ≤ 16 MHz	12/fмск		-		-		_		ns
			4 MHz < f _{MCK} ≤ 8 MHz	8/fмск		16/ƒмск		-		_		ns
			fmck ≤ 4 MHz	6/fмск		10/fмск		10/fмск		10/fмск		ns
		1.9 V ≤	24 MHz < f _{MCK}	48/fмск		_		_		-		ns
		EV _{DD} < 3.3 V,	20 MHz < fмcк ≤ 24 MHz	36/ƒмск		_		-		_		ns
		1.6 V ≤ V _b ≤ 2.0 VNote 2	16 MHz < fмcк ≤ 20 MHz	32/fмск		_		-		_		ns
		Visite 2	8 MHz < f _{MCK} ≤ 16 MHz	26/fмск		-		-		_		ns
			4 MHz < f _{MCK} ≤ 8 MHz	16/ƒмск		16/ƒмск		_		_		ns
			fмcк ≤ 4 MHz	10/fмск		10/fмск		10/fмск		10/fмск		ns
SCKp high- /low-level	tкн2, tкL2		EV _{DD} ≤ 5.5 V, V _b ≤ 4.0 V	tkcy2/ 2 – 12		tkcy2/ 2 - 50		tkcy2/ 2 - 50		tkcy2/ 2 - 50		ns
width			EV _{DD} < 4.0 V, √ _b ≤ 2.7 V	tkcy2/ 2 – 18		tkcy2/ 2 - 50		tkcy2/ 2-50		tkcy2/ 2 - 50		ns
			$EV_{DD} < 3.3 \text{ V},$ $V_b \le 2.0 \text{ V}^{\text{Note 2}}$	tkcy2/ 2 - 50		tkcy2/ 2 - 50		tkcy2/ 2 - 50		tkcy2/ 2 - 50		ns
SIp setup time (to	tsık2		$EV_{DD} \le 5.5 \text{ V},$ $V_b \le 4.0 \text{ V}^{\text{Note 2}}$	1/fмск + 20		1/fмск + 30		1/f _{MCK} + 30		1/f _{MCK} + 30		ns
SCKp↑) ^{Note 3}			EV _{DD} < 3.3 V, √ _b ≤ 2.0 V ^{Note 2}	1/fмск + 30		1/fмск + 30		1/fмск + 30		1/fмск + 30		ns
SIp hold time (from	tksi2		$EV_{DD} \le 5.5 \text{ V},$ $V_b \le 4.0 \text{ V}^{\text{Note 2}}$	1/fmck + 31		1/fмcк+ 31		1/f _{MCK} + 31		1/f _{MCK} + 31		ns
SCKp↑) ^{Note 3}			EV _{DD} < 3.3 V, V _b ≤ 2.0 V ^{Note 2}	1/fmck + 31		1/fмcк + 31		1/f _{MCK} + 31		1/f _{MCK} + 31		ns

(Notes, Caution and Remarks are listed on the next page.)

(8) Communication at different potential (1.8 V, 2.5 V, 3 V) (Simplified SPI (CSI) mode) (slave mode, SCKp ... external clock input)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note 5}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$ (2/2)

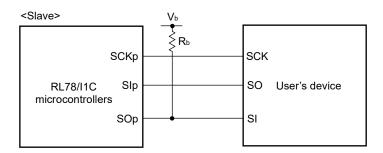
Parameter	Symbol	Conditions	` `	h-speed Mode	`	/-speed Mode	`	/-power Mode	LV (low- main)	-voltage Mode	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Delay time from SCKp↓ to SOp output ^{Note 4}	tkso2	$\begin{array}{l} 4.0 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}, \\ 2.7 \text{ V} \leq \text{V}_b \leq 4.0 \text{ V}, \\ C_b = 30 \text{ pF}, \text{ R}_b = 1.4 \text{ k}\Omega \\ \\ 2.7 \text{ V} \leq \text{EV}_{\text{DD}} < 4.0 \text{ V}, \\ 2.3 \text{ V} \leq \text{V}_b \leq 2.7 \text{ V}, \\ C_b = 30 \text{ pF}, \text{ R}_b = 2.7 \text{ k}\Omega \end{array}$		2/fмcк + 120 2/fмcк + 214		2/fмск + 573 2/fмск + 573		2/fмск + 573 2/fмск + 573		2/fмск + 573 2/fмск + 573	ns
		$1.9 \text{ V} \leq \text{EV}_{DD} < 3.3 \text{ V},$ $1.6 \text{ V} \leq \text{V}_{b} \leq 2.0 \text{ V}^{\text{Note 2}},$ $C_{b} = 30 \text{ pF}, R_{b} = 5.5 \text{ k}\Omega$		2/fмск + 573		2/fмск + 573		2/fмск + 573		2/fмск + 573	ns

Notes 1. Transfer rate in the SNOOZE mode: MAX. 1 Mbps

- 2. Use it with EV_{DD} ≥ V_b.
- **3.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **4.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 5. Either VDD or VBAT is selected by the battery backup function.

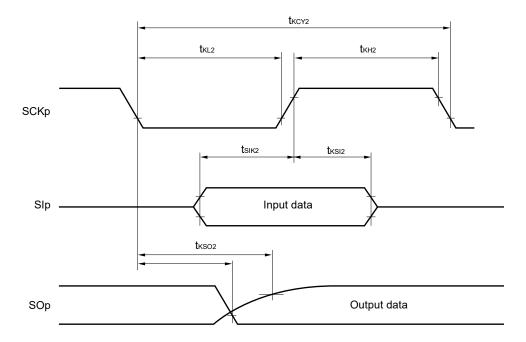
Caution Select the TTL input buffer for the SIp pin and SCKp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

Simplified SPI (CSI) mode connection diagram (during communication at different potential)

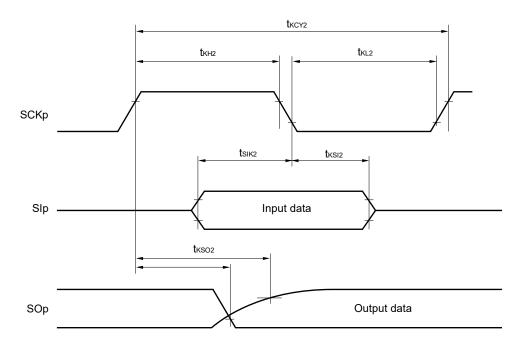


- **Remarks 1.** $R_b[\Omega]$:Communication line (SOp) pull-up resistance, $C_b[F]$: Communication line (SOp) load capacitance, $V_b[V]$: Communication line voltage
 - 2. p: CSI number (p = 00, 10, 30), m: Unit number, n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1, 8)
 - fMCK: Serial array unit operation clock frequency (Operating clock that is set with the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).
 - m: Unit number, n: Channel number (mn = 00, 02, 12))

Simplified SPI (CSI) mode serial transfer timing (slave mode) (during communication at different potential) (when DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1)



Simplified SPI (CSI) mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Caution Select the TTL input buffer for the SIp pin and SCKp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

Remark p: CSI number (p = 00, 10, 30), m: Unit number, n: Channel number (mn = 00, 02, 12), g: PIM and POM number (g = 0, 1, 8)

(9) Communication at different potential (1.8 V, 2.5 V, 3 V) (simplified I^2C mode) (1/2) (T_A = -40 to +85°C, 1.9 V \leq EV_{DD0} = EV_{DD1} \leq V_{DD}Note 4 \leq 5.5 V, Vss = EVss0 = EVss1 = 0 V)

Parameter	Symbol	Conditions	,	igh-speed n) Mode	•	v-speed Mode	,	v-power Mode	-	/-voltage) Mode	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCLr clock frequency	fscL	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$ $C_b = 50 \text{ pF}, R_b = 2.7 \text{ k}\Omega$		1000 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}	kHz
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$ $C_b = 50 \text{ pF}, R_b = 2.7 \text{ k}\Omega$		1000 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}	kHz
		$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$ $C_b = 100 \text{ pF}, R_b = 2.8 \text{ k}Ω$		400 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}	kHz
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$ $C_b = 100 \text{ pF}, R_b = 2.7 \text{ k}\Omega$		400 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}	kHz
		$\begin{split} 1.9 \ V &\leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V &\leq V_{b} \leq 2.0 \ V^{Note \ 2}, \\ C_{b} &= 100 \ pF, \ R_{b} = 5.5 \ k \Omega \end{split}$		300 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}	kHz
Hold time when SCLr = "L"	tLOW	$ \begin{aligned} 4.0 & \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}, \\ 2.7 & \text{ V} \leq \text{V}_{\text{b}} \leq 4.0 \text{ V}, \\ \text{C}_{\text{b}} & = 50 \text{ pF}, \text{ R}_{\text{b}} = 2.7 \text{ k}\Omega \end{aligned} $	475		1550		1550		1550		ns
		$ 2.7 \text{ V} \leq \text{EV}_{DD} < 4.0 \text{ V}, \\ 2.3 \text{ V} \leq \text{V}_b \leq 2.7 \text{ V}, \\ C_b = 50 \text{ pF}, R_b = 2.7 \text{ k}\Omega $	475		1550		1550		1550		ns
		$ \begin{aligned} 4.0 & \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}, \\ 2.7 & \text{ V} \leq \text{V}_b \leq 4.0 \text{ V}, \\ C_b &= 100 \text{ pF}, \text{ R}_b = 2.8 \text{ k}\Omega \end{aligned} $	1150		1150		1150		1150		ns
		$ \begin{aligned} 2.7 & \text{ V} \leq \text{EV}_{\text{DD}} < 4.0 \text{ V}, \\ 2.3 & \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}, \\ \text{C}_{\text{b}} &= 100 \text{ pF}, \text{ R}_{\text{b}} = 2.7 \text{ k}\Omega \end{aligned} $	1150		1150		1150		1150		ns
		$\begin{split} 1.9 \ V &\leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 2}}, \\ C_b &= 100 \ pF, \ R_b = 5.5 \ k\Omega \end{split}$	1150		1150		1150		1150		ns
Hold time when SCLr = "H"	tніgн	$ 4.0 \ V \le EV_{DD} \le 5.5 \ V, $ $ 2.7 \ V \le V_b \le 4.0 \ V, $ $ C_b = 50 \ pF, \ R_b = 2.7 \ k\Omega $	245		610		610		610		ns
		$ \begin{aligned} 2.7 & \text{ V} \leq \text{EV}_{\text{DD}} < 4.0 \text{ V}, \\ 2.3 & \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V}, \\ \text{C}_{\text{b}} & = 50 \text{ pF}, \text{ R}_{\text{b}} = 2.7 \text{ k}\Omega \end{aligned} $	200		610		610		610		ns
		$ \begin{aligned} 4.0 & \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}, \\ 2.7 & \text{ V} \leq \text{V}_{\text{b}} \leq 4.0 \text{ V}, \\ C_{\text{b}} & = 100 \text{ pF}, \text{ R}_{\text{b}} = 2.8 \text{ k}\Omega \end{aligned} $	675		610		610		610		ns
		$ 2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V}, \\ 2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V}, \\ C_b = 100 \text{ pF}, R_b = 2.7 \text{ k}\Omega $	600		610		610		610		ns
		$\begin{split} 1.9 \ V &\leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V &\leq V_{b} \leq 2.0 \ V^{Note \ 2}, \\ C_{b} &= 100 \ pF, \ R_{b} = 5.5 \ k \Omega \end{split}$	610		610		610		610		ns

(Notes, Caution and Remarks are listed on the next page.)

(9) Communication at different potential (1.8 V, 2.5 V, 3 V) (simplified I^2C mode) (2/2) (T_A = -40 to +85°C, 1.9 V \leq EV_{DD0} = EV_{DD1} \leq V_{DD}Note 4 \leq 5.5 V, Vss = EVss0 = EVss1 = 0 V)

Parameter	Symbol	Conditions	, 0	h-speed Mode	LS (low main)		LP (low main)	-power Mode	LV (low- main)	U	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Data setup time (reception)	tsu:dat	$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$ $C_b = 50 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	1/f _{MCK} + 135 ^{Note 3}		1/f _{MCK} + 190 ^{Note 3}		1/f _{MCK} + 190 ^{Note 3}		1/f _{MCK} + 190 ^{Note 3}		ns
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$ $C_b = 50 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	1/f _{MCK} + 135 ^{Note 3}		1/f _{MCK} + 190 ^{Note 3}		1/f _{MCK} + 190 ^{Note 3}		1/f _{MCK} + 190 ^{Note 3}		ns
		$4.0 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V},$ $2.7 \text{ V} \le \text{V}_b \le 4.0 \text{ V},$ $C_b = 100 \text{ pF}, R_b = 2.8 \text{ k}Ω$	1/f _{MCK} + 190 ^{Note 3}		1/f _{MCK} + 190 ^{Note 3}		1/f _{MCK} + 190 ^{Note 3}		1/f _{MCK} + 190 ^{Note 3}		ns
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V},$ $C_{b} = 100 \text{ pF}, R_{b} = 2.7 \text{ k}\Omega$	1/f _{MCK} + 190 ^{Note 3}		1/f _{MCK} + 190 ^{Note 3}		1/f _{MCK} + 190 ^{Note 3}		1/f _{MCK} + 190 ^{Note 3}		ns
		$\begin{split} 1.9 \ V &\leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 2}}, \\ C_b &= 100 \ pF, \ R_b = 5.5 \ k\Omega \end{split}$	1/f _{MCK} + 190 ^{Note 3}		1/f _{MCK} + 190 ^{Note 3}		1/f _{MCK} + 190 ^{Note 3}		1/f _{MCK} + 190 ^{Note 3}		ns
Data hold time (transmission)	thd:dat	$ 4.0 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}, \\ 2.7 \text{ V} \leq \text{V}_{\text{b}} \leq 4.0 \text{ V}, \\ \text{C}_{\text{b}} = 50 \text{ pF}, \text{R}_{\text{b}} = 2.7 \text{ k}\Omega $	0	305	0	305	0	305	0	305	ns
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$ $C_b = 50 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	0	305	0	305	0	305	0	305	ns
		$ 4.0 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}, \\ 2.7 \text{ V} \leq \text{V}_{\text{b}} \leq 4.0 \text{ V}, \\ C_{\text{b}} = 100 \text{ pF}, R_{\text{b}} = 2.8 \text{ k}\Omega $	0	355	0	355	0	355	0	355	ns
		$2.7 \text{ V} \le \text{EV}_{DD} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_b \le 2.7 \text{ V},$ $C_b = 100 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	0	355	0	355	0	355	0	355	ns
		$\begin{split} 1.9 \ V &\leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 2}}, \\ C_b &= 100 \ \text{pF}, \ R_b = 5.5 \ \text{k}\Omega \end{split}$	0	405	0	405	0	405	0	405	ns

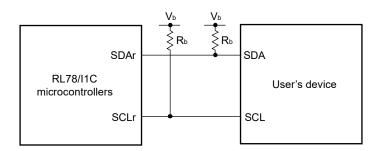
Notes 1. The value must also be equal to or less than fmck/4.

- 2. Use it with EV_{DD} ≥ V_b.
- 3. Set the fMCK value to keep the hold time of SCLr = "L" and SCLr = "H".
- **4.** Either V_{DD} or VBAT is selected by the battery backup function.

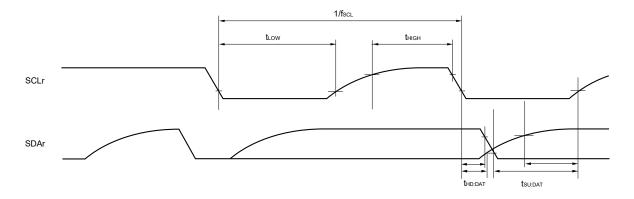
Caution Select the TTL input buffer and the N-ch open drain output (VDD tolerance) mode for the SDAr pin and the N-ch open drain output (VDD tolerance) mode for the SCLr pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

(Remarks are listed on the next page.)

Simplified I²C mode connection diagram (during communication at different potential)



Simplified I²C mode serial transfer timing (during communication at different potential)



Caution Select the TTL input buffer and the N-ch open drain output (VDD tolerance) mode for the SDAr pin and the N-ch open drain output (VDD tolerance) mode for the SCLr pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

- **Remarks 1.** R_b[Ω]:Communication line (SDAr, SCLr) pull-up resistance, C_b[F]: Communication line (SDAr, SCLr) load capacitance, V_b[V]: Communication line voltage
 - 2. r: IIC number (r = 00, 10, 30), g: PIM, POM number (g = 0, 1, 8)
 - fmck: Serial array unit operation clock frequency (Operating clock that is set with the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number, n: Channel number (mn = 00, 02, 12))

2.5.2 Serial interface IICA

(1) I²C standard mode (1/2)

(TA = -40 to +85°C, 1.7 V \leq EVDD0 = EVDD1 \leq VDDNote 3 \leq 5.5 V, Vss = EVss0 = EVss1 = 0 V)

Parameter	Symbol	C	conditions	, ,	h-speed Mode	`	/-speed Mode	`	v-power Mode	,	-voltage Mode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCLA0 clock frequency	fscL	Standard mode:	2.7 V ≤ EV _{DD} ≤ 5.5 V	0	100	0	100	0	100	0	100	kHz
, ,		fc∟κ≥ 1 MHz	1.9 V ≤ EV _{DD} ≤ 5.5 V	0	100	0	100	0	100	0	100	kHz
			1.8 V ≤ EV _{DD} ≤ 5.5 V	0	100	0	100	0	100	0	100	kHz
			1.7 V ≤ EV _{DD} ≤ 5.5 V	-	_	0	100	0	100	0	100	kHz
Setup time of	tsu:sta	2.7 V ≤ E\	/ _{DD} ≤ 5.5 V	4.7		4.7		4.7		4.7		μs
restart		1.9 V ≤ E\	/ _{DD} ≤ 5.5 V	4.7		4.7		4.7		4.7		μs
condition		1.8 V ≤ E\	/ _{DD} ≤ 5.5 V	4.7		4.7		4.7		4.7		μs
		1.7 V ≤ E\	/ _{DD} ≤ 5.5 V	_	_	4.7		4.7		4.7		μs
Hold time ^{Note 1}	thd:sta	2.7 V ≤ E\	/ _{DD} ≤ 5.5 V	4.0		4.0		4.0		4.0		μs
		1.9 V ≤ E\	/ _{DD} ≤ 5.5 V	4.0		4.0		4.0		4.0		μs
		1.8 V ≤ E\	/ _{DD} ≤ 5.5 V	4.0		4.0		4.0		4.0		μs
		1.7 V ≤ E\	/ _{DD} ≤ 5.5 V	_	_	4.0		4.0		4.0		μs
Hold time	tLOW	2.7 V ≤ E\	/ _{DD} ≤ 5.5 V	4.7		4.7		4.7		4.7		μs
when SCLA0		1.9 V ≤ E\	/ _{DD} ≤ 5.5 V	4.7		4.7		4.7		4.7		μs
= "L"		1.8 V ≤ E\	/ _{DD} ≤ 5.5 V	4.7		4.7		4.7		4.7		μs
		1.7 V ≤ E\	/ _{DD} ≤ 5.5 V	_	_	4.7		4.7		4.7		μs
Hold time	tніgн	2.7 V ≤ E\	/ _{DD} ≤ 5.5 V	4.0		4.0		4.0		4.0		μs
when SCLA0		1.9 V ≤ E\	/ _{DD} ≤ 5.5 V	4.0		4.0		4.0		4.0		μs
= "H"		1.8 V ≤ E\	/ _{DD} ≤ 5.5 V	4.0		4.0		4.0		4.0		μs
		1.7 V ≤ E\	/ _{DD} ≤ 5.5 V	_	_	4.0		4.0		4.0		μs
Data setup	tsu:dat	2.7 V ≤ E\	/ _{DD} ≤ 5.5 V	250		250		250		250		μs
time		1.9 V ≤ E\	/ _{DD} ≤ 5.5 V	250		250		250		250		μs
(reception)		1.8 V ≤ E\	/ _{DD} ≤ 5.5 V	250		250		250		250		μs
		1.7 V ≤ E\	/ _{DD} ≤ 5.5 V	_	_	250		250		250		μs
Data hold time	thd:dat	2.7 V ≤ E\	/ _{DD} ≤ 5.5 V	0	3.45	0	3.45	0	3.45	0	3.45	μs
(transmission)		1.9 V ≤ E\	/ _{DD} ≤ 5.5 V	0	3.45	0	3.45	0	3.45	0	3.45	μs
		1.8 V ≤ E\	/ _{DD} ≤ 5.5 V	0	3.45	0	3.45	0	3.45	0	3.45	μs
		1.7 V ≤ E\	/ _{DD} ≤ 5.5 V	_	_	0	3.45	0	3.45	0	3.45	μs

(Notes and $\mbox{\bf Remark}$ are listed on the next page.)

(1) I²C standard mode (2/2)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note 3}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

Parameter	Symbol	Conditions	, ,	h-speed Mode	`	v-speed Mode	`	/-power Mode	`	-voltage Mode	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Setup time of	tsu:sto	2.7 V ≤ EV _{DD} ≤ 5.5 V	4.0		4.0		4.0		4.0		μs
stop condition		1.9 V ≤ EV _{DD} ≤ 5.5 V	4.0		4.0		4.0		4.0		μs
		1.8 V ≤ EV _{DD} ≤ 5.5 V	4.0		4.0		4.0		4.0		μs
		1.7 V ≤ EV _{DD} ≤ 5.5 V	_	_	4.0		4.0		4.0		μs
Bus-free time	t BUF	2.7 V ≤ EV _{DD} ≤ 5.5 V	4.7		4.7		4.7		4.7		μs
		1.9 V ≤ EV _{DD} ≤ 5.5 V	4.7		4.7		4.7		4.7		μs
		1.8 V ≤ EV _{DD} ≤ 5.5 V	4.7		4.7		4.7		4.7		μs
		1.7 V ≤ EV _{DD} ≤ 5.5 V	_	_	4.7		4.7		4.7		μs

- Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.
 - 2. The maximum value (MAX.) of thd:DAT is during normal transfer and a clock stretch state is inserted in the ACK (acknowledge) timing.
 - **3.** Either V_{DD} or VBAT is selected by the battery backup function.

Remark The maximum value of C_b (communication line capacitance) and the value of R_b (communication line pull-up resistor) at that time in each mode are as follows.

Standard mode: $C_b = 400 \text{ pF}, R_b = 2.7 \text{ k}\Omega$

(2) I2C fast mode

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note 3}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

Parameter	Symbol	Co	onditions	` `	h-speed Mode	`	v-speed Mode	`	v-power Mode	,	-voltage Mode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCLA0 clock frequency	fscL	Fast mode:	2.7 V ≤ EV _{DD} ≤ 5.5 V	0	400	0	400	-	-	0	400	kHz
		fc∟k≥ 3.5 MHz	1.9 V ≤ EV _{DD} ≤ 5.5 V	0	400	0	400	-	-	0	400	kHz
Setup time of	tsu:sta	2.7 V ≤ EV	/ _{DD} ≤ 5.5 V	0.6		0.6		_	_	0.6		μs
restart condition		1.9 V ≤ EV	¹ / _{DD} ≤ 5.5 V	0.6		0.6		-	-	0.6		μs
Hold time ^{Note 1}	thd:sta	2.7 V ≤ EV	/ _{DD} ≤ 5.5 V	0.6		0.6		_	_	0.6		μs
		1.9 V ≤ EV	/ _{DD} ≤ 5.5 V	0.6		0.6		_	_	0.6		μs
Hold time	tLOW	2.7 V ≤ EV	/ _{DD} ≤ 5.5 V	1.3		1.3		_	_	1.3		μs
when SCLA0 = "L"		1.9 V ≤ EV	⁷ DD ≤ 5.5 V	1.3		1.3		_	_	1.3		μs
Hold time	t HIGH	2.7 V ≤ EV	/ _{DD} ≤ 5.5 V	0.6		0.6		_	_	0.6		μs
when SCLA0 = "H"		1.9 V ≤ EV	/ _{DD} ≤ 5.5 V	0.6		0.6		-	-	0.6		μs
Data setup	tsu:dat	2.7 V ≤ EV	/ _{DD} ≤ 5.5 V	100		100		_	_	100		ns
time (reception)		1.9 V ≤ EV	⁷ DD ≤ 5.5 V	100		100		-	_	100		ns
Data hold time	thd:dat	2.7 V ≤ EV	/ _{DD} ≤ 5.5 V	0	0.9	0	0.9	_	_	0	0.9	μs
(transmission) Note 2		1.9 V ≤ EV	⁷ DD ≤ 5.5 V	0	0.9	0	0.9	_	_	0	0.9	μs
Setup time of	tsu:sto	2.7 V ≤ EV _{DD} ≤ 5.5 V		0.6		0.6		_	_	0.6		μs
stop condition		1.9 V ≤ EV _{DD} ≤ 5.5 V		0.6		0.6		_	_	0.6		μs
Bus-free time	t BUF	2.7 V ≤ EV	/ _{DD} ≤ 5.5 V	1.3		1.3		_	_	1.3		μs
		1.9 V ≤ EV	/ _{DD} ≤ 5.5 V	1.3		1.3		_	_	1.3		μs

Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.

- 2. The maximum value (MAX.) of thd:DAT is during normal transfer and a clock stretch state is inserted in the ACK (acknowledge) timing.
- 3. Either V_{DD} or VBAT is selected by the battery backup function.

Remark The maximum value of C_b (communication line capacitance) and the value of R_b (communication line pull-up resistor) at that time in each mode are as follows.

Fast mode: $C_b = 320 \text{ pF}, R_b = 1.1 \text{ k}\Omega$

(3) I²C fast mode plus

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.7 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note 3}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

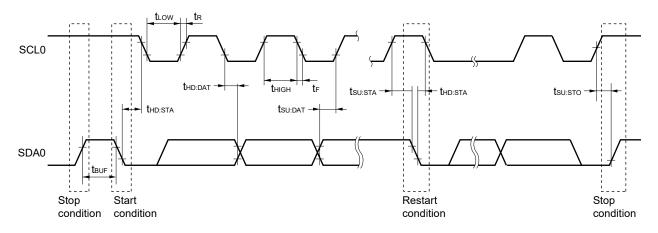
Parameter	Symbol	Со	nditions		h-speed Mode	`	/-speed Mode		/-power Mode	,	-voltage Mode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCLA0 clock frequency	fscL	Fast mode plus: fcLk ≥ 10 MHz	2.7 V ≤ EV _{DD} ≤ 5.5 V	0	1000	1	-	-	-	_	-	kHz
Setup time of restart condition	tsu:sta	2.7 V ≤ E	V _{DD} ≤ 5.5 V	0.26		-	-	-	-	_	-	μs
Hold time ^{Note 1}	thd:sta	2.7 V ≤ E	V _{DD} ≤ 5.5 V	0.26		ı	_	-	_	_	_	μs
Hold time when SCLA0 = "L"	tLOW	2.7 V ≤ E	V _{DD} ≤ 5.5 V	0.5		-	-	_	_	-	_	μs
Hold time when SCLA0 = "H"	t HIGH	2.7 V ≤ E	V _{DD} ≤ 5.5 V	0.26		-	-	_	_	-	_	μs
Data setup time (reception)	tsu:dat	2.7 V ≤ E	V _{DD} ≤ 5.5 V	50		-	-	_	_	-	_	ns
Data hold time (transmission) ^{Note 2}	thd:dat	2.7 V ≤ E	V _{DD} ≤ 5.5 V	0	0.5	-	-	_	_	-	_	μs
Setup time of stop condition	tsu:sto	2.7 V ≤ E	V _{DD} ≤ 5.5 V	0.26		_	_	_	_	-	_	μs
Bus-free time	t BUF	2.7 V ≤ E	V _{DD} ≤ 5.5 V	0.5		_	_	_	_	_	_	μs

- Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.
 - 2. The maximum value (MAX.) of thd:DAT is during normal transfer and a clock stretch state is inserted in the ACK (acknowledge) timing.
 - 3. Either VDD or VBAT is selected by the battery backup function.

Remark The maximum value of C_b (communication line capacitance) and the value of R_b (communication line pull-up resistor) at that time in each mode are as follows.

Fast mode plus: $C_b = 120 \text{ pF}$, $R_b = 1.1 \text{ k}\Omega$

IICA serial transfer timing



2.6 Analog Characteristics

2.6.1 A/D converter characteristics

(1) When reference voltage (+) = AVREFP/ANIO (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pins: ANI2 to ANI5 and internal reference voltage

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le V_{DD}^{Note 3} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V}, \text{reference voltage (+)} = \text{AV}_{REFP}, \text{reference voltage (-)} = \text{AV}_{REFM} = 0 \text{ V})$

Parameter	Symbol	C	conditions	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error ^{Note 1}	AINL	10-bit resolution AV _{REFP} = V _{DD}	1.9 V ≤ AV _{REFP} ≤ 5.5 V		1.2	±5.0	LSB
Conversion time	tconv	10-bit resolution	3.6 V ≤ V _{DD} ≤ 5.5 V	2.125		39	μs
			2.7 V ≤ V _{DD} ≤ 5.5 V	3.1875		39	μs
			1.9 V ≤ V _{DD} ≤ 5.5 V	17		39	μs
Zero-scale error ^{Notes 1, 2}	Ezs	10-bit resolution AV _{REFP} = V _{DD}	1.9 V ≤ AV _{REFP} ≤ 5.5 V			±0.35	%FSR
Full-scale error ^{Notes 1, 2}	E _F s	10-bit resolution AV _{REFP} = V _{DD}	1.9 V ≤ AV _{REFP} ≤ 5.5 V			±0.35	%FSR
Integral linearity error ^{Note 1}	ILE	10-bit resolution AV _{REFP} = V _{DD}	1.9 V ≤ AV _{REFP} ≤ 5.5 V			±3.5	LSB
Differential linearity error ^{Note 1}	DLE	10-bit resolution AV _{REFP} = V _{DD}	1.9 V ≤ AV _{REFP} ≤ 5.5 V			±2.0	LSB
Reference voltage (+)	AVREFP			1.9		V _{DD}	V
Analog input voltage	VAIN			0		AVREFP	V
	V _{BGR}	Select internal reference 2.4 V ≤ V _{DD} ≤ 5.5 V,	ence voltage output HS (high-speed main) mode	1.38	1.45	1.5	V

Notes 1. Excludes quantization error (±1/2 LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. Either V_{DD} or VBAT is selected by the battery backup function.

(2) When reference voltage (+) = V_{DD} (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = V_{SS} (ADREFM = 0), target pins: ANI0 to ANI5 and internal reference voltage

(T_A = -40 to +85°C, 1.9 V ≤ V_{DD}Note 3 ≤ 5.5 V, V_{SS} = 0 V, reference voltage (+) = V_{DD}Note 3, reference voltage (-) = V_{SS})

Parameter	Symbol	(Conditions	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error ^{Note 1}	AINL	10-bit resolution	1.9 V ≤ V _{DD} ≤ 5.5 V		1.2	±10.5	LSB
Conversion time	tconv	10-bit resolution	3.6 V ≤ V _{DD} ≤ 5.5 V	2.125		39	μs
			2.7 V ≤ V _{DD} ≤ 5.5 V	3.1875		39	μs
			1.9 V ≤ V _{DD} ≤ 5.5 V	17		39	μs
Zero-scale error ^{Notes 1, 2}	Ezs	10-bit resolution	1.9 V ≤ V _{DD} ≤ 5.5 V			±0.85	%FSR
Full-scale errorNotes 1, 2	Ers	10-bit resolution	1.9 V ≤ V _{DD} ≤ 5.5 V			±0.85	%FSR
Integral linearity error Note 1	ILE	10-bit resolution	1.9 V ≤ V _{DD} ≤ 5.5 V			±4.0	LSB
Differential linearity errorNote 1	DLE	10-bit resolution	1.9 V ≤ V _{DD} ≤ 5.5 V			±2.0	LSB
Analog input voltage	Vain			0		V _{DD}	V
	V _{BGR}		ence voltage output, HS (high-speed main) mode	1.38	1.45	1.5	V

Notes 1. Excludes quantization error (±1/2 LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. Either VDD or VBAT is selected by the battery backup function.

Caution When using reference voltage (+) = VDD, taking into account the voltage drop due to the effect of the power switching circuit of the battery backup function and use the A/D conversion result. In addition, enter HALT mode during A/D conversion and set VDD port to input.

(3) When reference voltage (+) = Internal reference voltage (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pins: ANI0, ANI2 to ANI5

(TA = -40 to +85°C, 2.4 V \leq V_{DD}Note 3 \leq 5.5 V, Vss = 0 V, reference voltage (+) = V_{BGR}, reference voltage (-) = AV_{REFM} = 0 V, HS (high-speed main) mode)

Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Resolution	RES				8		bit
Conversion time	tconv	8-bit resolution	2.4 V ≤ V _{DD} ≤ 5.5 V	17		39	μs
Zero-scale error ^{Notes 1, 2}	Ezs	8-bit resolution	2.4 V ≤ V _{DD} ≤ 5.5 V			±0.60	%FSR
Integral linearity errorNote 1	ILE	8-bit resolution	2.4 V ≤ V _{DD} ≤ 5.5 V			±2.0	LSB
Differential linearity errorNote 1	DLE	8-bit resolution	2.4 V ≤ V _{DD} ≤ 5.5 V			±1.0	LSB
Reference voltage (+)	V _{BGR}			1.38	1.45	1.5	V
Analog input voltage	Vain			0		V _{BGR}	V

Notes 1. Excludes quantization error (±1/2 LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. Either VDD or VBAT is selected by the battery backup function.

2.6.2 24-bit $\Delta\Sigma$ A/D converter characteristics

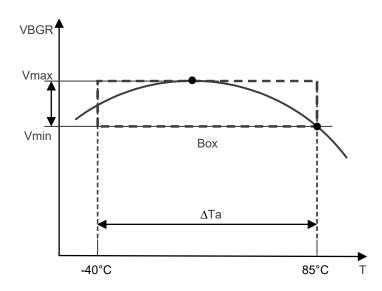
(1) Reference voltage

(Ta = -40 to +85°C, 2.4 V \leq VDD^{Note 1} \leq 5.5 V, Vss = AVss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Internal reference voltage	Vavrto			0.8		V
Temperature coefficient for internal reference voltage Note 2	ТСвох	$0.47~\mu\text{F}$ capacitor connected to AREGC, AVRT, and AVCM pins		10		ppm/°C

- Notes 1. Either V_{DD} or VBAT is selected by the battery backup function.
 - 2. This is as stipulated by the BOX method.

$$TC_{BOX} = \frac{1}{V_{min}} \cdot \frac{V_{max} - V_{min}}{\Delta T_{a}}$$



(2) Analog input

(TA = -40 to +85°C, 2.4 V \leq VDDNote \leq 5.5 V, Vss = AVss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Input voltage range (differential voltage)	Vain	x1 gain	-500		500	mV
		x2 gain	-250		250	
		x4 gain	-125		125	
		x8 gain	-62.5		62.5	
		x16 gain	-31.25		31.25	
		x32 gain	-15.625		15.625	
Input gain	ainGAIN	x1 gain		1		Times
		x2 gain		2		
		x4 gain		4		
		x8 gain		8		
		x16 gain		16		
		x32 gain		32		
Input impedance	ainRIN	Differential voltage	150	360		kΩ
		Single-ended voltage	100	240		

 $\textbf{Note} \quad \text{Either V_{DD} or VBAT is selected by the battery backup function}.$

(3) 4 kHz sampling mode

(TA = -40 to +85°C, 2.4 V \leq VDDNote \leq 5.5 V, Vss = AVss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Operation clock	f DSAD	fx oscillation clock, input external clock or high- speed on-chip oscillator clock is used		12		MHz
Sampling frequency	f s			3906.25		Hz
Oversampling frequency	fos			1.5		MHz
Output data rate	TDATA			256		μs
Data width	RES			24		bit
SNDR	SNDR	x1 gain High-speed system clock is selected as operating clock of 24-bit $\Delta\Sigma$ A/D converter (bit 0 of PCKC register (DSADCK) = 1)		80		dΒ
		x16 gain High-speed system clock is selected as operating clock of 24-bit $\Delta\Sigma$ A/D converter (bit 0 of PCKC register (DSADCK) = 1)	69	74		
		x32 gain High-speed system clock is selected as operating clock of 24-bit $\Delta\Sigma$ A/D converter (bit 0 of PCKC register (DSADCK) = 1)	65	69		
Passband (low pass band)	fchpf	At –3 dB (phase in high pass filter not adjusted) Bits 7 and 6 of DSADHPFCR register (DSADCOF1, DSADCOF0) = 00		0.607		Hz
		At –3 dB (phase in high pass filter not adjusted) Bits 7 and 6 of DSADHPFCR register (DSADCOF1, DSADCOF0) = 01		1.214		Hz
		At –3 dB (phase in high pass filter not adjusted) Bits 7 and 6 of DSADHPFCR register (DSADCOF1, DSADCOF0) = 10		2.429		Hz
		At –3 dB (phase in high pass filter not adjusted) Bits 7 and 6 of DSADHPFCR register (DSADCOF1, DSADCOF0) = 11		4.857		Hz
In-band ripple 1	rp1	45 Hz to 55 Hz @50 Hz 54 Hz to 66 Hz @60 Hz	-0.01		0.01	dB
In-band ripple 2	rp2	45 Hz to 275 Hz	-0.1		0.1	
In-band ripple 3	rp3	45 Hz to 1100 Hz	-0.1		0.1	
Passband (high pass band)	fClpf	−3 dB		1672		Hz
Stopband (high pass band)	fatt	-80 dB		2545		Hz
Out-band attenuation	ATT1	fs	-80			dB
	ATT2	2 fs	-80			dB

(4) 2 kHz sampling mode

(Ta = -40 to +85°C, 2.4 V \leq VDD^{Note} \leq 5.5 V, Vss = AVss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Operation clock	fdsad	fx oscillation clock, input external clock or high- speed on-chip oscillator clock is used		12		MHz
Sampling frequency	fs			1953.125		Hz
Oversampling frequency	fos			0.75		MHz
Output data rate	TDATA			512		μs
Data width	RES			24		bit
SNDR	SNDR	x1 gain High-speed system clock is selected as operating clock of 24-bit $\Delta\Sigma$ A/D converter (bit 0 of PCKC register (DSADCK) = 1)		80		dB
		x16 gain High-speed system clock is selected as operating clock of 24-bit $\Delta\Sigma$ A/D converter (bit 0 of PCKC register (DSADCK) = 1)	69	74		
		x32 gain High-speed system clock is selected as operating clock of 24-bit $\Delta\Sigma$ A/D converter (bit 0 of PCKC register (DSADCK) = 1)	65	69		
Passband (low pass band)	fChpf	At –3 dB (phase in high pass filter not adjusted)		0.303		Hz
In-band ripple 1	rp1	45 Hz to 55 Hz	-0.01		0.01	dB
In-band ripple 2	rp2	45 Hz to 275 Hz	-0.1		0.1	
In-band ripple 3	rp3	45 Hz to 660 Hz	-0.1		0.1	
Passband (high pass band)	fclpf	-3 dB		836		Hz
Stopband (high pass band)	fatt	-80 dB		1273		Hz
Out-band attenuation	ATT1	fs	-80			dB
	ATT2	2 fs	-80			dB

Note Either V_{DD} or VBAT is selected by the battery backup function.

2.6.3 Temperature sensor 2 characteristics

(TA = -40 to +85°C, 2.4 V \leq VDD^{Note 2} \leq 5.5 V, Vss = 0 V, HS (high-speed main) mode)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Temperature sensor 2 output voltage	Vоит			0.67		V
Temperature coefficient	F _{VTMPS2}	Temperature sensor that depends on the temperature	-11.7	-10.7	-9.7	mV/°C
Operation stabilization wait time ^{Note 1}	tтмром	Operable		15	50	μs
	tтмрснg	Switching mode		5	15	μs

Notes 1. Time to drop to output stable value ±5LSB (±7 mV) or less.

2. Either V_{DD} or VBAT is selected by the battery backup function.

2.6.4 POR circuit characteristics

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	VPOR	When power supply rises ^{Note 1}	1.47	1.51	1.55	V
	V _{PDR}	When power supply falls ^{Note 2}	1.46	1.50	1.54	V

- **Notes 1.** Be sure to maintain the reset state until the power supply voltage rises over the minimum V_{DD} value in the operating voltage range specified in **2.4 AC Characteristics**, by using the voltage detector or external reset pin.
 - 2. If the power supply voltage falls while the voltage detector is off, be sure to either shift to STOP mode or execute a reset by using the voltage detector or external reset pin before the power supply voltage falls below the minimum operating voltage specified in 2.4 AC Characteristics.

2.6.5 LVD circuit characteristics

LVD Detection Voltage of Reset Mode and Interrupt Mode

(TA = -40 to +85°C, $V_{PDR} \le V_{DD}^{Note} \le 5.5 \text{ V}$, $V_{SS} = 0 \text{ V}$)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	V _{LVD0}	When power supply rises	3.98	4.06	4.24	V
		When power supply falls	3.90	3.98	4.16	V
	V _{LVD1}	When power supply rises	3.68	3.75	3.92	V
		When power supply falls	3.60	3.67	3.84	V
	V _{LVD2}	When power supply rises	3.07	3.13	3.29	V
		When power supply falls	3.00	3.06	3.22	V
	V _{LVD3}	When power supply rises	2.96	3.02	3.18	V
		When power supply falls	2.90	2.96	3.12	V
	V _{LVD4}	When power supply rises	2.86	2.92	3.07	V
		When power supply falls	2.80	2.86	3.01	V
	V _{LVD5}	When power supply rises	2.76	2.81	2.97	V
		When power supply falls	2.70	2.75	2.91	V
	V _{LVD6}	When power supply rises	2.66	2.71	2.86	V
		When power supply falls	2.60	2.65	2.80	V
	V _{LVD7}	When power supply rises	2.56	2.61	2.76	V
		When power supply falls	2.50	2.55	2.70	V
	V _{LVD8}	When power supply rises	2.45	2.50	2.65	V
		When power supply falls	2.40	2.45	2.60	V
	V _{LVD9}	When power supply rises	2.05	2.09	2.23	V
		When power supply falls	2.00	2.04	2.18	V
	V _{LVD10}	When power supply rises	1.94	1.98	2.12	V
		When power supply falls	1.90	1.94	2.08	V
	V _{LVD11}	When power supply rises	1.84	1.88	2.01	V
		When power supply falls	1.80	1.84	1.97	V
	V _{LVD12}	When power supply rises	1.74	1.77	1.81	V
		When power supply falls	1.70	1.73	1.77	V
Minimum pulse width	tLW		300			μs
Detection delay time					300	μs

LVD Detection Voltage of Interrupt & Reset Mode

(Ta = -40 to +85°C, $V_{PDR} \le V_{DD}^{Note} \le 5.5 \text{ V}$, $V_{SS} = 0 \text{ V}$)

Parameter	Symbol		Con	ditions	MIN.	TYP.	MAX.	Unit
Detection voltage	V _{LVD8}	VPOC2,	VPOC1, VPOC0 = 0,	0, 1, falling reset voltage: 1.8 V	1.80	1.84	1.97	V
	V _{LVD7}		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	1.94	1.98	2.12	V
			(+0.1 V)	Falling interrupt voltage	1.90	1.94	2.08	V
	V _{LVD6}		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.05	2.09	2.23	V
			(+0.2 V)	Falling interrupt voltage	2.00	2.04	2.18	V
	V _{LVD1}		LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.07	3.13	3.29	V
			(+1.2 V)	Falling interrupt voltage	3.00	3.06	3.22	V
	V _{LVD8}	VPOC2,	VPOC1, VPOC0 = 0,	1, 0, falling reset voltage	2.40	2.45	2.60	V
	V _{LVD7}		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.56	2.61	2.76	V
				Falling interrupt voltage	2.50	2.55	2.70	V
	V _{LVD6}		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.66	2.71	2.86	V
				Falling interrupt voltage	2.60	2.65	2.80	V
	V _{LVD1}		LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.68	3.75	3.92	V
				Falling interrupt voltage	3.60	3.67	3.84	V
	V _{LVD5}	VPOC2,	VPOC1, VPOC0 = 0,	1, 1, falling reset voltage	2.70	2.75	2.91	V
	V _{LVD4}		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.86	2.92	3.07	V
				Falling interrupt voltage	2.80	2.86	3.01	V
	V _{LVD3}		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.96	3.02	3.18	V
	VLVDO			Falling interrupt voltage	2.90	2.96	3.12	V
		LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.98	4.06	4.24	V	
				Falling interrupt voltage	3.90	3.98	4.16	V

Note Either VDD or VBAT is selected by the battery backup function.

2.6.6 Power supply voltage rising slope characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Power supply voltage rising slope	SVDDR				54	V/ms
	SVRTCR					

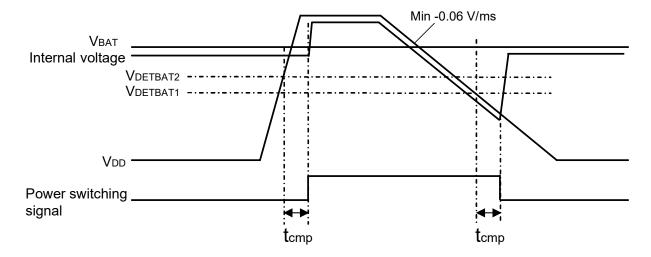
Caution Make sure to keep the internal reset state by the LVD circuit or an external reset until VDD reaches the operating voltage range shown in 2.4 AC Characteristics.

2.7 Battery Backup Function

2.7.1 Power supply switching characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$

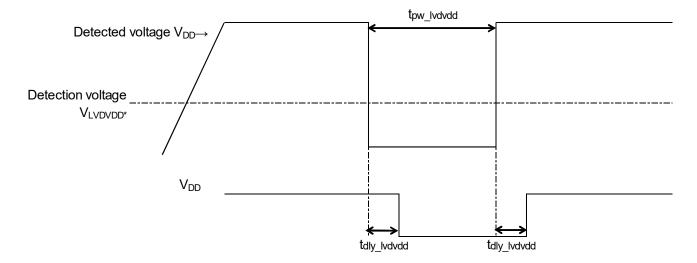
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Power switching detection voltage	V _{DETBAT1}	$V_{DD} \rightarrow VBAT$ $V_{BAT} \le 3.6 V$	2.09	2.18	2.26	V
	VDETBAT2	$VBAT \rightarrow V_{DD}$ $V_{BAT} \leq 3.6 \text{ V}$	2.19	2.28	2.36	V
V _{DD} fall slope	SVDDF		-0.06			V/ms
Response time of power switch detector	tcmp	V _{BAT} ≤ 3.6 V			500	μs



2.7.2 VDD pin voltage detection characteristics

(Ta = -40 to +85°C, 1.9 V \leq VDD^{Note} \leq 5.5 V, Vss = 0 V)

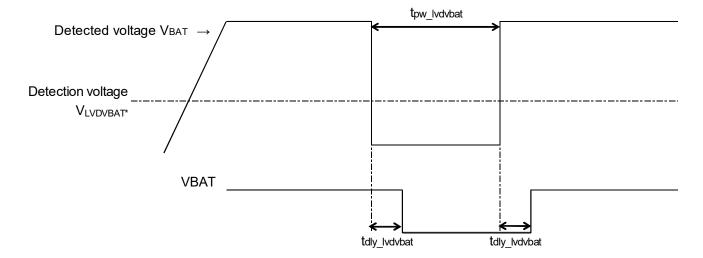
Parameter	Symbol	LVDVDD[2:0]	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	VLVDVDD0	000	Rising	2.40	2.53	2.65	V
			Falling	2.33	2.46	2.58	V
	VLVDVDD1	001	Rising	2.60	2.74	2.86	V
			Falling	2.53	2.67	2.79	V
	VLVDVDD2	010	Rising	2.79	2.94	3.07	V
			Falling	2.73	2.87	2.99	V
	V _{LVDVDD3}	011	Rising	3.00	3.15	3.28	V
			Falling	2.93	3.08	3.21	V
	VLVDVDD4	100	Rising	3.30	3.46	3.60	V
			Falling	3.23	3.39	3.52	V
	V _{LVDVDD5}	101	Rising	3.59	3.77	3.91	V
			Falling	3.53	3.70	3.84	V
Minimum pulse width	tpw_lvdvdd	_	_	300			μs
Detection delay time	tdly_lvdvdd	_	_			300	μs



2.7.3 VBAT pin voltage detection characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le V_{DD}^{Note} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$

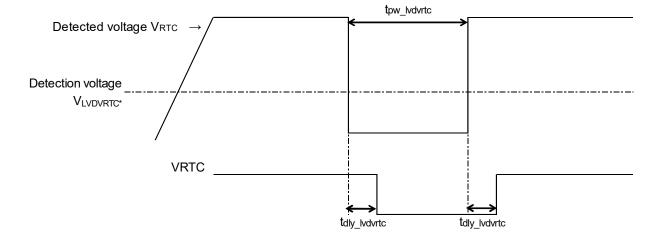
Parameter	Symbol	LVDVBAT[2:0]	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	VLVDVBAT0	000	Rising	1.99	2.11	2.22	V
			Falling	1.94	2.05	2.16	V
	VLVDVBAT1	001	Rising	2.09	2.21	2.32	V
			Falling	2.03	2.15	2.26	V
	VLVDVBAT2	010	Rising	2.20	2.32	2.43	V
			Falling	2.14	2.26	2.37	V
	VLVDVBAT3	011	Rising	2.29	2.42	2.53	V
			Falling	2.23	2.36	2.47	V
	VLVDVBAT4	100	Rising	2.38	2.52	2.64	V
			Falling	2.33	2.46	2.58	V
	VLVDVBAT5	101	Rising	2.48	2.62	2.74	V
			Falling	2.42	2.56	2.68	V
	VLVDVBAT6	110	Rising	2.59	2.73	2.86	V
			Falling	2.53	2.67	2.79	V
Minimum pulse width	tpw_lvdvbat	_	_	300			μs
Detection delay time	tdly_lvdvbat	_	_			300	μs



2.7.4 VRTC pin voltage detection characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le \text{V}_{DD}^{Note} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

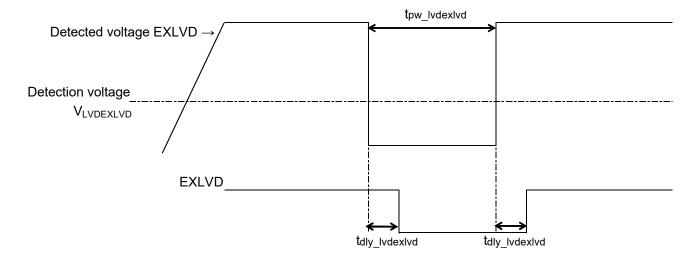
Parameter	Symbol	LVDVRTC[1:0]	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	VLVDVRTC0	00	Rising	2.16	2.22	2.28	V
			Falling	2.10	2.16	2.22	V
	VLVDVRTC1	01	Rising	2.36	2.43	2.50	V
			Falling	2.30	2.37	2.44	V
	VLVDVRTC2	10	Rising	2.56	2.63	2.70	V
			Falling	2.50	2.57	2.64	V
	VLVDVRTC3	11	Rising	2.76	2.84	2.92	V
			Falling	2.70	2.78	2.86	V
Minimum pulse width	tpw_lvdvrtc	_	_	300			μs
Detection delay time	tdly_lvdvrtc	_	_			300	μs



2.7.5 EXLVD pin voltage detection

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le \text{V}_{DD}^{Note} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	VLVDEXLVD	Rising	1.25	1.33	1.41	V
		Falling	1.20	1.28	1.36	V
Minimum pulse width	tpw_lvdexlvd	_	300			μs
Detection delay time	tdly_lvdexlvd	_			300	μs
Pin resistor	rin_exlvd	LVDEXLVDEN = 1		34		ΜΩ



2.8 LCD Characteristics

2.8.1 Resistance division method

(1) Static display mode

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, V_{L4} \text{ (MIN.)} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	V _{L4}		2.0		$V_{\text{DD}}^{\text{Note}}$	V

Note Either V_{DD} or VBAT is selected by the battery backup function.

(2) 1/2 bias method, 1/4 bias method

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, V_{L4} \text{ (MIN.)} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	V _{L4}		2.7		V _{DD} Note	V

Note Either V_{DD} or VBAT is selected by the battery backup function.

(3) 1/3 bias method

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, V_{L4} \text{ (MIN.)} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	V _{L4}		2.5		V _{DD} Note	V

2.8.2 Internal voltage boosting method

(1) 1/3 bias method

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note 4}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

Parameter	Symbol	Cond	itions	MIN.	TYP.	MAX.	Unit
LCD output voltage variation range	V _{L1}	C1 to C4 ^{Note 1}	VLCD = 04H	0.90	1.00	1.08	V
		= 0.47 µF	VLCD = 05H	0.95	1.05	1.13	V
			VLCD = 06H	1.00	1.10	1.18	V
			VLCD = 07H	1.05	1.15	1.23	V
			VLCD = 08H	1.10	1.20	1.28	V
			VLCD = 09H	1.15	1.25	1.33	V
			VLCD = 0AH	1.20	1.30	1.38	V
			VLCD = 0BH	1.25	1.35	1.43	٧
			VLCD = 0CH	1.30	1.40	1.48	V
			VLCD = 0DH	1.35	1.45	1.53	V
			VLCD = 0EH	1.40	1.50	1.58	٧
			VLCD = 0FH	1.45	1.55	1.63	V
			VLCD = 10H	1.50	1.60	1.68	V
			VLCD = 11H	1.55	1.65	1.73	٧
			VLCD = 12H	1.60	1.70	1.78	V
			VLCD = 13H	1.65	1.75	1.83	V
Doubler output voltage	V _{L2}	C1 to C4 ^{Note 1} =	0.47 μF	2 V _{L1} –0.10	2 V _{L1}	2 V _{L1}	٧
Tripler output voltage	V _{L4}	C1 to C4 ^{Note 1} =	0.47 μF	3 V _{L1} –0.15	3 VL1	3 VL1	V
Reference voltage setup timeNote 2	tvwait1			5			ms
Voltage boost wait time ^{Note 3}	tvwait2	C1 to C4 ^{Note 1} =	0.47 μF	500			ms

Notes 1. This is a capacitor that is connected between voltage pins used to drive the LCD.

- C1: A capacitor connected between CAPH and CAPL
- C2: A capacitor connected between V_{L1} and GND
- C3: A capacitor connected between VL2 and GND
- C4: A capacitor connected between VL4 and GND

$$C1 = C2 = C3 = C4 = 0.47 \mu F \pm 30\%$$

- 2. This is the time required to wait from when the reference voltage is specified by using the VLCD register (or when the internal voltage boosting method is selected (by setting the MDSET1 and MDSET0 bits of the LCDM0 register to 01B) if the default value reference voltage is used) until voltage boosting starts (VLCON = 1).
- 3. This is the wait time from when voltage boosting is started (VLCON = 1) until display is enabled (LCDON = 1).
- **4.** Either V_{DD} or VBAT is selected by the battery backup function.

(2) 1/4 bias method

(TA = -40 to +85°C, 1.7 V \leq EVDD0 = EVDD1 \leq VDDNote 4 \leq 5.5 V, Vss = EVss0 = EVss1 = 0 V)

Parameter	Symbol	Cor	ditions	MIN.	TYP.	MAX.	Unit
LCD output voltage variation range	V _{L1}	C1 to C5 ^{Note 1}	VLCD = 04H	0.90	1.00	1.08	V
		= 0.47 µF	VLCD = 05H	0.95	1.05	1.13	V
			VLCD = 06H	1.00	1.10	1.18	V
		VLCD = 07H VLCD = 08H VLCD = 09H VLCD = 0AH	VLCD = 07H	1.05	1.15	1.23	V
			VLCD = 08H	1.10	1.20	1.28	V
			VLCD = 09H	1.15	1.25	1.33	V
			1.20	1.30	1.38	V	
Doubler output voltage	V _{L2}	C1 to C5 ^{Note 1} =	0.47 μF	2 VL1-0.08	2 V _{L1}	2 V _{L1}	V
Tripler output voltage	V _{L3}	C1 to C5 ^{Note 1} =	0.47 μF	3 VL1-0.12	3 VL1	3 V _{L1}	V
Quadruply output voltage	V _{L4}	C1 to C5 ^{Note 1} =	0.47 μF	4 VL1-0.16	4 V _{L1}	4 V _{L1}	V
Reference voltage setup timeNote 2	tvwait1			5			ms
Voltage boost wait timeNote 3	tvwait2	C1 to C5 ^{Note 1} =	0.47 μF	500			ms

Notes 1. This is a capacitor that is connected between voltage pins used to drive the LCD.

- C1: A capacitor connected between CAPH and CAPL
- C2: A capacitor connected between VL1 and GND
- C3: A capacitor connected between VL2 and GND
- C4: A capacitor connected between VL3 and GND
- C5: A capacitor connected between VL4 and GND
- $C1 = C2 = C3 = C4 = C5 = 0.47 \mu F \pm 30\%$
- 2. This is the time required to wait from when the reference voltage is specified by using the VLCD register (or when the internal voltage boosting method is selected (by setting the MDSET1 and MDSET0 bits of the LCDM0 register to 01B) if the default value reference voltage is used) until voltage boosting starts (VLCON = 1)
- 3. This is the wait time from when voltage boosting is started (VLCON = 1) until display is enabled (LCDON = 1).
- **4.** Either V_{DD} or VBAT is selected by the battery backup function.

2.8.3 Capacitor split method

(1) 1/3 bias method

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.2 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note 3}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
V _{L4} voltage	V _{L4}	C1 to C4 = 0.47 µF ^{Note 2}		V _{DD} Note 3		V
V _{L2} voltage	V _{L2}	C1 to C4 = 0.47 µF ^{Note 2}	2/3 V _{L4} —	2/3 V _{L4}	2/3 V _{L4} +	V
			0.1		0.1	
V _{L1} voltage	V _{L1}	C1 to C4 = 0.47 µF ^{Note 2}	1/3 V _{L4} —	1/3 VL4	1/3 V _{L4} +	V
			0.1		0.1	
Capacitor split wait timeNote 1	towait		100			ms

Notes 1. This is the wait time from when voltage bucking is started (VLCON = 1) until display is enabled (LCDON = 1).

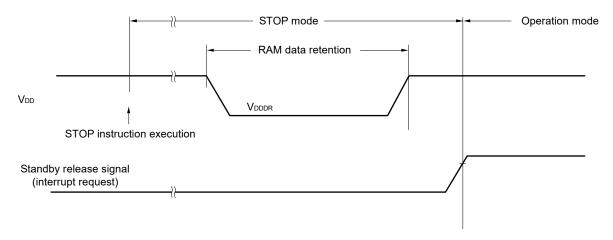
- 2. This is a capacitor that is connected between voltage pins used to drive the LCD.
 - C1: A capacitor connected between CAPH and CAPL
 - C2: A capacitor connected between VL1 and GND
 - C3: A capacitor connected between VL2 and GND
 - C4: A capacitor connected between VL4 and GND
 - $C1 = C2 = C3 = C4 = 0.47 \mu F \pm 30\%$
- 3. Either VDD or VBAT is selected by the battery backup function.

2.9 RAM Data Retention Characteristics

$(T_A = -40 \text{ to } +85^{\circ}\text{C})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.46 ^{Note}		5.5	V

Note The value depends on the POR detection voltage. When the voltage drops, the data in RAM are retained until a POR is applied, but are not retained following a POR.



2.10 Flash Memory Programming Characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le \text{V}_{DD}^{Note 4} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
System clock frequency	fclk	1.9 V ≤ V _{DD} ^{Note 4} ≤ 5.5 V	1		24	MHz
Number of code flash rewrites ^{Notes 1, 2, 3}	Cerwr	Retained for 20 years TA = 85°C	1,000			Times
Number of data flash rewrites ^{Notes 1, 2, 3}		Retained for 1 year TA = 25°C		1,000,000		
		Retained for 5 years TA = 85°C	100,000			
		Retained for 20 years	10,000			
		TA = 85°C				

- **Notes 1.** 1 erase + 1 write after the erase is regarded as 1 rewrite. The retaining years are until next rewrite after the rewrite
 - 2. When using flash memory programmer and Renesas Electronics self programming library
 - 3. This characteristic indicates the flash memory characteristic and based on Renesas Electronics reliability test.
 - **4.** Either V_{DD} or VBAT is selected by the battery backup function.

2.11 Dedicated Flash Memory Programmer Communication (UART)

(T_A = -40 to +85°C, 1.9 V ≤ EVDD0 = EVDD1 ≤ VDDNote ≤ 5.5 V, Vss = EVss0 = EVss1 = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		During serial programming	115,200		1,000,000	bps

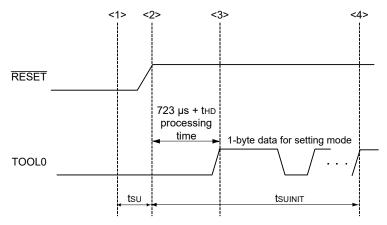


2.12 Timing Specs for Switching Flash Memory Programming Modes

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Time to complete the communication for the initial setting after the external reset is released		POR and LVD reset must be released before the external reset is released.			100	ms
Time to release the external reset after the TOOL0 pin is set to the low level	tsu	POR and LVD reset must be released before the external reset is released.	10			μs
Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)	tно	POR and LVD reset must be released before the external reset is released.	1			ms

Note Either V_{DD} or VBAT is selected by the battery backup function.



- <1> The low level is input to the TOOL0 pin.
- <2> The external reset is released (POR and LVD reset must be released before the external reset is released.).
- <3> The TOOL0 pin is set to the high level.
- <4> Setting of the flash memory programming mode by UART reception and complete the baud rate setting.

Remark tsuinit: The segment shows that it is necessary to finish specifying the initial communication settings within 100 ms from when the resets end.

 t_{SU} : Time to release the external reset after the TOOL0 pin is set to the low level.

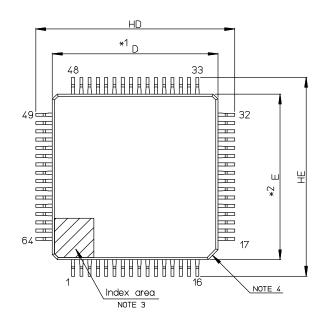
thd: Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)

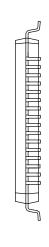
PACKAGE DRAWINGS

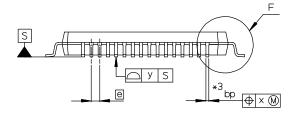
3.1 64-pin Products

R5F10NLEDFB, R5F10NLGDFB, R5F11TLEDFB, R5F11TLGDFB

JEITA Package Code	RENESAS Code	Previous Code	MASS[Typ.]
P-LFQFP64-10×10-0.50	PLQP0064KB-C		0.3g







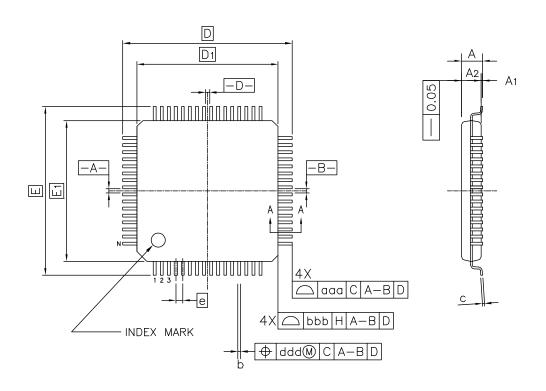


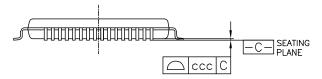
- DIMENSIONS '*1' AND '*2' DO NOT INCLUDE MOLD FLASH.
 DIMENSION '*3' DOES NOT INCLUDE TRIM OFFSET.
 PIN 1 VISUAL INDEX FEATURE MAY VARY, BUT MUST BE
 LOCATED WITHIN THE HATCHED AREA.
 CHAMFERS AT CORNERS ARE OPTIONAL; SIZE MAY VARY.

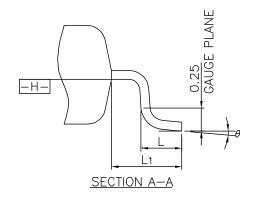
4 4				0.25	٥	θ
1	.			 		
		_		Lp	_	
		Detail F	_	_1_		

Reference	Dimension in Millimeters		limeters
Symbol	Min	Nom	Max
D	9.9	10.0	10.1
Е	9.9	10.0	10.1
A2		1.4	
HD	11.8	12.0	12.2
HE	11.8	12.0	12.2
А			1.7
A1	0.05		0.15
bp	0.15	0.20	0.27
С	0.09		0.20
θ	0 "	3.5	8 "
е		0.5	
×			0.08
У			0.08
Lp	0.45	0.6	0.75
L1		1.0	

JEITA Package code	RENESAS code	MASS(TYP.)[g]
P-LFQFP064-10x10-0.50	PLQP0064KL-A	0.36





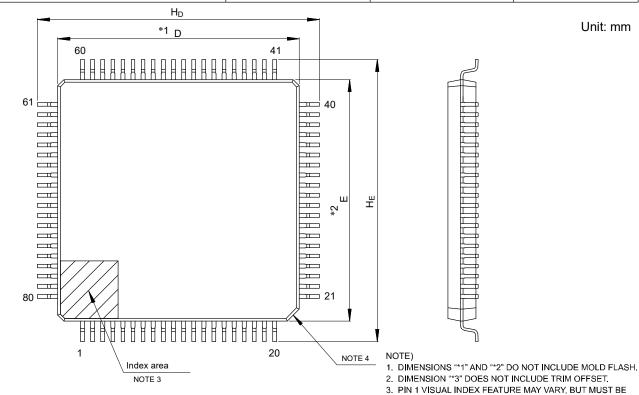


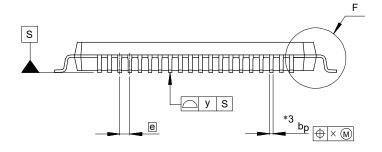
Reference	Dimension in Millimeters		
Symbol	Min.	Nom.	Max.
А	_	-	1.60
A ₁	0.05	-	0.15
A ₂	1.35	1.40	1.45
D	_	12.00	1
D ₁	_	10.00	-
E	_	12.00	-
E ₁	_	10.00	1
N	_	64	_
е	_	0.50	-
b	0.17	0.22	0.27
С	0.09	_	0.20
θ	0°	3.5°	7°
L	0.45	0.60	0.75
L	_	1.00	1
aaa	_	_	0.20
bbb	_	_	0.20
ccc	_	_	0.08
ddd	_	_	0.08

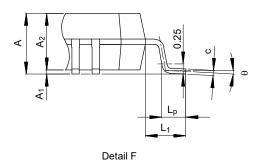
3.2 80-pin Products

R5F10NMEDFB, R5F10NMGDFB, R5F10NMJDFB

JEITA Package Code	RENESAS Code	Previous Code	MASS (Typ) [g]
P-LFQFP80-12x12-0.50	PLQP0080KB-B	_	0.5







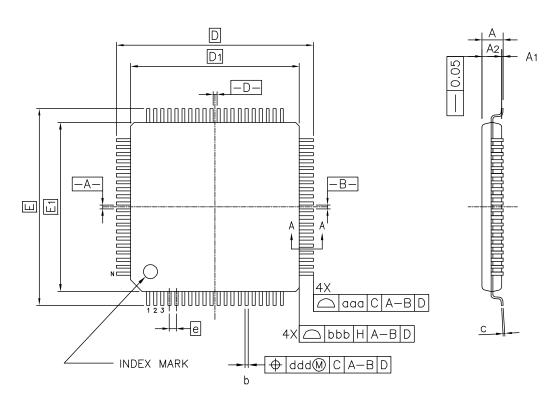
Reference	Dimensions in millimeters		llimeters
Symbol	Min	Nom	Max
D	11.9	12.0	12.1
Е	11.9	12.0	12.1
A ₂	1	1.4	1
H _D	13.8	14.0	14.2
HE	13.8	14.0	14.2
Α	l		1.7
A ₁	0.05	_	0.15
bp	0.15	0.20	0.27
С	0.09	_	0.20
θ	0°	3.5°	8°
е	_	0.5	_
х	1	_	80.0
у	_	_	0.08
Lp	0.45	0.6	0.75
L ₁	_	1.0	_

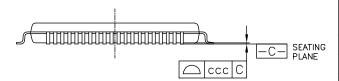
© 2017 Renesas Electronics Corporation. All rights reserved.

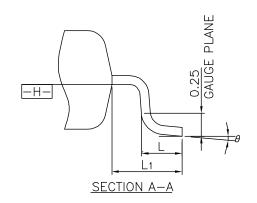
LOCATED WITHIN THE HATCHED AREA.

4. CHAMFERS AT CORNERS ARE OPTIONAL, SIZE MAY VARY.

JEITA Package code	RENESAS code	MASS(TYP.)[g]
P-LFQFP80-12x12-0.50	PLQP0080KJ-A	0.49



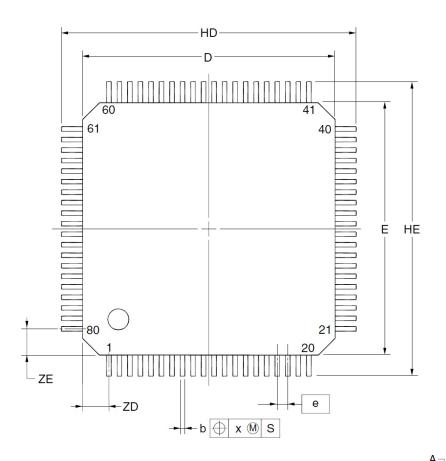


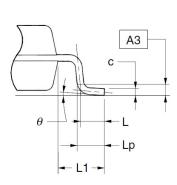


Reference	Dimension in Millimeters		
Symbol	Min.	Nom.	Max.
А	_	_	1.60
A ₁	0.05		0.15
A ₂	1.35	1.40	1.45
D	_	14.00	_
D_1	_	12.00	_
E		14.00	
Eı		12.00	
Ν	_	80	_
е		0.50	
Ь	0.17	0.22	0.27
C	0.09	_	0.20
θ	0,	3.5°	7°
L	0.45	0.60	0.75
7		1.00	
aaa			0.20
ррр		_	0.20
ССС		_	0.08
ddd	_	_	0.08

<R>

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LFQFP80-12x12-0.50	PLQP0080KE-A	P80GK-50-8EU	0.53





ITEM

D

Е

HD

HE

Α

A1

A2

A3

b

С

L

Lp

L1

 θ

е

ZD

ZE

(UNIT:mm)

DIMENSIONS

12.00±0.20

12.00±0.20

14.00±0.20

14.00±0.20

1.60 MAX.

0.10±0.05

1.40±0.05

0.22±0.05

0.60±0.15

1.00±0.20

 $0.145^{\,+0.055}_{\,-0.045}$

0.25

0.50

3°+5°

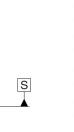
0.50 0.08 0.08

1.25

1.25

detail of lead end





A2

A1-

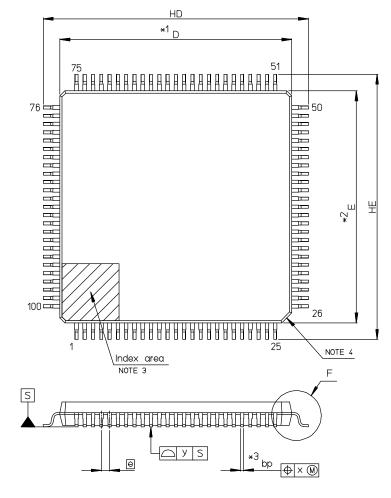
y S NOTE Each lead centerline is located within 0.08 mm of

its true position at maximum material condition.

3.3 100-pin Products

R5F10NPJDFB, R5F10NPGDFB

JEITA Package Code	RENESAS Code	Previous Code	MASS[Typ.]
P-LFQFP100-14×14-0.50	PLQP0100KB-B	 -	0.6g



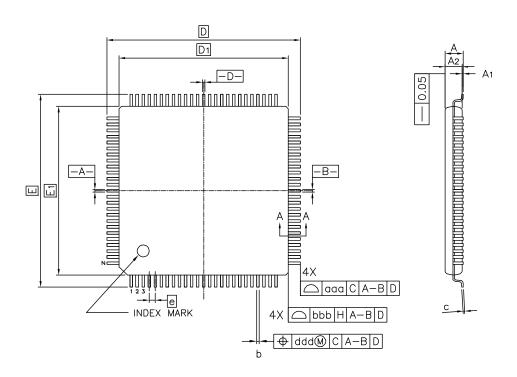


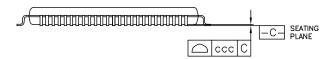
- DIMENSIONS '*1" AND '*2" DO NOT INCLUDE MOLD FLASH.
 DIMENSION '*3" DOES NOT INCLUDE TRIM OFFSET.
 RN 1 VISUAL INDEX FEATURE MAY VARY, BUT MUST BE
 LOCATED WITHIN THE HATCHED AREA.
 CHAMFERS AT CORNERS ARE OPTIONAL; SIZE MAY VARY. 1. 2. 3.

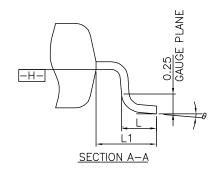
A A		0.25	* •
Α		† †	•
		Lp	
		L1	
	Detail	F	

Reference	Dimension in Millimeters		
Symbol	Min	Nom	Max
D	13.9	14.0	14.1
Е	13.9	14.0	14.1
A2		1.4	
HD	15.8	16.0	16.2
HE	15.8	16.0	16.2
Α			1.7
A1	0.05		0.15
bp	0.15	0.20	0.27
С	0.09		0.20
θ	0 "	3.5°	8 "
е		0.5	
×			0.08
У			0.08
Lp	0.45	0.6	0.75
L1		1.0	

JEITA Package code	RENESAS code	MASS(TYP.)[g]
P-LFQFP100-14x14-0.50	PLQP0100KP-A	0.67







Reference Symbol	Dimension in Millimeters			
	Min.	Nom.	Max.	
Α	_	_	1.60	
A ₁	0.05 –		0.15	
A ₂	1.35	1.40	1.45	
D	-	16.00	-	
D ₁	ı	14.00	1	
Е	I	- 16.00		
E ₁	1	14.00	1	
N	1	100	-	
е		0.50		
b	0.17	0.22	0.27	
С	0.09	_	0.20	
θ	0°	3.5°	7°	
L	0.45	0.60	0.75	
L ₁	1	1.00	1	
aaa		_	0.20	
bbb	_	- -		
ccc		_	0.08	
ddd	_	_	0.08	

Revision	History
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RL78/I1C Datasheet

		Description		
Rev.	Date	Page	Summary	
1.00	May 31, 2016	_	First Edition issued	
2.00	Aug 31, 2018	p.12	Modification of table in 1.6 Outline of Functions	
		p.21, 22	Modification of description in 2.3.1 Pin characteristics	
		p.67	Modification of table in 2.6.1 (1) When reference voltage (+) = AV _{REFP} /ANI0	
			(ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AV _{REFM} /ANI1	
			(ADREFM = 1), target pins: ANI2 to ANI5 and internal reference voltage	
		p.68	Modification of table in 2.6.1 (2) When reference voltage (+) = V _{DD} (ADREFP1	
			= 0, ADREFP0 = 0), reference voltage (-) = Vss (ADREFM = 0), target pins:	
		n 60	ANI0 to ANI5 and internal reference voltage Modification of parameter and symbol, and addition of note 2 in 2.6.2 (1)	
		p.69	Reference voltage	
		p.70	Modification of condition and unit in 2.6.2 (2) Analog input	
		p.72	Modification of typical value in 2.6.2 (4) 2 kHz sampling mode	
2.10	2.10 Aug 23, 2019		Addition of products in which AES function is not available (R5F11TLG a	
			R5F11TLE)	
		p.1	Addition of description in 1.1 Features	
		p.3	Modification of note 2 in 1.1 Features	
		p.4	Modification of Figure 1-1 Part Number, Memory Size, and Package of	
			RL78/I1C	
		p.4	Modification of Table 1-1 List of Ordering Part Numbers	
		p.12	Deletion of note 1 in the "100-pin" column in 1.6 Outline of Functions	
		p.13, 14	Modification of 1.6 Outline of Functions	
		p.78	Modification of 2.7.3 VBAT pin voltage detection characteristics	
		p.79	Modification of 2.7.4 VRTC pin voltage detection characteristics	
		p.82	Deletion of note 2 for V _{L1} in 2.8.2 Internal voltage boosting method, (1) 1/3 bias method	
		p.83	Deletion of note 2 for V _{L1} in 2.8.2 Internal voltage boosting method, (2) 1/4	
		<u>'</u>	bias method	
2.11	Nov 30, 2022	Throughout	The module name for CSI was changed to simplified SPI.	
			"Wait" was modified to "clock stretch"	
		p.4	Modification of Figure 1-1. Part Number, Memory Size, and Package of	
			RL78/I1C	
		p.5	Modification of Table 1-1. List of Ordering Part Numbers	
		p.88	Modification of package drawing in 3.1 64-pin Products (PLQP0064KB-C)	
		p.89	Addition of package drawing in 3.1 64-pin Products (PLQP0064KL-A)	
		p.90	Modification of package drawing in 3.2 80-pin Products (PLQP0080KB-B)	
		p.91	Addition of package drawing in 3.2 80-pin Products (PLQP0080KJ-A)	
		p.92	Modification of package drawing in 3.3 100-pin Products (PLQP0100KB-B)	
2.20	Jul 20, 2022	p.93	Addition of package drawing in 3.3 100-pin Products (PLQP0100KP-A)	
2.20	Jul 20, 2023	p.30	Modification of Note 1 and 4 in 2.3.2 Supply current characteristics	
		p.31 p.32	Modification of Note 9 to Note 5 in 2.3.2 Supply current characteristics Modification of Note 5 to Note 6 in 2.3.2 Supply current characteristics	
		p.32	Deletion of Note 6 in 2.3.2 Supply current characteristics	
		p.33	Modification of Note 1, 5 and 6 in 2.3.2 Supply current characteristics	
2.30	Mar 29, 2024	p.33	Modification of Figure 1-1. Part Number, Memory Size, and Package of	
2.00	Widi 23, 2024	ρ.4	RL78/I1C	
		p.5	Modification of Table 1-1. List of Ordering Part Numbers	
		p.92	Addition of package drawing in 3.2 80-pin Products (PLQP0080KE-A)	
	1	<u> </u>	1 0 0 1	

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The following usage notes are applicable to all Microprocessing unit and Microcontroller unit products from Renesas. For detailed usage notes on the products covered by this document, refer to the relevant sections of the document as well as any technical updates that have been issued for the products.

1. Precaution against Electrostatic Discharge (ESD)

A strong electrical field, when exposed to a CMOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop the generation of static electricity as much as possible, and quickly dissipate it when it occurs. Environmental control must be adequate. When it is dry, a humidifier should be used. This is recommended to avoid using insulators that can easily build up static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work benches and floors must be grounded. The operator must also be grounded using a wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions must be taken for printed circuit boards with mounted semiconductor devices.

2. Processing at power-on

The state of the product is undefined at the time when power is supplied. The states of internal circuits in the LSI are indeterminate and the states of register settings and pins are undefined at the time when power is supplied. In a finished product where the reset signal is applied to the external reset pin, the states of pins are not guaranteed from the time when power is supplied until the reset process is completed. In a similar way, the states of pins in a product that is reset by an on-chip power-on reset function are not guaranteed from the time when power is supplied until the power reaches the level at which resetting is specified.

3. Input of signal during power-off state

Do not input signals or an I/O pull-up power supply while the device is powered off. The current injection that results from input of such a signal or I/O pull-up power supply may cause malfunction and the abnormal current that passes in the device at this time may cause degradation of internal elements. Follow the guideline for input signal during power-off state as described in your product documentation.

4. Handling of unused pins

Handle unused pins in accordance with the directions given under handling of unused pins in the manual. The input pins of CMOS products are generally in the high-impedance state. In operation with an unused pin in the open-circuit state, extra electromagnetic noise is induced in the vicinity of the LSI, an associated shoot-through current flows internally, and malfunctions occur due to the false recognition of the pin state as an input signal become possible.

5. Clock signals

After applying a reset, only release the reset line after the operating clock signal becomes stable. When switching the clock signal during program execution, wait until the target clock signal is stabilized. When the clock signal is generated with an external resonator or from an external oscillator during a reset, ensure that the reset line is only released after full stabilization of the clock signal. Additionally, when switching to a clock signal produced with an external resonator or by an external oscillator while program execution is in progress, wait until the target clock signal is stable.

6. Voltage application waveform at input pin

Waveform distortion due to input noise or a reflected wave may cause malfunction. If the input of the CMOS device stays in the area between V_{IL} (Max.) and V_{IH} (Min.) due to noise, for example, the device may malfunction. Take care to prevent chattering noise from entering the device when the input level is fixed, and also in the transition period when the input level passes through the area between V_{IL} (Max.) and V_{IH} (Min.).

7. Prohibition of access to reserved addresses

Access to reserved addresses is prohibited. The reserved addresses are provided for possible future expansion of functions. Do not access these addresses as the correct operation of the LSI is not guaranteed.

8. Differences between products

Before changing from one product to another, for example to a product with a different part number, confirm that the change will not lead to problems. The characteristics of a microprocessing unit or microcontroller unit products in the same group but having a different part number might differ in terms of internal memory capacity, layout pattern, and other factors, which can affect the ranges of electrical characteristics, such as characteristic values, operating margins, immunity to noise, and amount of radiated noise. When changing to a product with a different part number, implement a system-evaluation test for the given product.

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